



Capacitive Charging Mode (CCM) of VNF1248F

Introduction

The purpose of this document is to demonstrate the functionality of the capacitive charging mode (CCM) feature in an application environment using the [EV-VNF1248F](#) easy board (Rev. 3.0). For major details, please refer to the updated easy board data brief ([DB5511](#)) and user manual ([UM3487](#)).

All tests were conducted on a typical sample representative of the standard population.

1 System Overview

1.1 VNF1248F Description

The VNF1248F is an advanced controller for a power MOSFET in a high-side configuration. It is designed to implement an intelligent high-side switch for 12 V, 24 V, and 48 V automotive applications. The control IC interfaces with a host microcontroller through a 3.3 V and 5 V CMOS-compatible SPI interface. It provides protection features and diagnostics signals for the system.

1.2 Block diagram and pin description

Figure 1. Block diagram

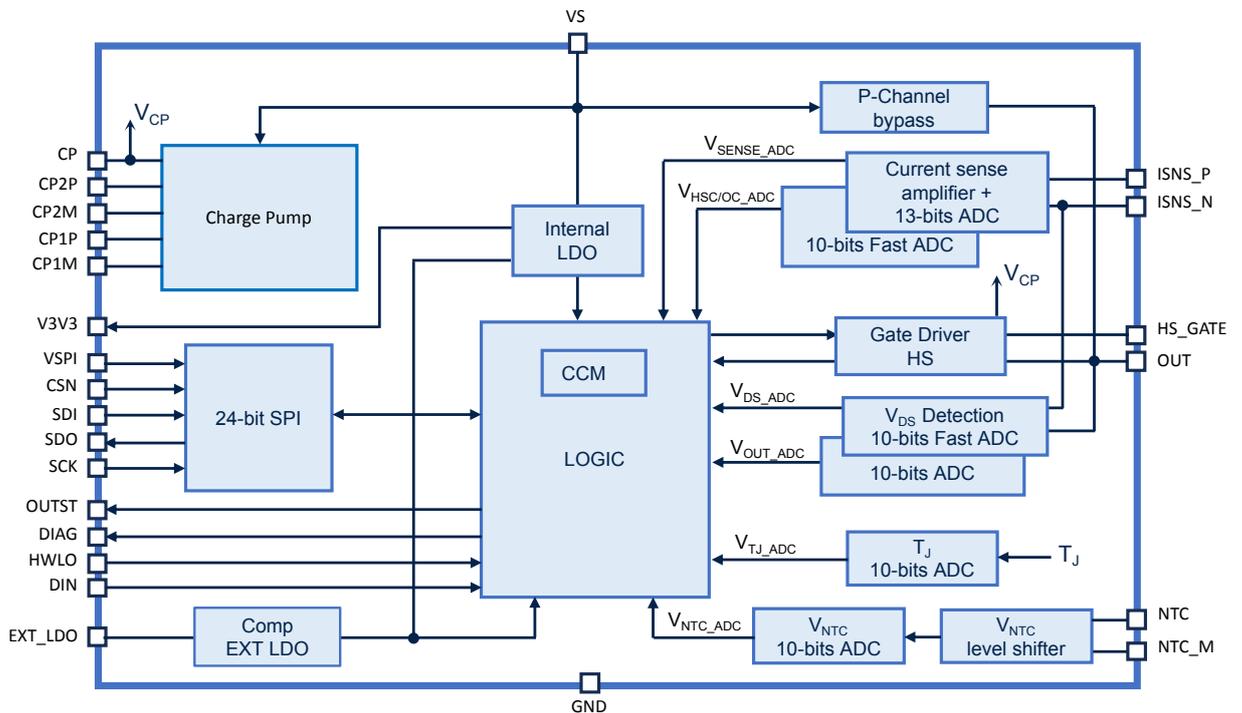
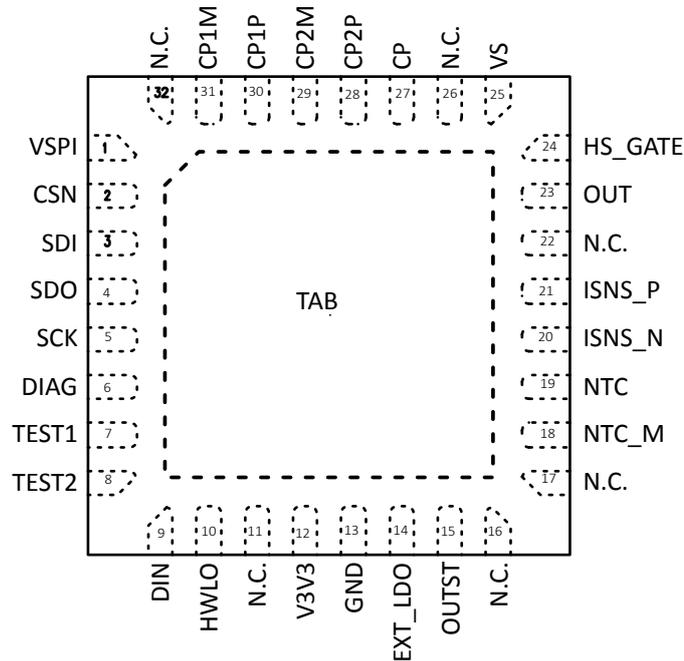


Figure 2. Configuration diagram (top through view)


Note: *TAB connection must be connected to the ground. TAB is not intended as the device reference ground (a dedicated pin shall be used).*

Table 1. Pin functions

Pin #	Name	Function
TAB		GND
1	VSPI	DC supply input for the SPI interface. 3.3 V and 5 V are compatible.
2	CSN	Chip select (active low) for SPI communication. It is the selection pin of the device. CMOS compatible input.
3	SDI	Serial data input for SPI communication. Data is transferred serially into the device and sampled on the SCK rising edge.
4	SDO	Serial data output for SPI communication. Data is transferred serially out of the device on the SCK falling edge.
5	SCK	Serial clock for SPI communication. It is a CMOS compatible input.
6	DIAG	Open drain logic output. Diagnostic feedback. DIAG = '0' if ((SR1.FAILSAFE_ST='1' or (CR1.AUTO_ON_DIS='1') and BYPASS_SAT='1') or (GSB.DIAGS = '1') or (GSB.DE = '1') or "internal oscillator fault event" else '1'
7	TEST1	Test mode pin 1 - It must be connected to the ground through 1 kΩ resistor.
8	TEST2	Test mode pin 2 - It must be connected to the ground through 1 kΩ resistor.
9	DIN	Direct input to wake up device from standby and to directly control gate turn-on/turn-off. If not used, it must be connected to the ground through 1 kΩ resistor.
10	HWLO	Active high input pin compatible with 3.3 V and 5 V CMOS. If not used, it must be connected to the ground through 1 kΩ resistor.
11, 16, 17, 22, 26, 32	N.C	Not connected.
12	V3V3	Output of the 3.3 V internal LDO voltage regulator (logic and I/O supply). Connect a low ESR capacitor (1 μF) close to this pin.

Table 2. Adopted BOM on VNF1248F application easy board

General reference	EV-VNF1248F reference	Value
C _S	C ₁ // C ₉	2*10 μF
C _{S2}	C ₅	100 nF
C _{P1} , C _{P2}	C ₂ , C ₄	470 nF
C _P	C ₃	470 nF
C _{VSP1}	C ₈	330 nF
C _{V3V3}	C ₆	1 μF
R _{PU}	R ₁₁	4.7 kΩ
R _{PD}	R ₂₃	47 kΩ
	R ₂₁	4.7 kΩ
R _{PROT(SPI)}	R ₄	330 Ω
R _{PROT(OUTST)}	R ₂₉	330 Ω
R _{PROT}	R ₂ , R ₅ , R ₆ , R ₁₉ , R ₂₀ , R ₃₀ , R ₃₃ , R ₃₈ , R ₃₉ , R ₄₀	1 kΩ
R _{GATE}	R _G	1 Ω
R _{GB}	R _{GB}	47 kΩ
R _{REF}	R ₂₂	10 kΩ ± 1%
R _{SHUNT}	R _{SENSE}	5 mΩ
R _{NTC}	R ₈	B57232V5103F360
External MOSFET	Q ₂	STL135N8F7AG
Reverse polarity protection	D ₁	STPS2H100AY
Free wheeling diode	D ₂	STPS5H100-Y
--	LED3	Red LED
Voltage suppressor	Tr_d1	SM15T68CAY

Figure 4. Schematic of adopted VNF1248F application easy board

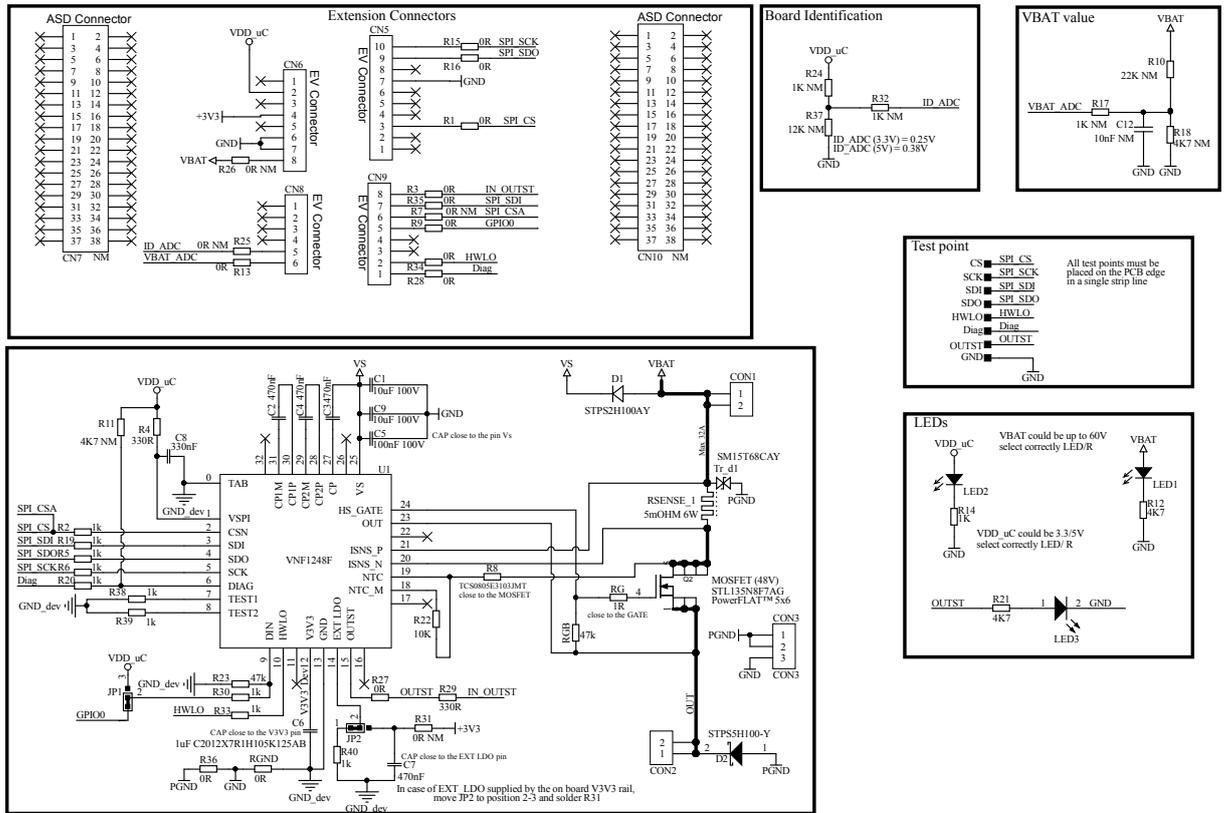
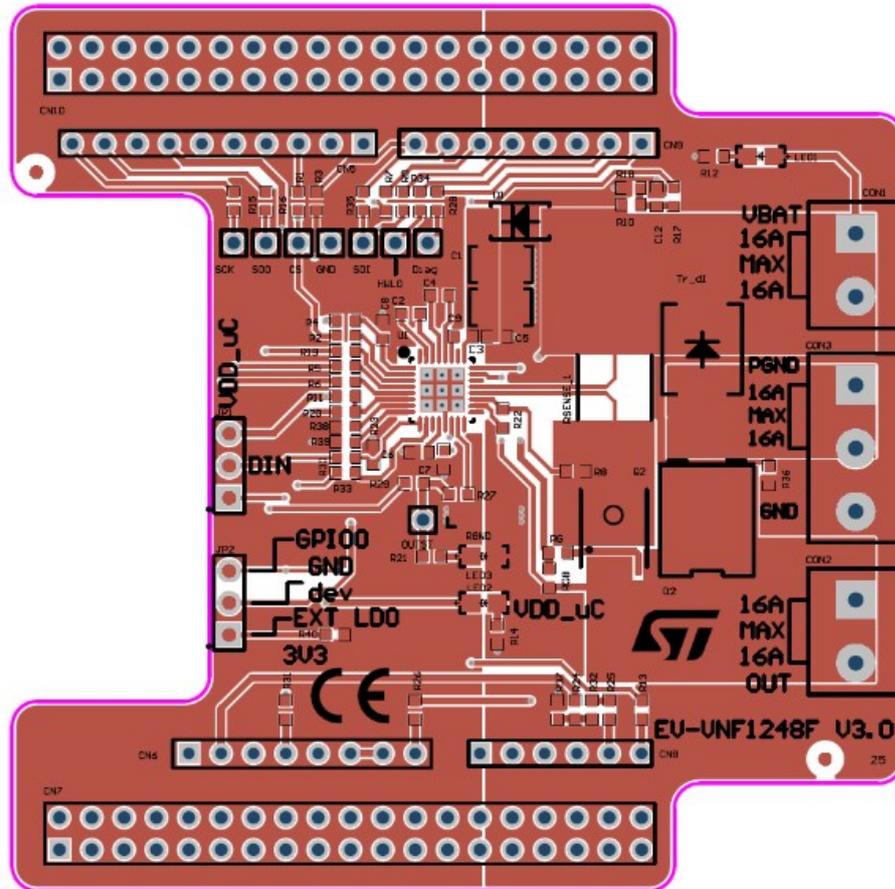


Figure 5. Layout of adopted VNF1248F application easy board



2 Capacitive Charging Mode – CCM

2.1 CCM and variables tuning application behavior

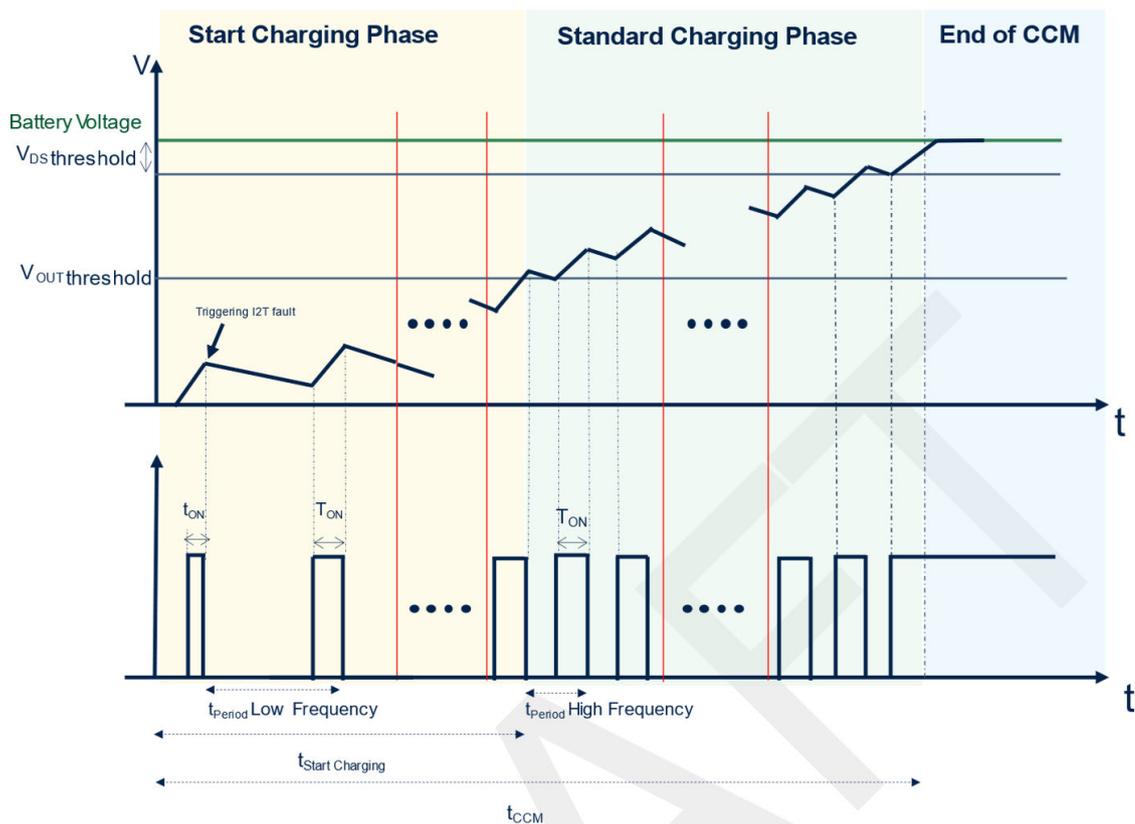
The device state machine implements a PWM-based control for the high-side driver controller to enable charging a capacitive load through the off-chip power MOSFET driven by the device.

The CCM feature is always available (for detailed information please refer to the flow charts available in "Capacity Charging Mode - CCM" chapter in the device datasheet, [DS14109](#)), and it can be triggered either in Unlocked/ Locked or in Fail-safe states.

The capacitive load charging sequence is split into two phases as shown in [Figure 6](#):

1. **Start charging phase:** in this phase, the load is charged with a slower PWM period to check for a possible short circuit at the output; a maximum number of PWM pulses is allowed to reach a minimum V_{OUT} value, otherwise CCM is aborted.
2. **Standard charging phase:** in this phase, the load is charged with a nominal PWM period until V_{DS} reaches an internally defined threshold (100 mV), or a timeout limit is reached.

Figure 6. CCM charging phases



The register SR#1 (at address 0x11) reports the CCM status within the **CCM_STATUS** field, bits [23:22]. These two bits define four possible configurations:

- 00 → **IDLE**: CCM operation not started
- 01 → **RUN**: CCM operation running
- 10 → **CHARGED**: CCM operation completed successfully
- 11 → **CHARGE INCOMPLETE**: CCM operation aborted or stopped

Burst mode control for charging a capacitive load is configured by the following parameters, which must be programmed in dedicated registers:

Table 3. CCM relevant fields

Parameter	Description	Field name	Field position in bits	Register number	Range
PWM period	($t_{ON} + t_{OFF}$) set during standard charging phase	CCM_PWM_T	7:2	CR#5	From 50 to 4000 μ s corresponding to frequency from 250 Hz to 20 KHz. (refer to "CCM PWM t_{ON} setting" table in DS14109)
PWM t_{ON} time	PWM interval time with high-side driver turned on	CCM_PWM_TON	13:8	CR#5	1-50 μ s (refer to "CCM PWM t_{ON} setting" table in DS14109)
PWM t_{ON} multiplying factor	to multiply by 1-2-4-8 T_{on} time defined by CCM_PWM_TON setting, for duty cycle configuration	CCM_PWM_TON_MF	19:18	CR#3	1-2-4-8
PWM start period	PWM period ($T_{on} + T_{off}$) set during starting phase (short circuit check)	CCM_PWM_SC_T	16:14	CR#5	2.0-2.5-3.0-3.5-4.0 ms
PWM start pulses max number	Max number of PWM pulses during starting phase (short circuit check)	CCM_PWM_SC_T_NB	21:17	CR#5	From 5 to 50 pulses (refer to "CCM PWM max. start pulses number setting" table in DS14109)
CCM timeout	Maximum time allowed to charging phase	CCM_TIMEOUT	23:22	CR#5	200-250-300-400 ms
VOUT threshold	VOUT limit to be achieved to switch from starting phase to standard charging phase	CCM_VOUT_THR	16:14	CR#3	1-2-3-4-5 V
Hard short circuit latch-off threshold	It configures the Delta V reading at extremes of R_{SHUNT} triggering the HSC protection	HSC_THR	10:7	CR#2	From 20 to 160 mV (refer to "hard short circuit protection with integrated 10-bit ADC" table in DS14109)
Nominal overcurrent threshold	Value of the nominal overcurrent threshold for the eFuse emulation	OVC_THR	15:11	CR#2	From 6 to 90 mV (refer to "overcurrent protection" table in DS14109)
Nominal time ON	Value of nominal time required for the eFuse emulation. It corresponds to the trip time obtained when the current is equal to the nominal overcurrent threshold	T_NOM	23:16	CR#2	From 1 to 511 s (refer to "CCM PWM max. start pulses number setting" table in DS14109)

Additional important variables affecting the CCM behavior are:

- V_B battery supply voltage of entire application circuit
- R_{SHUNT} dimension
- Ambient temperature
- C_{LOAD} features and connection

2.2 Start Charging Phase

During this phase, the load is charged with a T_{ON} (**CCM_PWM_TON**) and a PWM period (**CCM_PWM_SC_T**) to check for possible short circuit on output.

This phase ends when one of the following two conditions occurs:

- V_{OUT} triggers the threshold as set in CR#3 (**CCM_VOUT_THR**) so that the standard phase can start
- The maximum number of PWM pulses has been reached as set in CR#5 (**CCM_PWM_SC_T_NB**) with V_{OUT} below the threshold set by **CCM_VOUT_THR**

For the second condition, where the charging phase is interrupted, when the field **CCM_STATUS** (bits [23:22] of SR#1) sets to "11", it means that the charging of the load has not succeeded. This event can occur in case of a setup not able to allow V_{OUT} to reach the target threshold set by **CCM_VOUT_THR** (see [Figure 63](#) below) or in case of short circuit between OUT and GND (see [Figure 107](#) below).

2.3 Standard Charging Phase

Once the "Start Charging Phase" has been successfully completed (i. e.: V_{OUT} triggers the target threshold), the load charging continues with a nominal PWM period (**CCM_PWM_T**).

The CCM ends when one of the following two conditions occurs:

- External power MOS VDS reaches an internally defined threshold (100 mV).
The field **CCM_STATUS** (bits [23:22] of SR#1) sets to "10" meaning that the charging of the load is **completed successfully**
- t_{CCM} timeout elapsed (**CCM_TIMEOUT**).
The field **CCM_STATUS** (bits [23:22] of SR#1) sets to "11" indicating that the charging of the load is **aborted** (see [Figure 113](#) below).

2.4 How to launch CCM

Capacitive charging mode can be launched with the device in Fail-safe, Unlocked or Locked state.

Please consider that with the device in Unlocked state, it is possible to configure all parameters reported in [Table 5](#) by writing the related involved bits in the indicated fields while in case of the device in Fail-safe or Locked state, the mentioned parameters will follow the contents in the related CRs of NVM. For NVM operation, refer to [AN6394 "NVM feature of VNF1248F"](#)

Once the device is in Unlocked or Locked state, the CCM will be started or stopped by means of dedicated commands ON and OFF on bits 18 (**CCM_CTRL_ON**) and 19 (**CCM_CTRL_OFF**) inside CR#1.

Please refer to the trial setup A1 vs A2 below for the CCM with the device in Unlocked vs Locked state.

Refer to the trial setup Z1 vs Z3 below for the charge completed or aborted with device in Unlocked state.

Once the device is in Fail-safe state, capacitive load burst charging mode functionality can be enabled by proper DIN toggling sequence that ends with DIN high to maintain HS_GATE ON. In Fail-safe, the CCM can be stopped before charge completion by setting DIN low. Please refer to the trial setup Z2 vs Z4 below for the charge completed or aborted with device in Fail-safe state.

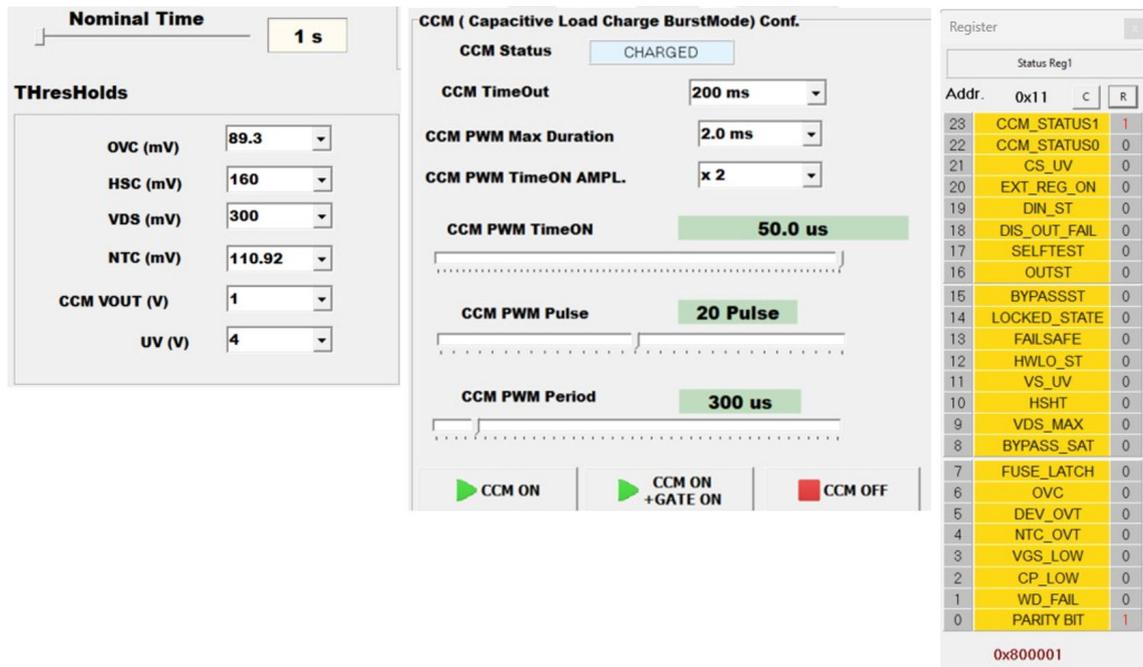
3 CCM test in Unlocked vs Locked vs Fail-safe state

This paragraph reports the examples of the charge of a capacitance working with the application circuit indicated in Figure 16, having $R_{SHUNT} = 5 \text{ m}\Omega$ and $C_S = 2 * 10 \text{ uF}$ (100 V) and using the following setups.

3.1 Trial Setup A1

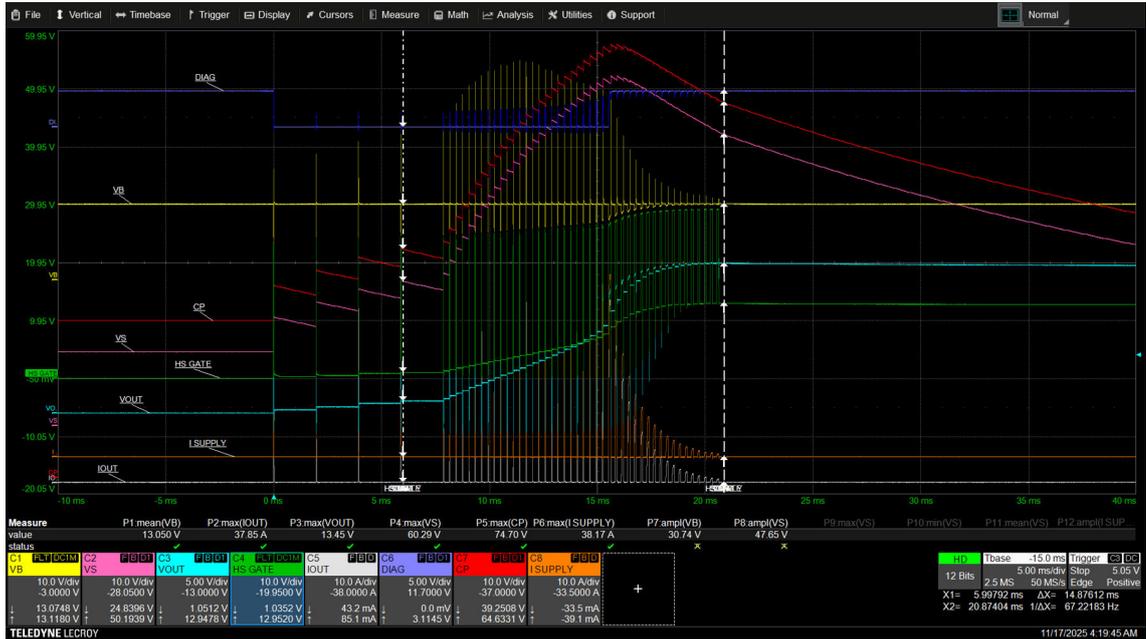
- $V_B = 13 \text{ V}$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 30^\circ\text{C}$
- $C_{LOAD} = 2.2 \text{ mF}$ (measured 2.08 mF)
- Device in Unlocked state with following settings:
 - CCM_VOUT_THR → bits [16:14] of CR#5 set @ "000b" = 1 V
 - OVC_THR = VOC_THRS_31 → bits [15:11] of CR#2 set @ "11111b" = 89.3 mV
 - HSC_THR = VHSC_THRS_15 → bits [10:7] of CR#2 set @ "11111b" = 160 mV
 - T_NOM = T_NOM_MIN → bits [23:16] of CR#2 set @ "00000000b" = 1 s
 - CCM_PWM_TON → bits [13:8] of CR#5 set @ "111111b" = 50 μs
 - CCM_PWM_TON_MF → bits [19:18] of CR#3 set @ "01b" = 2 x
 - CCM_PWM_SC_T_NB → bits [21:17] of CR#5 set @ "01111b" = 20 pulses
 - CCM_PWM_T → bits [7:2] of CR#5 set @ "000100b" = 300 μs
 - CCM_TIMEOUT → bits [23:22] of CR#5 set @ "00b" = 200 ms
 - CCM_PWM_SC_T → bits [16:14] of CR#5 set @ "000b" = 2 ms
 - GUI settings as per Figure 7

Figure 7. CCM configuration and result from GUI for test setup A1



With the mentioned setup A1, the C_{LOAD} is charged in 8 ms (start phase) + 12.9 ms (standard phase).

Figure 8. Waveforms acquired during CCM with setup A1



The image below highlights the two phases during the CCM and the I²t - fuse protections triggering.

Figure 9. Zoomed waveforms acquired during CCM with setup A1

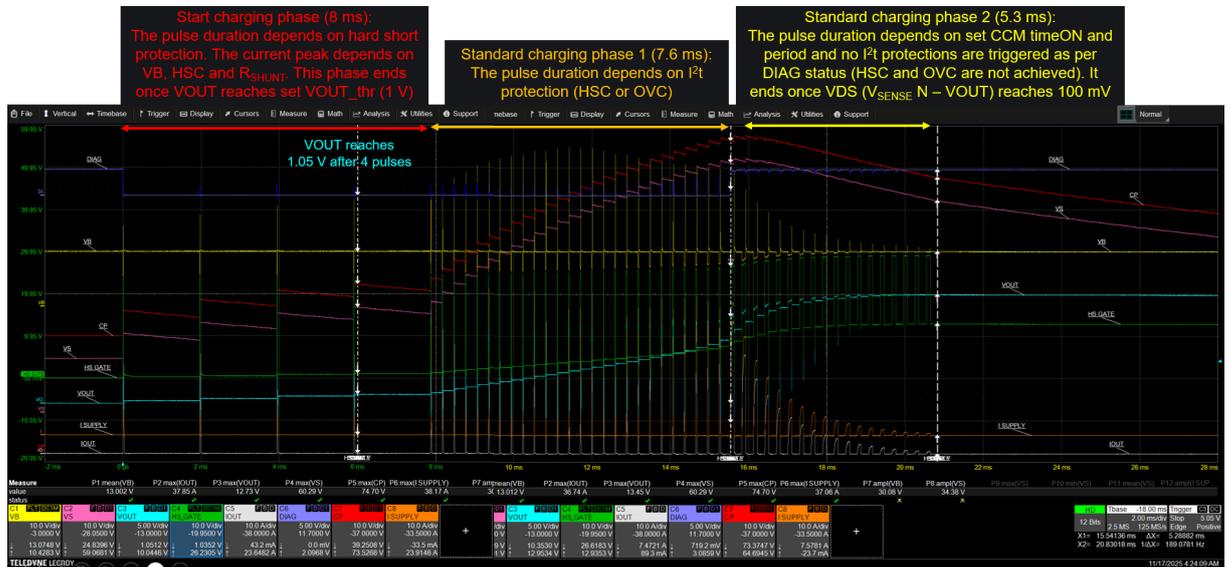
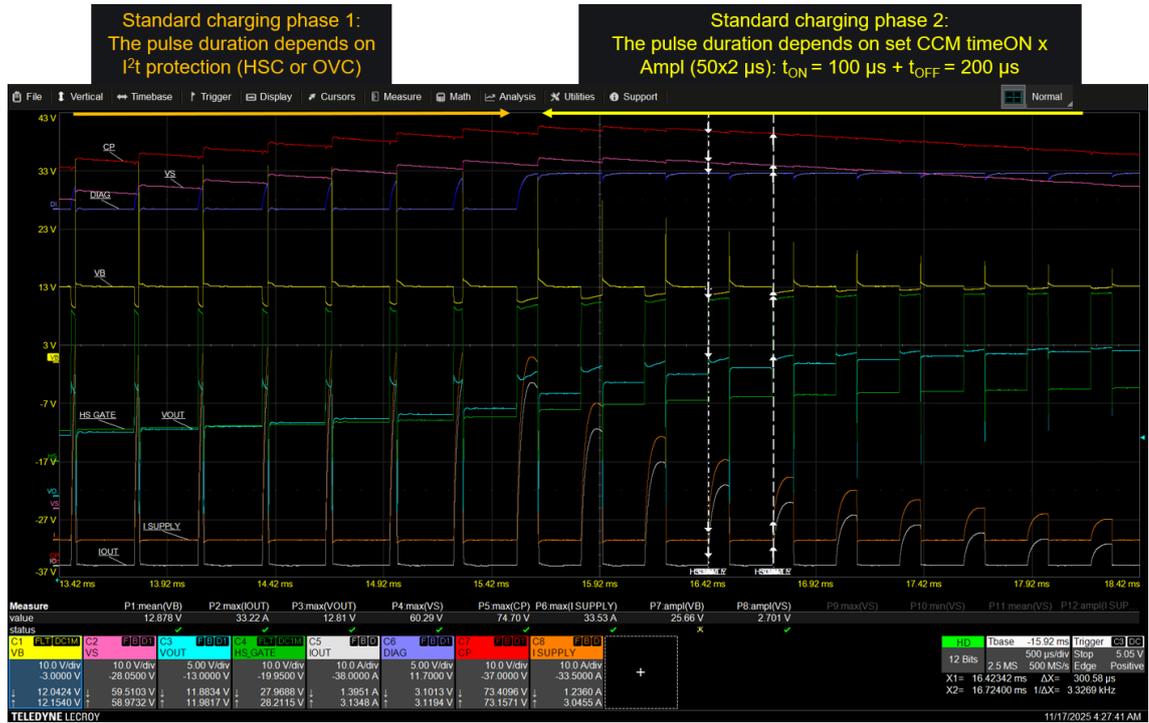


Figure 9 points out that the CCM time ON and time OFF configured in CR#5 are visible only when I²t protection is no longer triggered.

Figure 10. Zoomed waveforms acquired during CCM with setup A1


The CCM activation on the same circuit, C_{LOAD} and V_B , but with the device in Locked mode, generates a different result because the device, once in Locked or Fail-safe modes, recovers the default setting written in the NVM. In case of device in Locked state, the CCM operation is incomplete after 10 ms, with V_{OUT} reaching 0.4 V after the five set pulses, as shown in trial A2 below.

3.2 Trial Setup A2

- $V_B = 13\text{ V}$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 2.2\text{ mF}$ (measured 2.08 mF)
- Device in Locked state recovering default NVM setting (the DUT was moved from Unlocked state with $NVM_CFG_EN = 1b$, bit 16 of CR#1, to Locked state):
 - $CCM_VOUT_THR = 1\text{ V}$
 - $OVC_THR = VOC_THRS_0 \rightarrow 6\text{ mV}$
 - $HSC_THR = VHSC_THRS_0 \rightarrow 20\text{ mV}$
 - $T_NOM = T_NOM_{MIN} \rightarrow 1\text{ s}$
 - $CCM_PWM_TON = T_{ON}$ stopped by protection
 - $CCM_PWM_SC_T_NB = 5\text{ pulses}$
 - $CCM_PWM_T = 50\text{ }\mu\text{s}$
 - $CCM_PWM_TON_MF = 1\text{ x}$
 - $CCM_TIMEOUT = 200\text{ ms}$
 - $CCM_PWM_SC_T = 2\text{ ms}$
 - GUI settings collected at the end of CCM operations as shown in Figure 11

Figure 11. CCM configuration and result from GUI for test setup A2

Nominal Time 1 s

THresHolds

OVC (mV)	6
HSC (mV)	20
VDS (mV)	300
NTC (mV)	110.92
CCM VOUT (V)	1
UV (V)	4

CCM (Capacitive Load Charge BurstMode) Conf.

CCM Status: INCOMPLETE

CCM TimeOut: 200 ms

CCM PWM Max Duration: 2.0 ms

CCM PWM TimeON AMPL.: x 1

CCM PWM TimeON: **TON Protection**

CCM PWM Pulse: **5 Pulse**

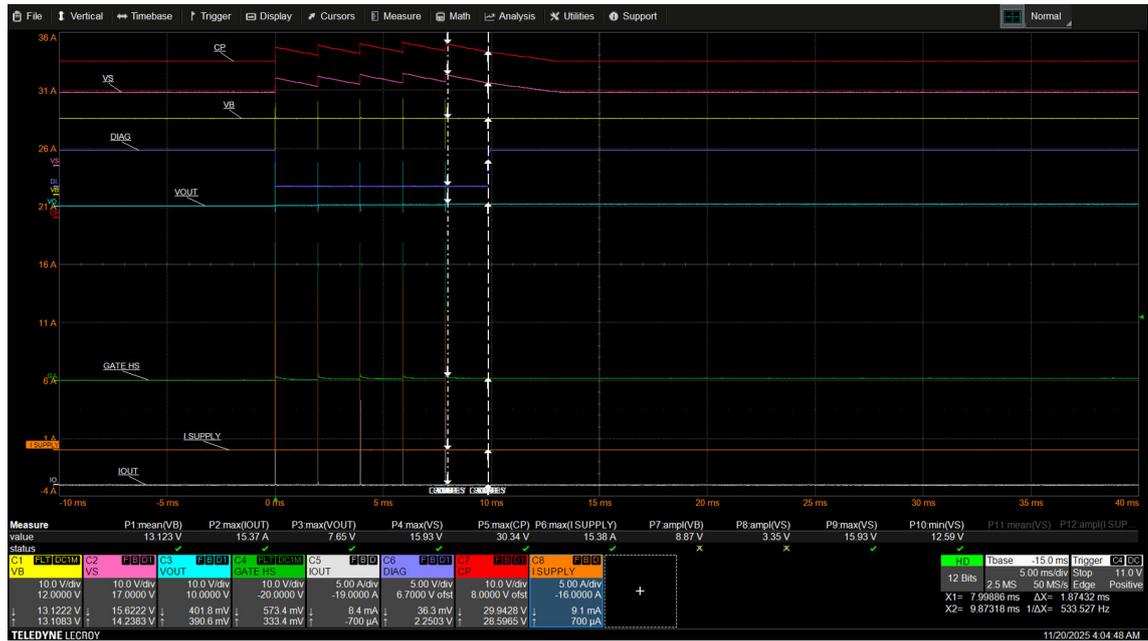
CCM PWM Period: **50 us**

Buttons: CCM ON, CCM ON +GATE ON, CCM OFF

Register

Addr.	0x11	C	R
23	CCM_STATUS1	1	
22	CCM_STATUS0	1	
21	CS_UV	0	
20	EXT_REG_ON	0	
19	DIN_ST	0	
18	DIS_OUT_FAIL	0	
17	SELFTEST	0	
16	OUTST	0	
15	BYPASSST	0	
14	LOCKED_STATE	1	
13	FAILSAFE	0	
12	HWLO_ST	0	
11	VS_UV	0	
10	HSHT	0	
9	VDS_MAX	0	
8	BYPASS_SAT	0	
7	FUSE_LATCH	0	
6	OVC	0	
5	DEV_OVT	0	
4	NTC_OVT	0	
3	VGS_LOW	0	
2	CP_LOW	0	
1	WD_FAIL	0	
0	PARITY BIT	1	

0xC04001

Figure 12. Waveforms acquired during CCM with test setup A2


Also, in case of the device in Fail-safe state, the CCM operation is incomplete after 10 ms, with V_{OUT} reaching 0.4 V after the five set pulses. Considering that CCM operations in Fail-safe are activated by DIN toggling ending with DIN high, the DIAG signal remains low and FUSE_LATCH + HSC are reported on SR#1 together with the CCM STATUS incomplete as shown in the images below related to trial A3.

3.3 Trial Setup A3

- $V_B = 13\text{ V}$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 2.2\text{ mF}$ (measured 2.08 mF)
- Device in Fail-safe state recovering default NVM setting:
 - $CCM_VOUT_THR = 1\text{ V}$
 - $OVC_THR = OVC_THRS_0 \rightarrow 6\text{ mV}$
 - $HSC_THR = VHSC_THRS_0 \rightarrow 20\text{ mV}$
 - $T_NOM = T_NOM_{MIN} \rightarrow 1\text{ s}$
 - $CCM_PWM_TON = T_{ON}$ stopped by protection
 - $CCM_PWM_SC_T_NB = 5\text{ pulses}$
 - $CCM_PWM_T = 50\text{ }\mu\text{s}$
 - $CCM_PWM_TON_MF = 1\text{ x}$
 - $CCM_TIMEOUT = 200\text{ ms}$
 - $CCM_PWM_SC_T = 2\text{ ms}$
 - GUI settings collected at the end of CCM operations as shown in [Figure 13](#)

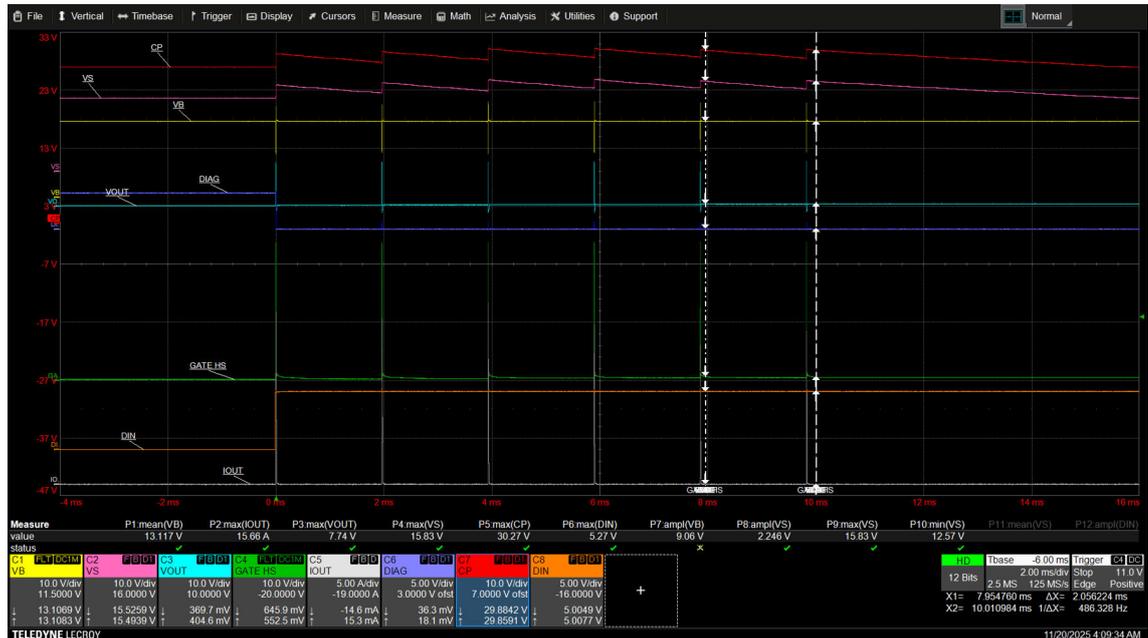
Figure 13. CCM configuration and result from GUI for test setup A3

The screenshot displays the CCM (Capacitive Load Charge BurstMode) configuration interface. It is divided into three main sections:

- Nominal Time:** Set to 1 s.
- THresHolds:**
 - OVC (mV): 6
 - HSC (mV): 20
 - VDS (mV): 300
 - NTC (mV): 110.92
 - CCM VOUT (V): 1
 - UV (V): 4
- CCM (Capacitive Load Charge BurstMode) Conf.:**
 - CCM Status: INCOMPLETE
 - CCM TimeOut: 200 ms
 - CCM PWM Max Duration: 2.0 ms
 - CCM PWM TimeON AMPL.: x 1
 - CCM PWM TimeON: TON Protection (indicated by a green bar)
 - CCM PWM Pulse: 5 Pulse (indicated by a green bar)
 - CCM PWM Period: 50 us (indicated by a green bar)
 - Control buttons: CCM ON, CCM ON +GATE ON, CCM OFF
- Register:** A table showing the status of various registers. The address is 0xC82481.

Addr.	0x11	C	R
23	CCM_STATUS1	1	
22	CCM_STATUS0	1	
21	CS_UV	0	
20	EXT_REG_ON	0	
19	DIN_ST	1	
18	DIS_OUT_FAIL	0	
17	SELFTEST	0	
16	OUTST	0	
15	BYPASSST	0	
14	LOCKED_STATE	0	
13	FAILSAFE	1	
12	HWLO_ST	0	
11	VS_UV	0	
10	HSHT	1	
9	VDS_MAX	0	
8	BYPASS_SAT	0	
7	FUSE_LATCH	1	
6	OVC	0	
5	DEV_OVT	0	
4	NTC_OVT	0	
3	VGS_LOW	0	
2	CP_LOW	0	
1	WD_FAIL	0	
0	PARITY BIT	1	

0xC82481

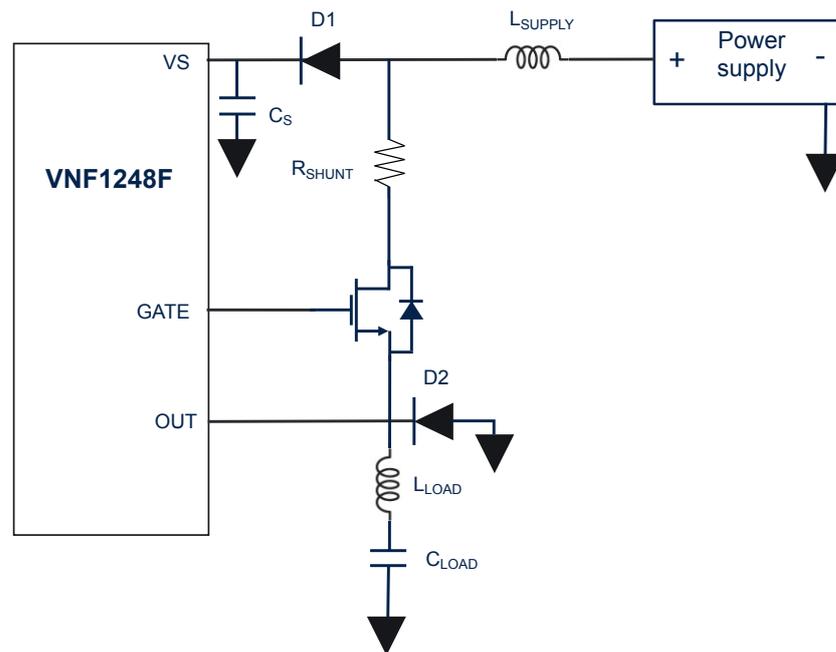
Figure 14. Waveforms acquired during CCM with test setup A3

Figure 15. Zoomed view on DIN toggling activating CCM in Fail-safe with test setup A3


4 Application boost effects

An important aspect that the user must consider to correctly dimension the final application is that the combination of the circuit itself and the parasitic inductance of the surrounding connections leads results in a hidden boost architecture, potentially causing hazardous effects.

The hidden boost architecture is illustrated in Figure 16, where the inductance effect arises from the potentially long wire connecting the battery to the module on which the VNF1248F application is mounted.

Figure 16. Hidden boost schematization



The hazardous effects of the hidden boost architecture are evident in the setup analyzed in the previous chapters. In Figure 8, V_S achieves a maximum value of 60.3 V.

During the standard charging phase, the voltage on the VS pin increases along with the output voltage. In addition to the VS pin, the ISNS_P and ISNS_N pins are also impacted by the side effects of the hidden boost. Of course, the CP voltage value also increases as a consequence of this effect.

The VNF1248F can withstand these side effects as long as the voltage of the affected pins remains below their absolute maximum rating (AMR) value, which is 70 V for the VS, ISNS_P, and ISNS_N pins and 90 V for the CP pin.

To mitigate the hazardous effects of the hidden boost, an additional capacitance C_{IN} can be placed between the supply and ground connectors of the module.

This solution is suggested for 12 V applications, while it is absolutely needed for applications with a 24 V or 48 V battery to avoid reaching dangerous voltage values above AMR. In this case, a capacitance or a combination of caps, must fit with the required breakdown voltage (> 60 V) and provide a clamping voltage below the AMR (70 V).

To select the input capacitor C_{IN} , we performed several checks and calculations in our circuit using an energy-balance approach: the energy stored in the parasitic inductance L_{SUPPLY} is transferred to the input capacitor C_{IN} , causing its voltage to rise from V_{BATT} to V_S (which must remain ≤ 70 V).

The schematic adding C_{IN} and the schematic of the ST application circuit, showing the points in which the voltage and current measurements were performed, are reported below:

Figure 17. Schematic of applicative circuit with the insertion of dedicated C_{IN} to smooth boost effect

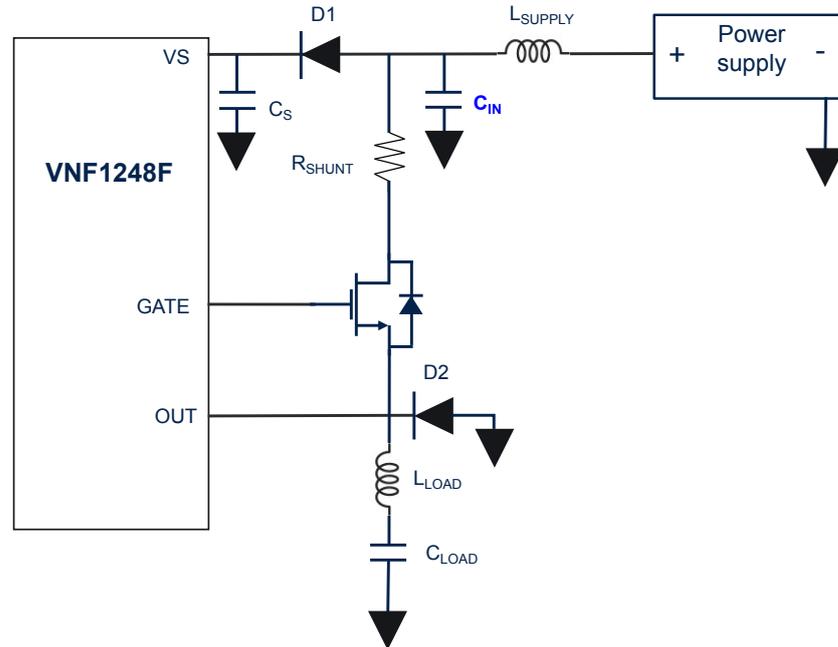
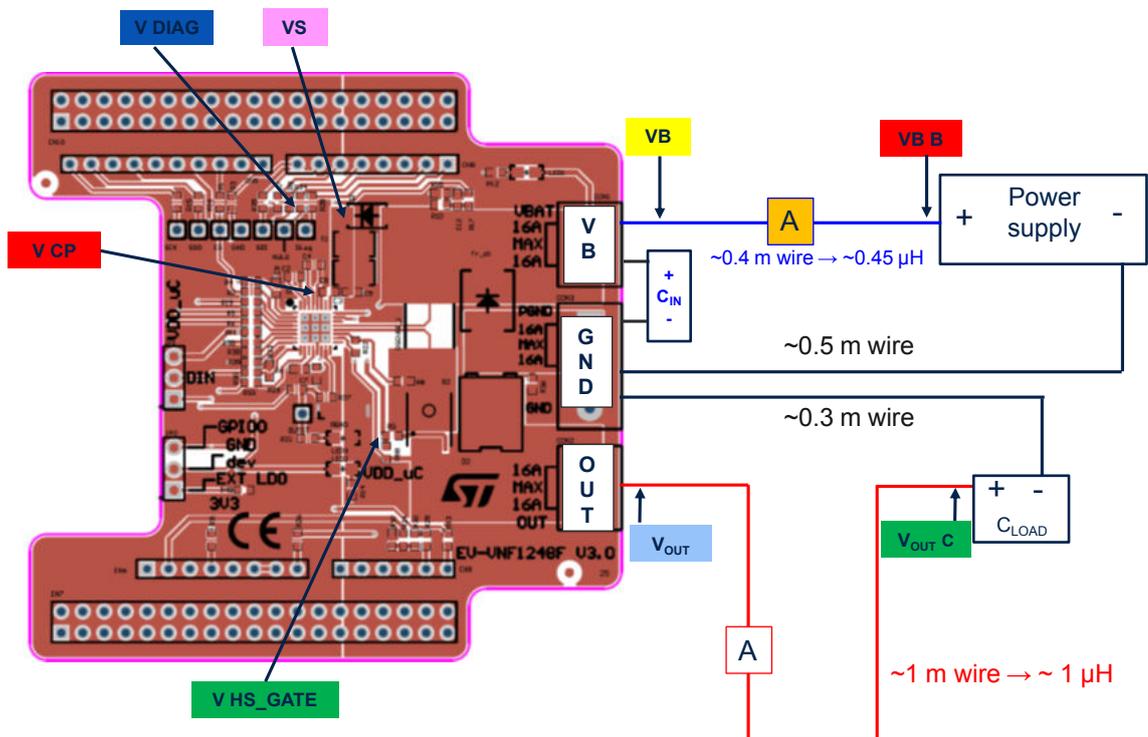
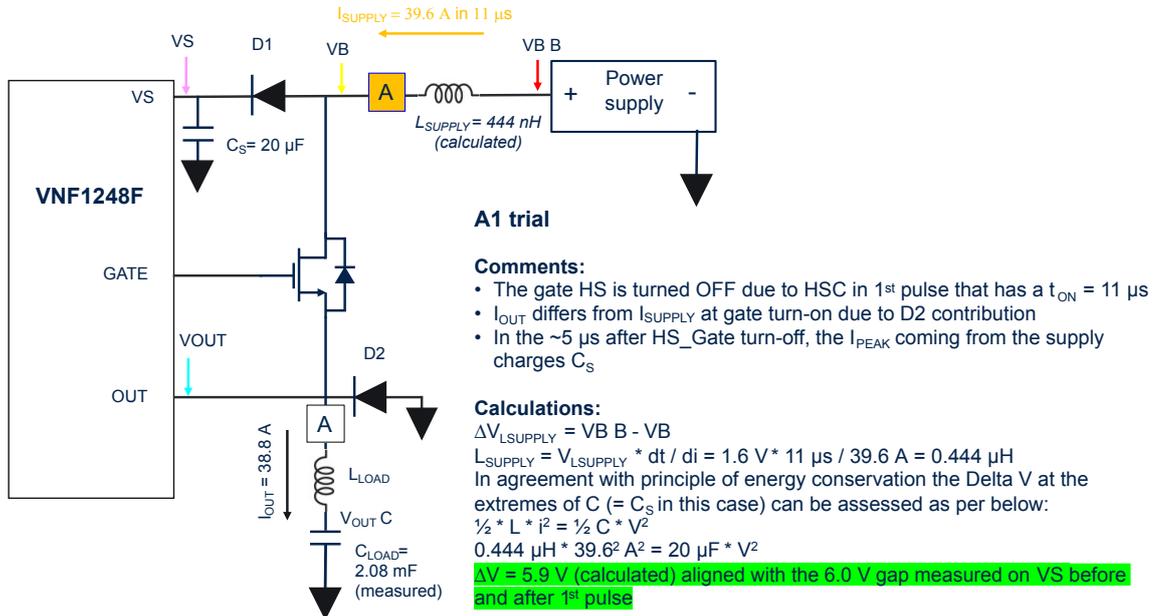


Figure 18. Schematic of applicative circuit used to assess the dimension of C_{IN}



First of all, we focused on the waveforms captured during the 1st pulse related to trial setup A1, in which no C_{IN} was mounted, to assess the L_{SUPPLY} value and develop a model able to relate the VS step to the adopted setups.

Figure 20. Schematic and calculation adopted in setup A1



To consolidate the above model and assess the dimension of C_{IN} value to be added to C_S to achieve the wanted safe ΔV on V_S , we repeated the charge of the same C_{LOAD} with the same setup of trial A1 by inserting different C_{IN} with measured value of 18.6 μF , 37.9 μF , and 42.6 μF and verifying the ΔV on V_S generating trials B1, B2 and B3 with results summarized in table 4 below and detailed in the next paragraphs.

Table 4. Evaluations done to assess L_{SUPPLY}

Trial	C = $C_S + C_{IN}$ (mounted) in μF	Max CP value in V	Max Vs value in V	t_{CHARGE} of C_{LOAD} in ms	I_{PEAK} supply measured in A	HS_GATE t_{ON} measured in μs	$\Delta V_{LSUPPLY}$ measured in V	L_{SUPPLY} calculated in μH	ΔV measured in V	ΔV calculated in V
A1	20	74.7	60.3	20.9	39.6	11.0	1.60	0.444	6.00	5.90
B1	38.6	43.3	29.0	20.6	37.3	10.8	1.60	0.463	4.18	4.09
B2	58.6	34.8	20.4	20.9	31.1	9.3	1.50	0.448	2.70	2.70
B3	63.4	29.8	15.4	20.6	31.1	9.0	1.55	0.449	2.69	2.62

4.1 Trial Setup B1

Trial B1 uses the same setup as trial A1 (DUT in Unlocked state) with the only insertion of C_{IN} of nominal 22 μF (measured 18.6 μF).

The C_{LOAD} is charged in approximately the same time while the max achieved values on CP and VS appear smoother compared to trial A1 as shown in Figure 21.

Figure 21. Waveforms acquired during CCM with setup B1

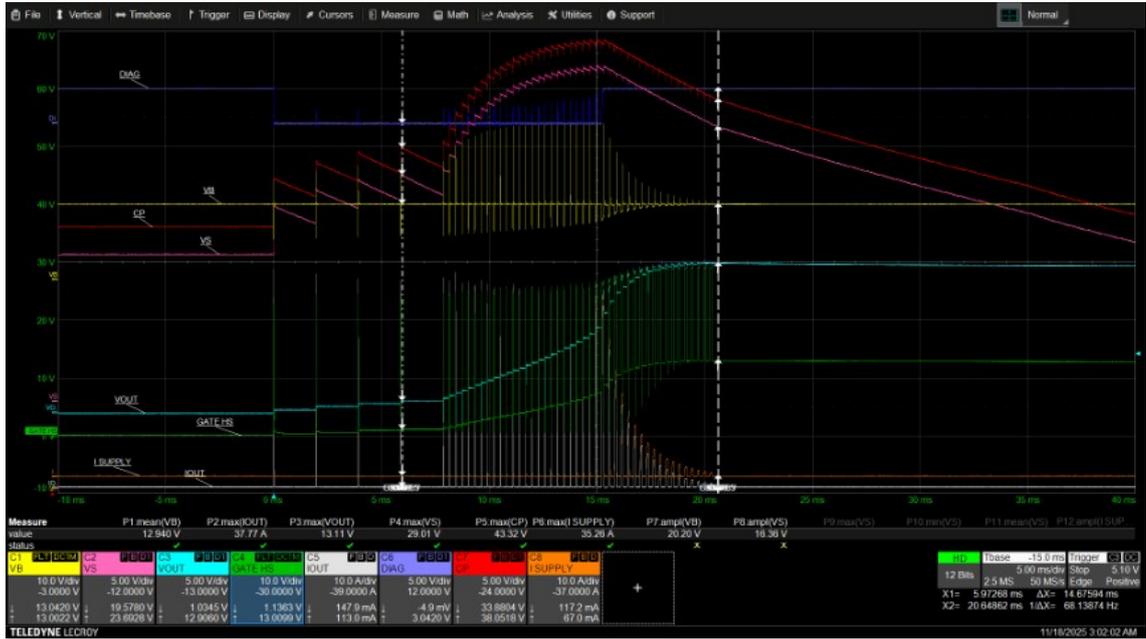


Figure 22. Waveforms collected on 1st CCM pulse using setup B1

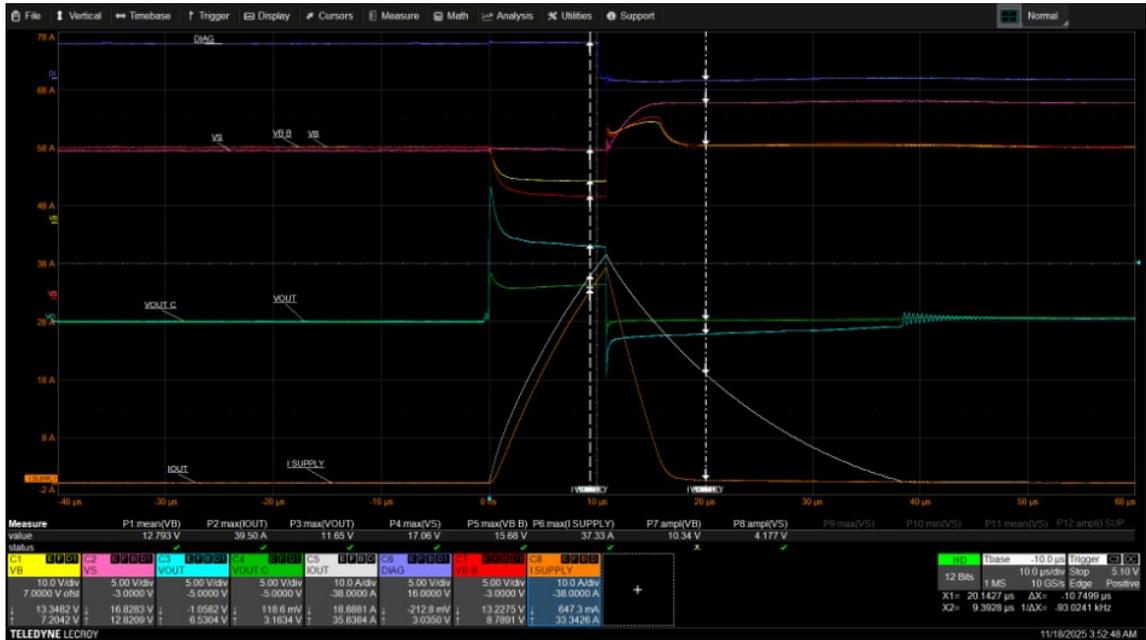
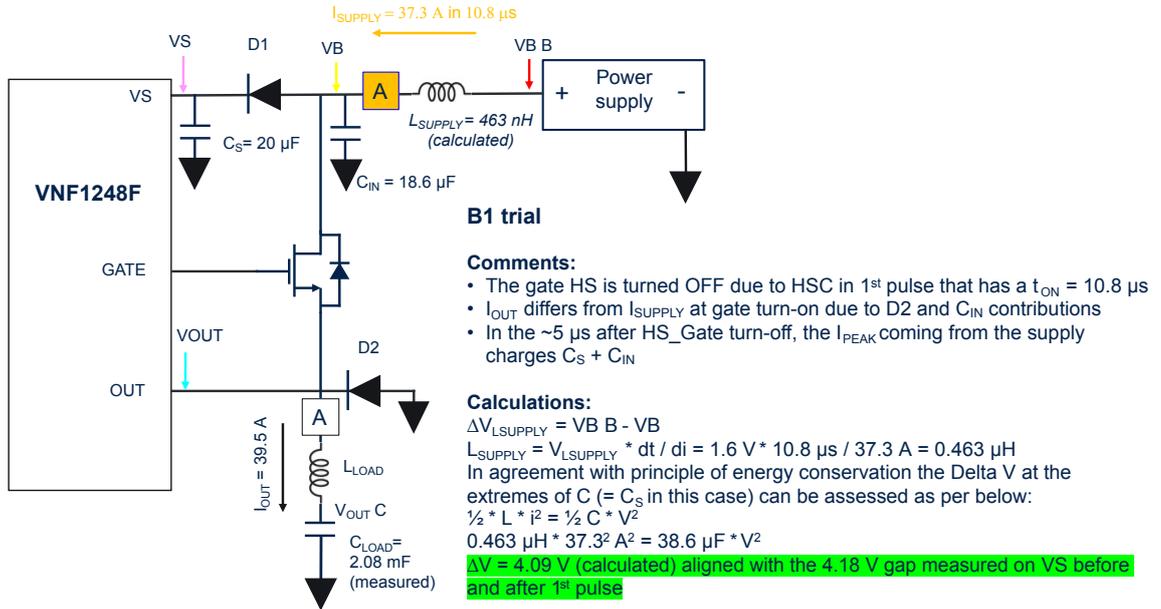


Figure 23. Schematic and calculation adopted in setup B1



4.2 Trial Setup B2

Trial B2 uses the same setup as trial A1 (DUT in Unlocked state) with the only insertion of C_{IN} of nominal $2 \cdot 22 \mu F$ (measured 38.6 μF).

The C_{LOAD} is charged in approximately the same time of trials A1 and B1 while the max achieved values on CP and VS appear even smoother.

Figure 24. Waveforms acquired during CCM with setup B2

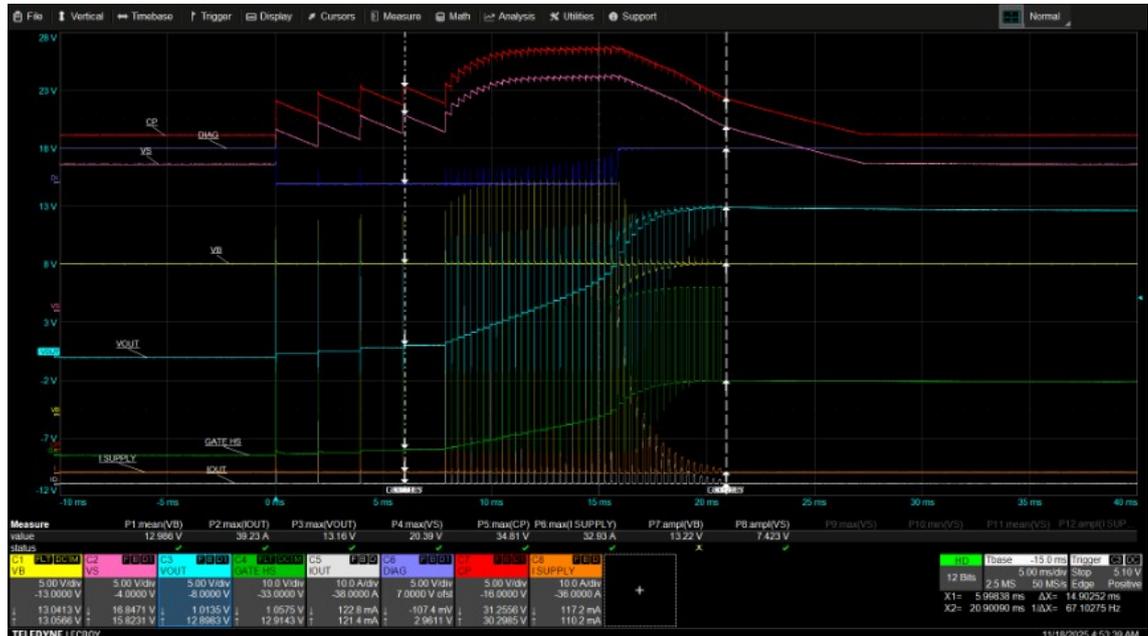


Figure 25. Waveforms collected on 1st CCM pulse using setup B2

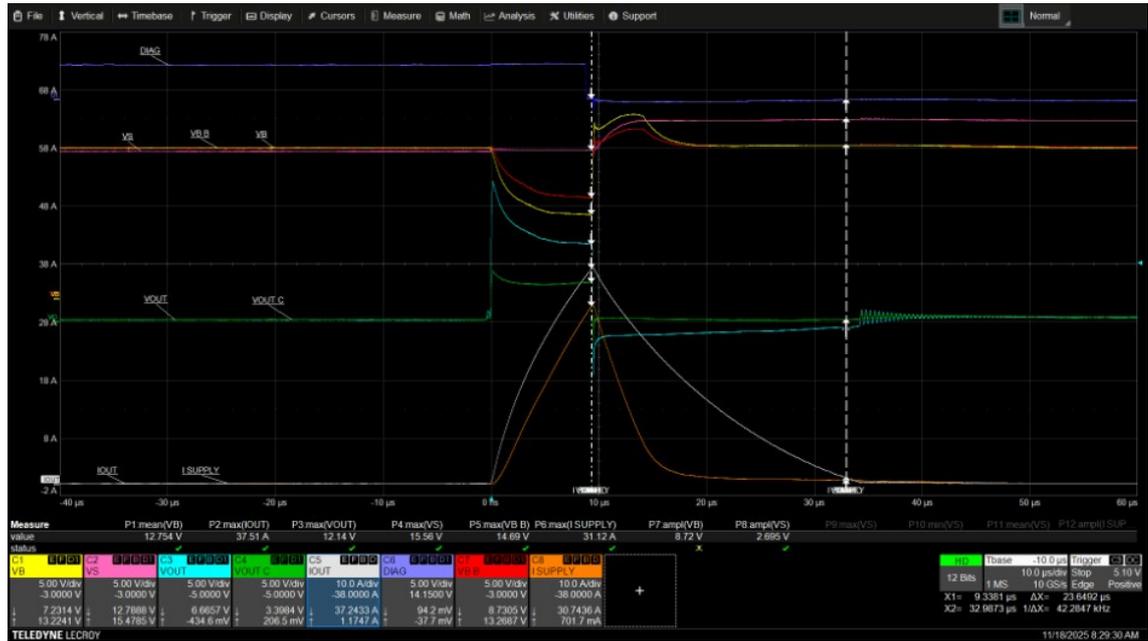
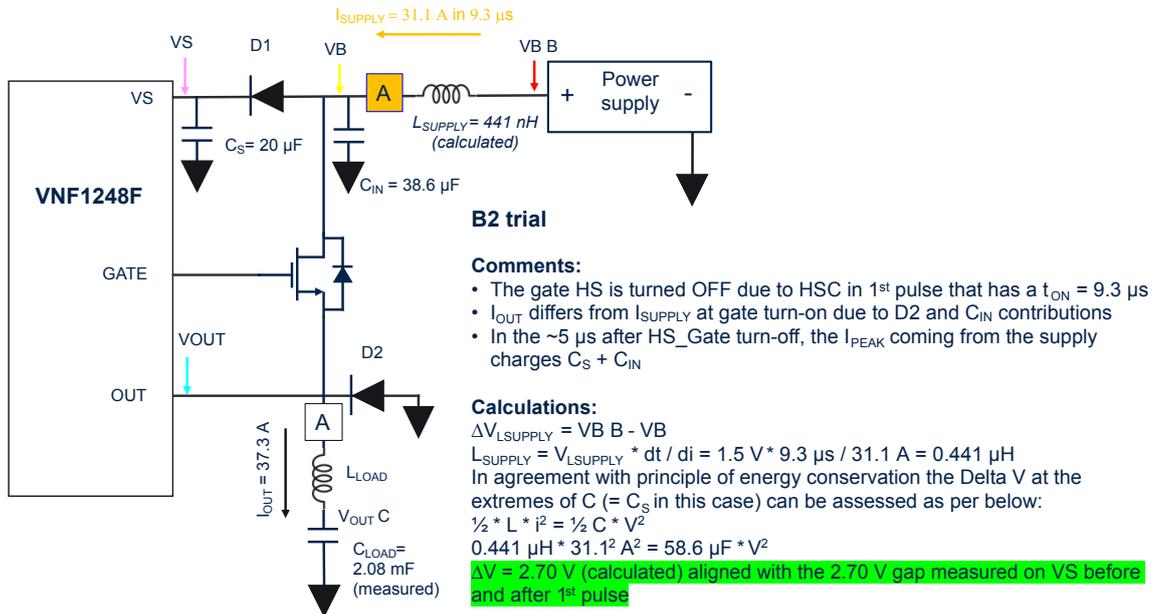


Figure 26. Schematic and calculation adopted in setup B2



4.3 Trial Setup B3

Trial B3 uses the same setup as trial A1 (DUT in Unlocked state) with the only insertion of C_{IN} of nominal 47 μF (measured 43.4 μF).

The C_{LOAD} is charged in approximately the same time of previous trials A1, B1 and B2 while the max achieved values on CP and VS appear even smoother.

Figure 27. Waveforms acquired during CCM with setup B3

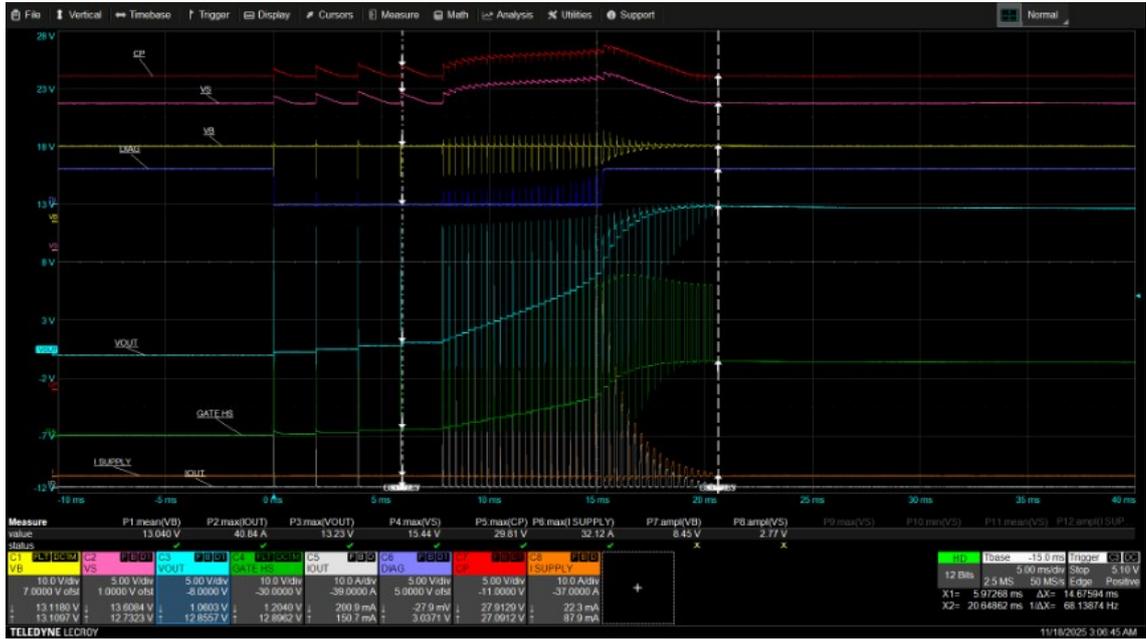


Figure 28. Waveforms collected on 1st CCM pulse using setup B3

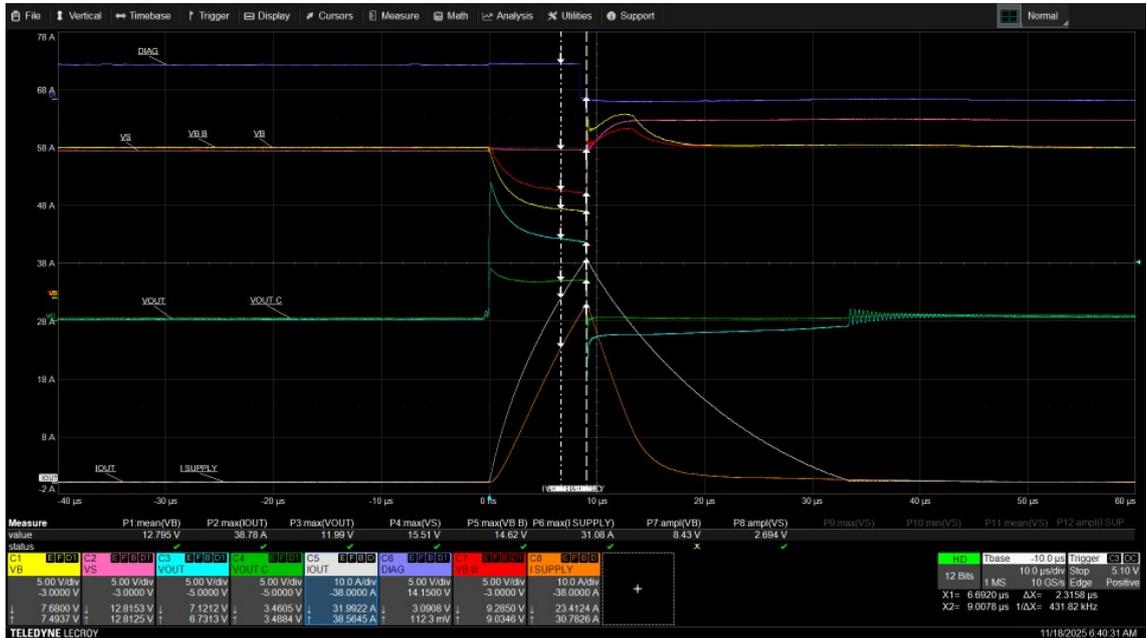
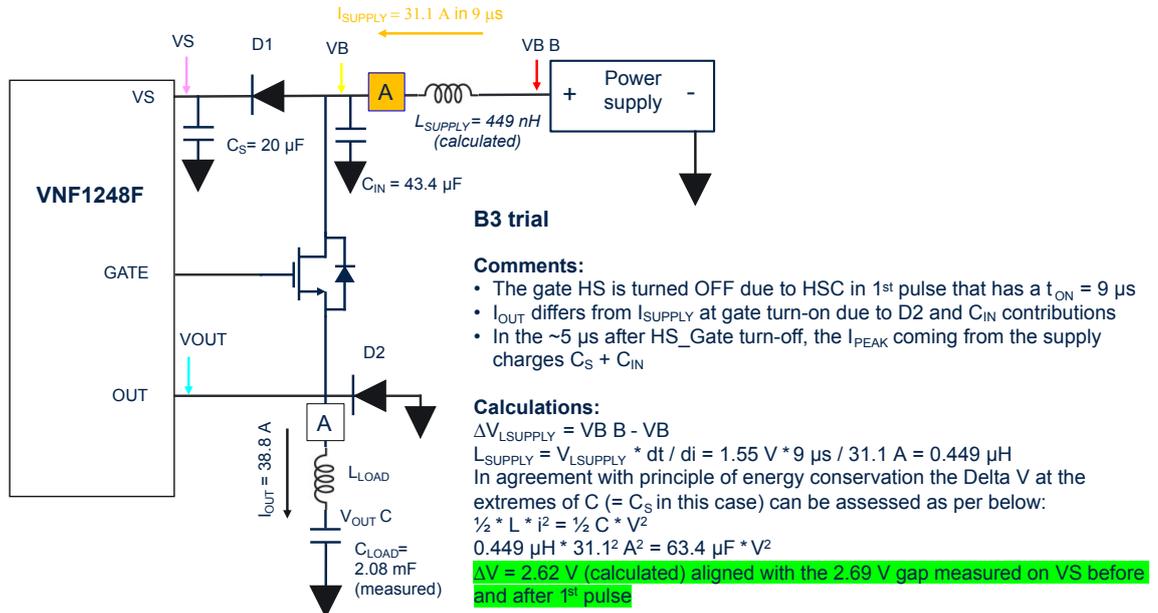


Figure 29. Schematic and calculation adopted in setup B3



Based on the results from above tests, we assessed that $L_{SUPPLY} \sim 450$ nH. Assuming a peak current $I_{PEAK} \sim 10$ A (due to the contribution of $C_S + C_{IN}$), we estimated that the C_{IN} value to be used to limit the ΔV on V_S to 0.4 V (a very safe value that strongly limits the boost effect):

$$\frac{1}{2} * L * i^2 = \frac{1}{2} C * V^2$$

$$0.45 \mu H * 10^2 A^2 = C \mu F * 0.4^2$$

$$C = C_S + C_{IN} = 281 \mu F$$

$$C_{IN} = 261 \mu F$$

4.4 Trial Setup B4

Below is the results of the CCM test using the same setup of trial A1 with insertion of C_{IN} of nominal 300 μF (measured 314 μF) generating trial B4.

Figure 30. Waveforms acquired during CCM with setup B4

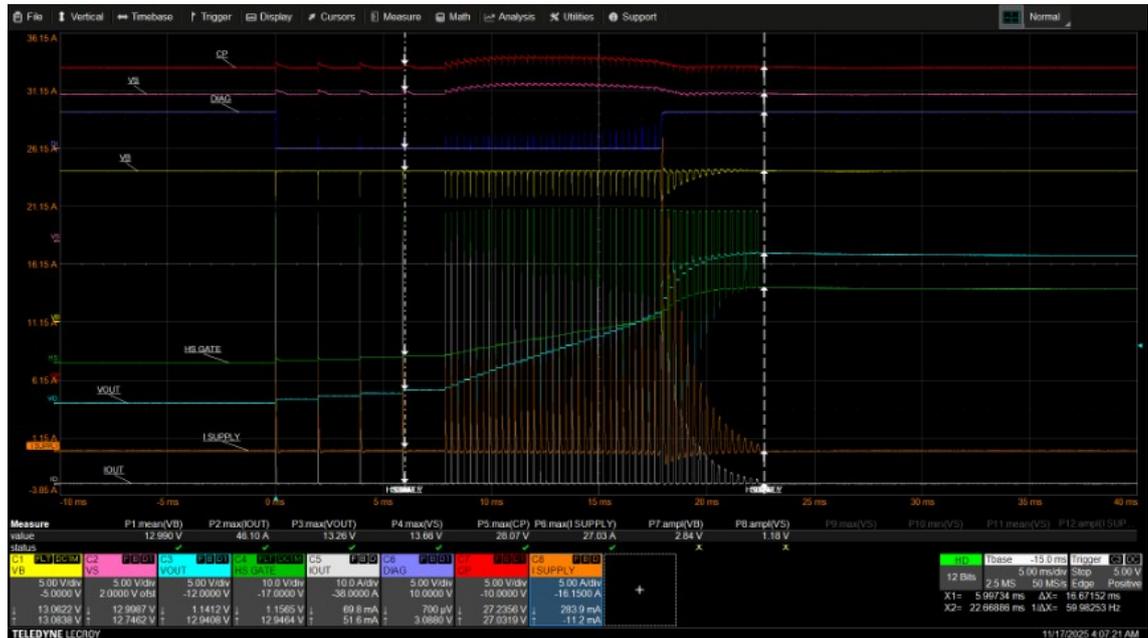
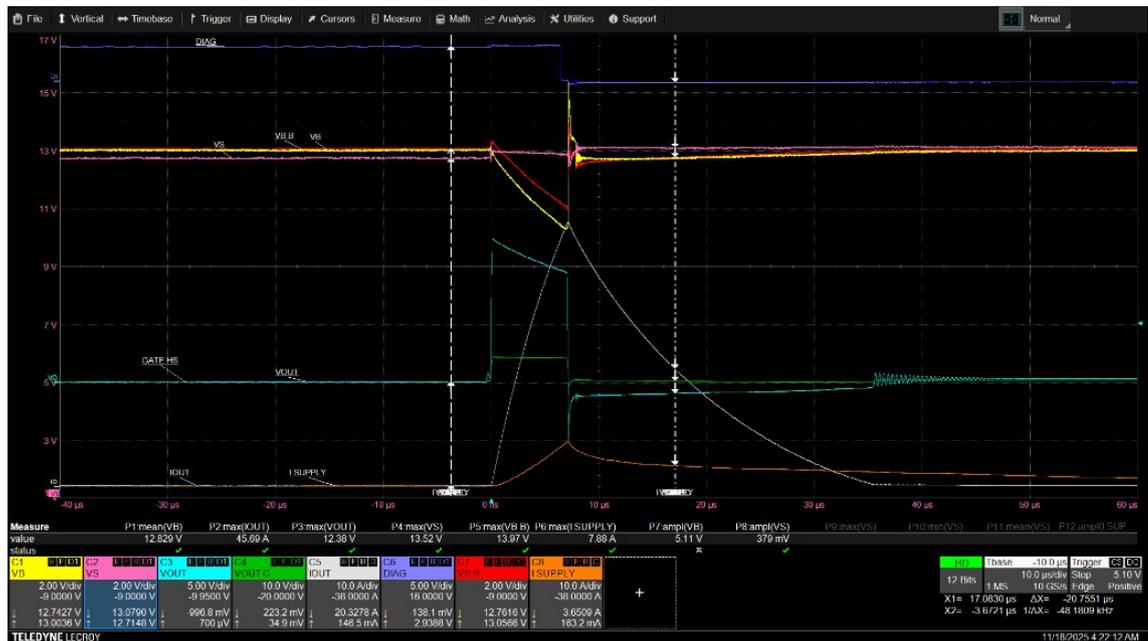


Figure 31. Waveforms collected on 1st CCM pulse using setup B4



The usage of $C_{IN} = 314 \mu\text{F}$ generates the following results:

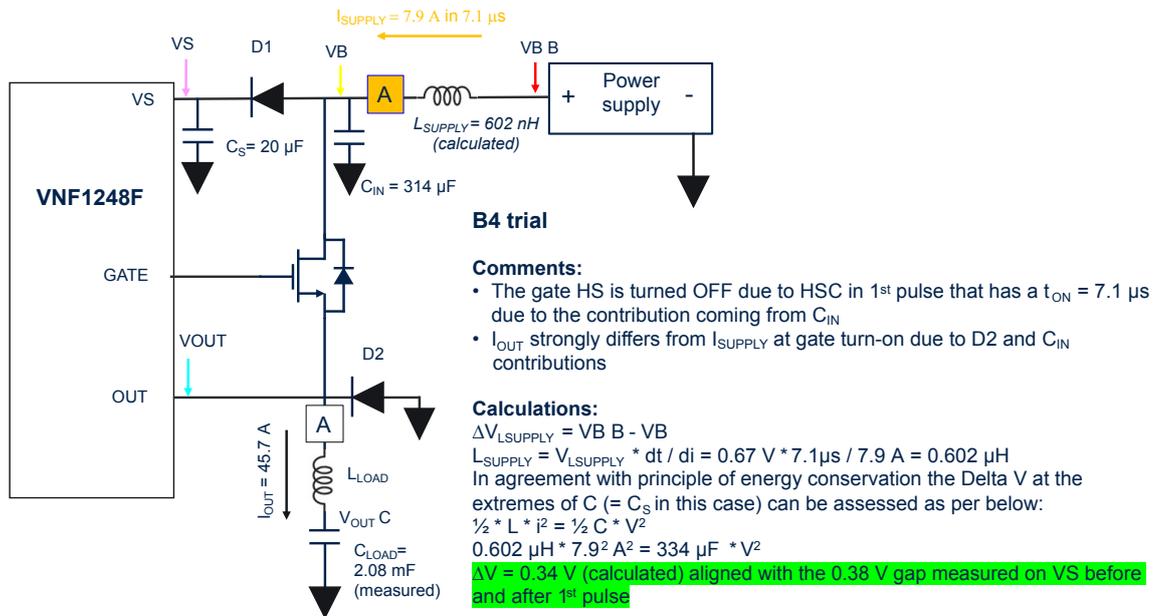
- $t_{\text{CHARGE}} = 22.7 \text{ ms}$
- $I_{\text{PEAK}} = 7.9 \text{ A}$
- $\Delta V_{\text{LSUPPLY}} = V_{\text{B B}} - V_{\text{B}} = 0.67 \text{ V}$
- $\text{HS_GATE } t_{\text{ON}} = 7.1 \mu\text{s}$
- $\Delta V = 0.38 \text{ V}$

The C_{LOAD} is charged in a time slightly longer than in the previous cases (20.8 ms vs 22.7 ms) due to the impact of the greater C_{IN} in the standard phase (in each pulse, the supply must charge both C_{LOAD} and C_{IN}).

The measured gap on VS is close to the estimated 0.4 V, even if the I_{PEAK} resulted lower than assessed (7.9 A vs 10 A) due to the contribution of C_{IN} . Reusing the same model adopted for the previous cases A1, B1, B2 and B3, we estimate for L_{SUPPLY} a value greater than the previously assessed one (602 μH vs 450 μH).

Of course, these little errors are consequences of the adopted simplified model, but the safe wanted gap on VS was achieved, close to expectations.

Figure 32. Schematic and calculation adopted in setup B4



The need for a careful C_{IN} value definition explained in this paragraph is more evident in case of the usage of greater C_{LOAD} or higher V_B that will involve a greater number of pulses in both phases, strongly impacting the max value achievable by VS.

Two examples are reported below using the same setup of trial A1, but differing in the following conditions:

- Trial A4: for the usage as C_{LOAD} of 3.3 mF nominal capacitance (measured 3.17 mF)
- Trial A5: for the usage of $V_B = 20 \text{ V}$

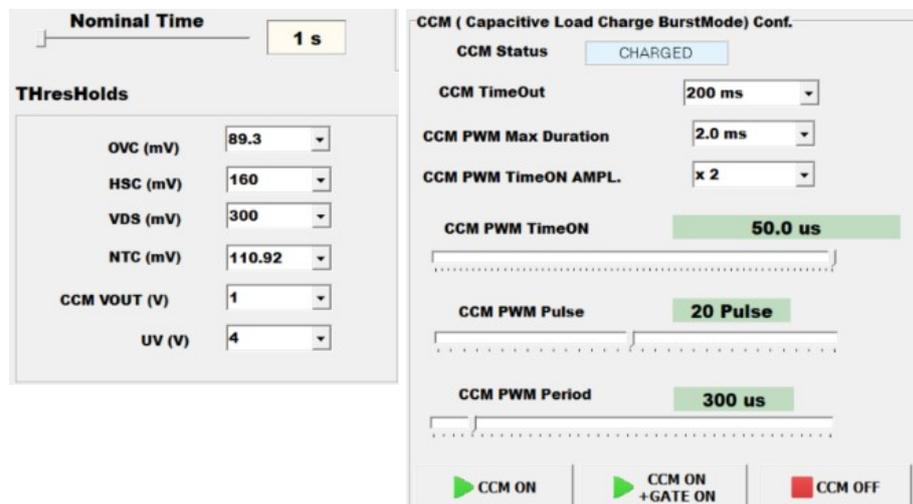
4.5 Trial Setup A4

- $V_B = 13 \text{ V}$
- $R_{SHUNT} = 5 \text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- **$C_{LOAD} = 3.3 \text{ mF}$ (measured 3.17 mF)**
- No C_{IN} mounted, $C_S = 20 \mu\text{F}$

Device in Unlocked state with the following settings:

- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_31 → 89.3 mV
- HSC_THR = VHSC_THRS_15 → 160 mV
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 2 x
- CCM_PWM_SC_T_NB = 20 pulses
- CCM_PWM_T = 300 μs
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in Figure 33

Figure 33. CCM configuration and result from GUI for test setup A4



Result A4:

With the mentioned setup A4, the C_{LOAD} is charged in 12 ms (start phase) + 19.4 ms (standard phase).

In this case, a strong boost effect is visible due to the C_{LOAD} of 3.3 mF vs 2.2 mF adopted in trial A1. VS reached a maximum value of 67.7 V very close to the AMR that is not violated thanks to the contribution coming from the component Tr_{d1} (SM15T68CAY).

The gap on VS after 1st pulse was 6.08 V.

Figure 34. Waveforms acquired during CCM with setup A4

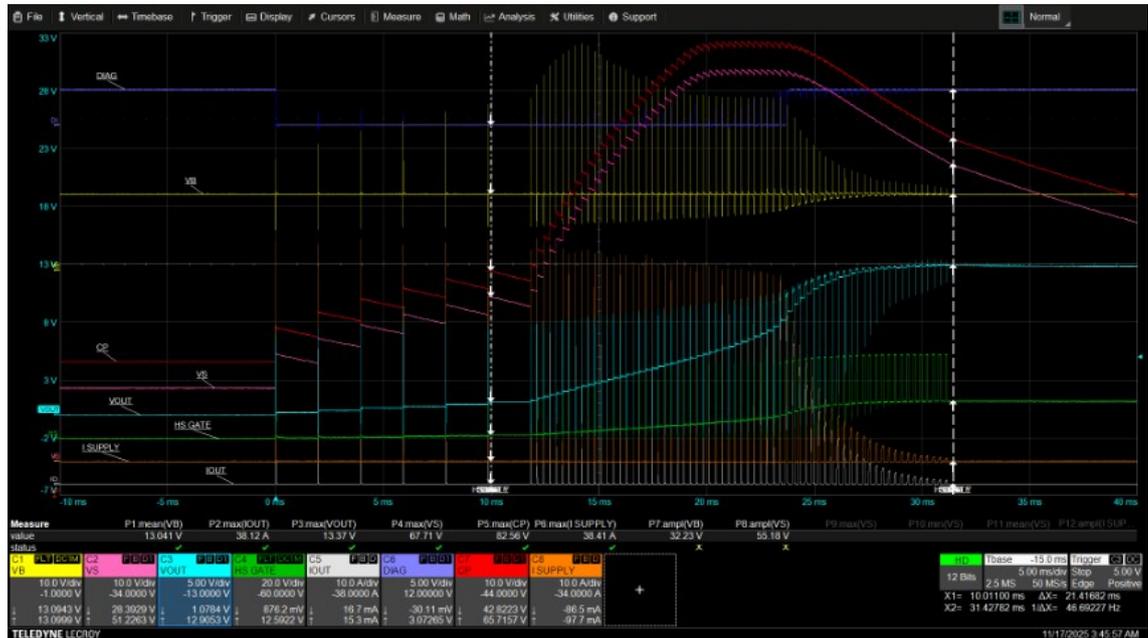


Figure 35. Zoomed view of waveforms acquired at 1st pulse during CCM with setup A4



4.6

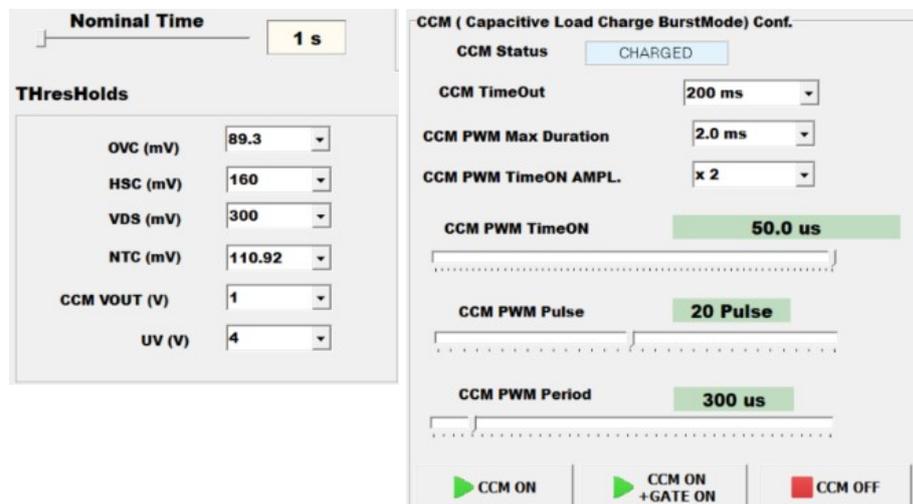
Trial Setup A5

- VB = 20 V
- R_{SHUNT} = 5 mΩ
- Ambient temperature = room temperature ~25°C generating T_J ~35°C
- C_{LOAD} = 2.2 mF (measured 2.08 mF)
- No C_{IN} mounted, C_S = 20 µF

Device in Unlocked state with the following settings:

- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_31 → 89.3 mV
- HSC_THR = VHSC_THRS_15 → 160 mV
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 2 x
- CCM_PWM_SC_T_NB = 20 pulses
- CCM_PWM_T = 300 μs
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in [Figure 36](#)

Figure 36. CCM configuration and result from GUI for test setup A5



Result A5:

With the mentioned setup A5, the C_{LOAD} is charged in 6 ms (start phase) + 24.8 ms (standard phase).

In this case, a strong boost effect is visible due to the VB set at 20 V vs 13 V adopted in trial A1. VS reached a maximum value of 69.1 V very close to the AMR that is not violated thanks to the contribution coming from the component Tr_{d1} [SM15T68CAY](#).

The gap on VS after 1st pulse was 9.15 V.

Figure 37. Waveforms acquired during CCM with setup A5

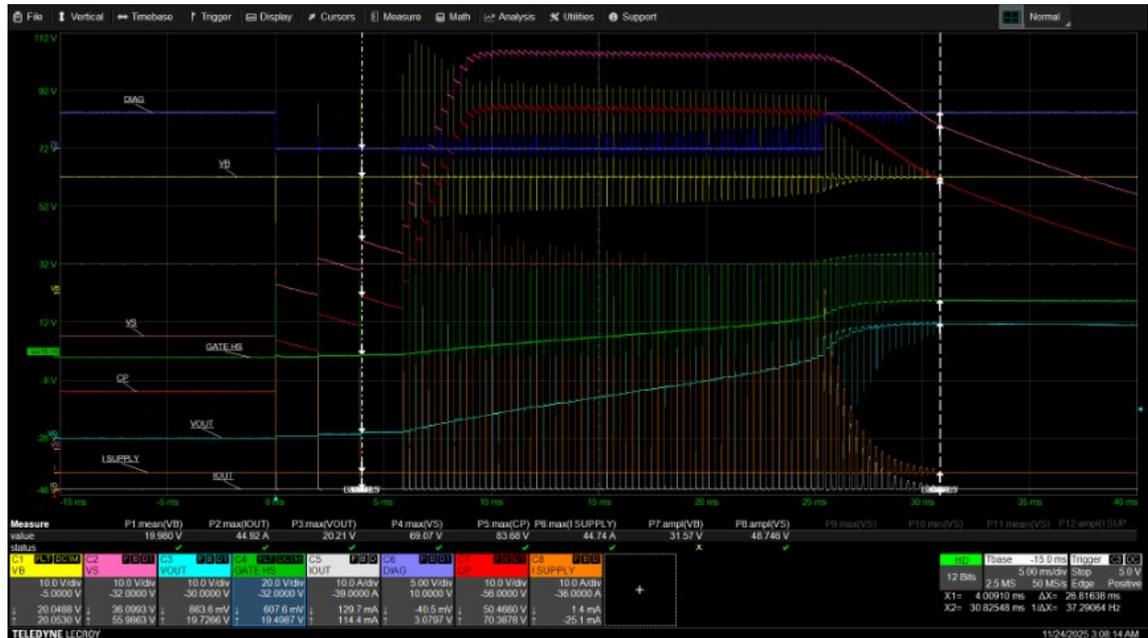


Figure 38. Zoomed view of waveforms acquired at 1st pulse during CCM with setup A5



Based on this analysis, we recommend the end user to perform a careful assessment of the setup conditions including VB, C_{LOAD}, L_{SUPPLY}, and C_{IN} to perform CCM activities in safe conditions.

In this document, we continued the CCM tests by always adopting C_{IN} = 314 µF to verify the impact of various parameters including verifications with VB set at 24 V and 48 V and using greater C_{LOAD} of 4.7 mF and 6.9 mF. As visible in the results reported in the next chapter, the adoption of this C_{IN} always ensures a safe condition for the VNF1248F. In fact, in all cases a VS max well below the AMR was observed.

5 CCM application measurements tuning various parameters

This chapter shows several CCM measurements carried out on the [EV-VNF1248F](#) easy board, modifying one or more variables listed in [Section 2.1](#).

The overall effects of each parameter are summarized in [Table 5](#).

Table 5. CCM relevant fields

Parameter	Description	Comment	Reference trials
VB	Battery supply voltage of the entire application circuit (range from 6 to 60 V)	It affects the duration of the charge because the greater the VB is, the greater the VOUT value that must be achieved. Fixing all parameters, higher value of VB involves longer charging time	B5 vs C vs D and E vs F vs G
VOUT threshold	OUT pin voltage to be reached during the first charging phase at low frequency in ton protection (range from 1 to 5 V)	Due to the low frequency of the start charging phase, the higher the CCM_VOUT_THR, the longer the duration of the 1 st phase in case of a high PWM pulse number setting. Fixing all parameters a greater CCM_VOUT_THR involves a longer time to charge	C vs F
PWM start period	Period used in the first charging phase at low frequency in ton protection (range from 2 to 4 ms)	Fixing all parameters a greater CCM_PWM_SC_T duration involves a longer time to charge	C vs G
PWM period	It refers to the period of standard charging phase (range from 0.2 to 4 ms)	Fixing all parameters, the higher the CCM_PWM_T, the longer the charging time because it reduces the GATE turn ON frequency	E vs H
PWM t_{ON} multiplying factor	It is an amplifier of the PWM Time ON duration in the standard charging phase (range from 1 to 8 x)	Fixing all parameters, the higher CM_PWM_TON_MF, the shorter the charging time because it increases the duty cycle and GATE turn ON duration	K vs L
PWM t_{ON} time	It defines the CCM PWM time ON duration in standard charging phase in combination with PWM ton multiplying factor (range from 1 to 50 μ s in case of multiplying factor=1x arriving at 400us in case of multiplying factor = 8x or ton protection)	Fixing all parameters, the higher the CM_PWM_TON, the shorter the charging time . Once t _{ON} protection is selected, the high-side driver is controlled by protection only (hard short, fuse latch) so that this configuration assures the maximum ton value limited only by i2t algorithm	E vs K vs L vs M
OVC	Nominal overcurrent threshold for the eFuse emulation (VOVC_THRS range from 6 to 89.3 mv)	It affects the duration of the charge only in the portion of the standard charging phase in which hard short (HSC) is not triggered. Fixing all parameters, the higher this value, the lower the charging time	E vs O vs Q vs R
HSC	It configures the Delta V reading at extremes of R _{SHUNT} triggering the hard short protection threshold (VHSC_THRS, range from 20 mV to 160 mV)	It affects the duration of the charge because it has a direct impact on the amplitude in current of each pulse triggered by the HSC protection (start phase) and i2t or fuse protection (standard phase). Fixing all parameters, the higher the HSC threshold, the lower the charging time	E vs P vs Q vs R
R_{SHUNT}	high precision sense resistance connected between sense P and sense N	It affects the duration of the charge because it has a direct impact on the current sense voltage drop at its extremes influencing HSC and OVC currents. Greater R_{SHUNT} involves longer charging time .	E vs W

Parameter	Description	Comment	Reference trials
Ambient temperature	Operative temperature of the device	The Tj of VNF1248 device has a negligible impact on charging time. The heating of the entire circuit also affects MOSFET, which has very little effect on reducing the charging time.	U vs W
TNOM	Value of nominal time required for the fuse emulation.	It has a little effect in time to charge affects the duration of standard charging phase where i2t protection is triggered after a longer time, assuring a longer HS_GATE time ON. The greater tnom is, the shorter the charging time	X1 vs X2
PWM start pulses max number	It refers to the max number of attempts allowed in start charging phase at low frequency to achieve the set CCM VOUT (CCM_PWM_SC_T_NB range from 5 to 50 pulses)	Higher value is suggested in case of a higher CCM_VOUT_THR value to avoid CHARGE INCOMPLETE due to CCM_VOUT_THR not achieved or short circuit on OUT	H vs H-bis and Y
CCM timeout	Maximum time allowed to start + standard charging phases (CCM_TIMEOUT range from 200 to 400 ms) independently of the successful charge of the load	Higher values are suggested in case of a higher VB, RSHUNT, CCM_VOUT_THR, the longer the CCM_PWM_SC_T duration, the greater capacitance and lower values of CCM PWM duty cycle in start phase and standard phase, OVC, HSC	J vs J-bis

The overall collected results are summarized in [Table 6](#).

Table 6. Summary of all performed trials

Trial	VB	VOUT (V)	PWM start period (ms)	PWM Period (us)	PWM Time ON (us)	PWM Time ON Ampl.	OVC (mV)	HSC (mV)	TNOM (s)	TJ (°C)	RSHUNT (mΩ)	C _{LOAD} ⁽¹⁾ (mF) Measured - nominal	MAX Vs (V)	Number of pulses in start phase - duration in ms	Duration of charging phase (ms)	Time to charge (ms)
B4	13	1	2	300	50	2	89.3	160	1	35	5	2.08 - 2.2	13.7	4 - 8	14.7	22.7
B5	13	1	2	50	3	1	89.3	160	1	35	5	2.08 - 2.2	13.7	13 - 26	169	195
B6	13	1	2	300	50	2	89.3	160	1	35	5	3.17 - 3.3	13.9	5 - 10	22.3	32.3
C	24	1	2	300	50	2	89.3	160	1	35	5	3.17 - 3.3	26.7	3 - 6	53.6	59.6
D	48	1	2	300	50	2	89.3	160	1	35	5	3.17 - 3.3	52.2	2 - 4	131	135
E1 ⁽²⁾	13	1	2	300	50	2	89.3	160	1	35	5	4.52 - 4.7	13.8	7 - 14	30	44.0
F	24	1	2	300	50	2	89.3	160	1	35	5	4.52 - 4.7	27	4 - 8	77.7	85.7
G	48	1	2	300	50	2	89.3	160	1	35	5	4.52 - 4.7	52.2	2 - 4	220.6	224.6
H	13	5	2	300	50	2	89.3	160	1	35	5	4.52 - 4.7	13.3	48 - 95	18.4	113
I	13	1	4	300	50	2	89.3	160	1	35	5	4.52 - 4.7	13.7	7 - 28	31.8	57.8
J	13	1	2	3000	50	2	89.3	160	1	35	5	4.52 - 4.7	13.0	7 - 14	321.6	335.6
K	13	1	2	300	10	2	89.3	160	1	35	5	4.52 - 4.7	13.7	7 - 14	111.8	125.8
L	13	1	2	300	30	8	89.3	160	1	35	5	4.52 - 4.7	13.7	6 - 12	24.3	36.3
M	13	1	2	300	Ton Prot	2	89.3	160	1	35	5	4.52 - 4.7	13.7	6 - 12	21.6	33.6
N	13	1	2	50	Ton Prot	2	89.3	160	1	35	5	4.52 - 4.7	16.1	7 - 14	3.9	17.9
O	13	1	2	300	50	2	6	160	1	35	5	4.52 - 4.7	13.8	7 - 14	39.8	53.8
P	13	1	2	300	50	2	89.3	80	1	35	5	4.52 - 4.7	13.0	14 - 28	87.2	115.1
Q1	13	1	2	300	50	2	6	20	1	35	5	4.52 - 4.7	12.8	26 - 52	348	incomplete
Q2	13	1	2	300	50	2	44.5	60.6	1	35	5	4.52 - 4.7	13.0	16 - 32	127	159
R1	48	1	2	300	50	2	44.5	60.6	1	35	5	4.52 - 4.7	51.7	1 - 2	398	incomplete

Trial	VB	VOUT (V)	PWM start period (ms)	PWM Period (us)	PWM Time ON (us)	PWM Time ON Ampl.	OVC (mV)	HSC (mV)	TNOM (s)	TJ (°C)	R _{SHUNT} (mΩ)	C _{LOAD} ⁽¹⁾ (mF) Measured - nominal	MAX Vs (V)	Number of pulses in start phase - duration in ms	Duration of charging phase (ms)	Time to charge (ms)
R2	48	1	2	300	50	2	69.5	91.9	1	35	5	4.52 – 4.7	51.9	3-6	359	365
S	13	1	2	300	50	2	89.3	160	1	35	5	6.69 – 6.9	14.1	9-18	45.5	63.5
T	13	1	2	300	Ton Prot	2	89.3	160	1	35	5	6.69 – 6.9	14.1	8-16	33.4	49.4
U	13	3	2	300	50	2	89.3	91.9	1	35	5	4.52 – 4.7	13.2	12-24	70.1	94.1
V	13	3	2	300	50	2	89.3	91.9	1	100	5	4.52 – 4.7	13.4	10-20	70	90
W	13	1	2	300	50	2	89.3	160	1	35	20	4.52 – 4.7	12.9	17-34	219.5	253.5
X1	13	1	2	500	50	8	10.4	80	1	35	5	4.52 – 4.7	13.0	12-24	144.4	168.4
Y2	13	1	2	500	50	8	10.4	80	511	35	5	4.52 – 4.7	13.0	12-24	135.1	159.1
Y	13	1	2	300	50	2	89.3	160	1	35	5	Short circuit	13.1	20-40	NA	incomplete
Z1	13	4	2	1000	50	2	89.3	160	1	35	5	4.52 – 4.7	13.0	37-74	41.4	115.4
Z2 ⁽³⁾	13	4	2	1000	50	2	89.3	160	1	35	5	4.52 – 4.7	13.0	38-76	44.4	120.4
Z3	13	4	2	1000	50	2	89.3	160	1	35	5	4.52 – 4.7	13.0	NA	NA	Stopped after 46.8 ms
Z4 ⁽³⁾	13	4	2	1000	50	2	89.3	160	1	35	5	4.52 – 4.7	13.0	37-74	NA	Stopped after 85.6 ms
E2 ⁽⁴⁾	13	1	2	300	50	2	89.3	160	1	35	5	4.52 – 4.7	13.8	7-14	31	45

1. C_{LOAD} is connected to OUT through 1 m wire

2. Trial-Setup E1 was verified with device both in Unlocked and Fail-safe states

3. Z2 and Z4 trials were performed with DUT in Fail-safe state while all other trials were verified with DUT in Unlocked state

4. E2 is the only trial performed in Unlocked state sending CCM ON + HS_GATE ON

Note: The values modified with respect to the reference setup adopted in Trial E1 are shown in bold (reference values are in italic)

Note: 314 μF (3 x 100 uF – 100 V) is connected as C_{IN} on VB vs GND connectors of the evaluation board

5.1 Effect of CCM_PWM_TON before hard short protection triggering

5.1.1 Trial Setup B5

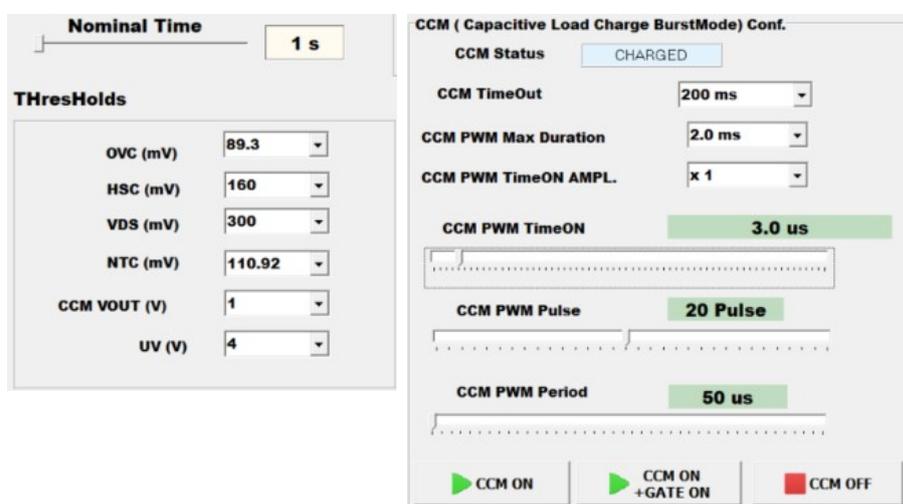
It adopts the same setup as trial B4 modifying the CCM_PWM_TON at 3 μs vs 100 μs and CCM_PWM_T at 50 μs vs 300 μs to highlight the possibility of interrupting the pulse before the hard short protection triggering.

- **VB = 13 V**
- R_{SHUNT} = 5 mΩ
- Ambient temperature = room temperature ~25°C generating TJ ~35°C
- **C_{LOAD} = 2.2 mF (measured 2.08 mF)**
- C_{IN} = 314 μF and C_S = 20 μF

Device in Unlocked state with following settings:

- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_31 → 89.3 mV
- HSC_THR = VHSC_THRS_15 → 160 mV
- T_NOM = T_NOM_{MIN} → 1 s
- **CCM_PWM_TON = 3 μs**
- **CCM_PWM_TON_MF = 1 x**
- CCM_PWM_SC_T_NB = 20 pulses
- **CCM_PWM_T = 50 μs**
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in [Figure 39](#)

Figure 39. CCM configuration and result from GUI for test setup B5



Result B5:

With setup B5, the C_{LOAD} is charged in 26 ms (start phase) + 169 ms (standard phase).

The CIN strongly limits the boost effect so that V_S max = 13.7 V.

The reduction of CCM_PWM_TON at 3 μs has a strong impact on the t_{CHARGE} because it interrupts each gate HS pulse (both in start and standard phase) before the triggering of I^2t protection so that the DIAG signal remains high along the charge of the C_{LOAD} .

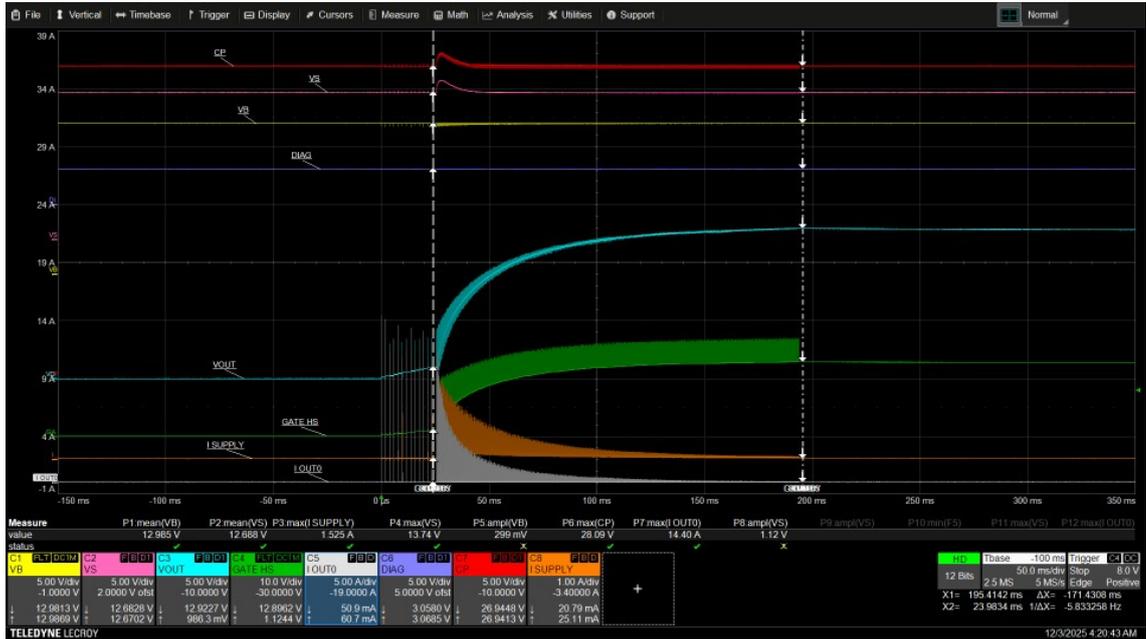
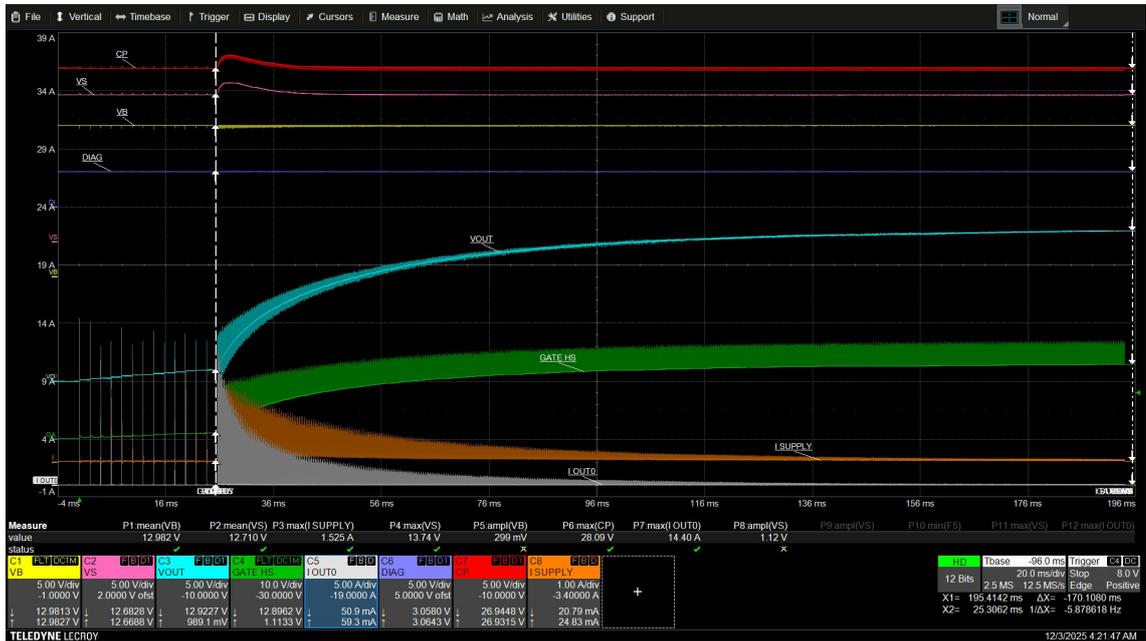
Figure 40. Waveforms acquired during CCM with setup B5

Figure 41. Zoomed view of waveforms acquired during CCM with setup B5


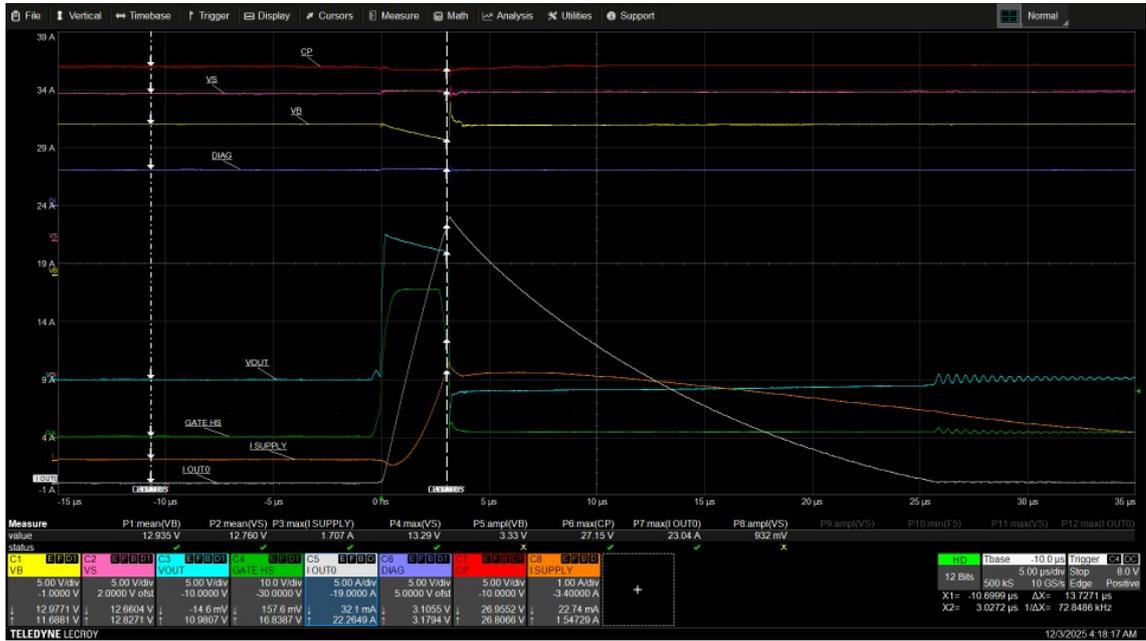
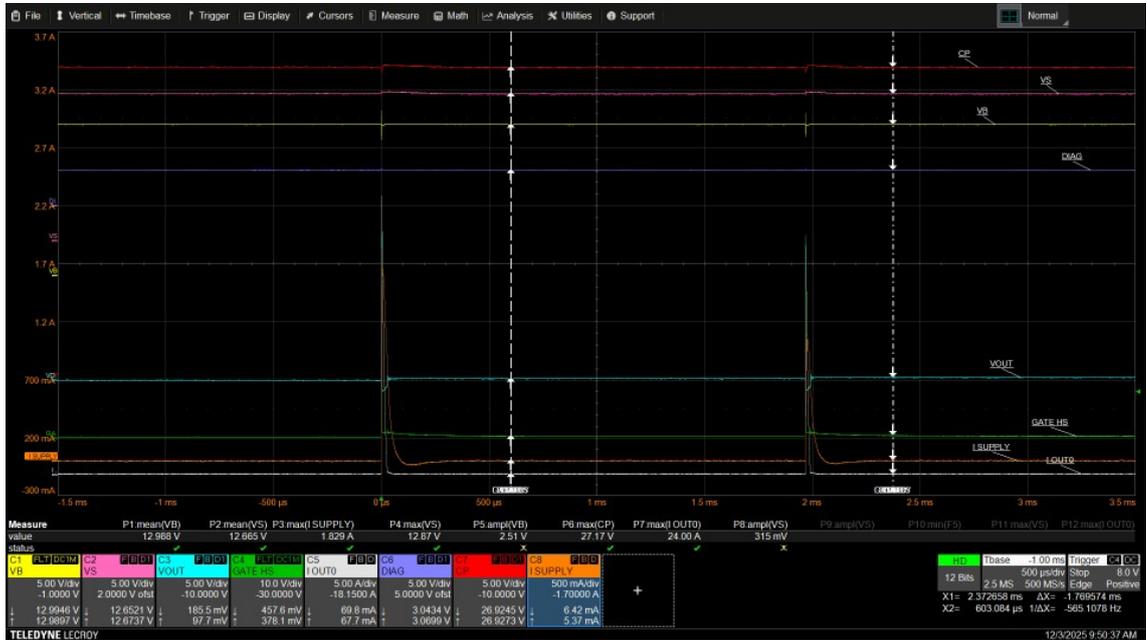
Figure 42. Zoomed view of waveforms acquired at 1st pulse during CCM with setup B5 (TON is 3 μ s and TOFF is \sim 1997 μ s)

Figure 43. Zoomed view of waveforms acquired on first 2 pulses during CCM with setup B5 showing a period of 2 ms


Figure 44. Zoomed view of waveforms acquired at last 3 pulses during CCM with setup B5 (PWM period is 50 μ s with TON = 3 μ s and TOFF = 47 μ s)



5.2 Effect of CLOAD (3.3 mF vs 4.7 mF) and VB (13 V vs 24 V vs 48 V) on CCM

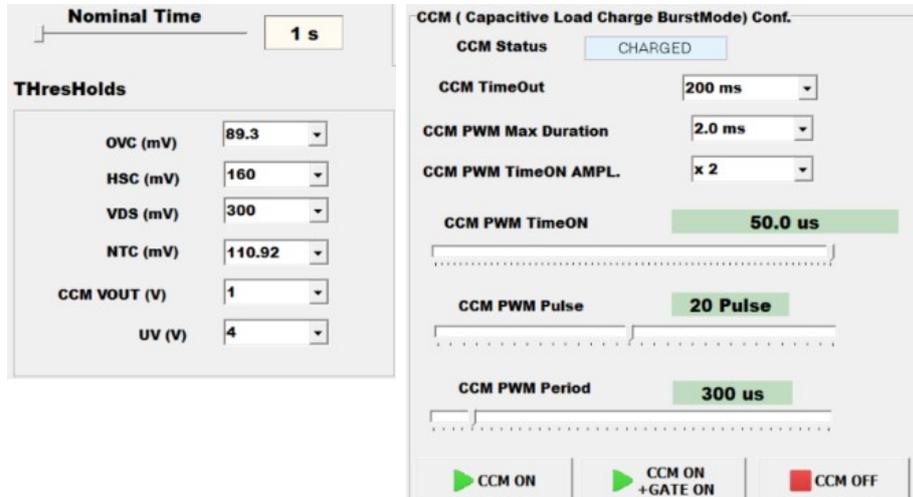
5.2.1 Trial Setup B6

It adopts the same setup as trial B4 with C_{LOAD} increased at 3.3 mF.

- **VB = 13 V**
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- **$C_{LOAD} = 3.3\text{ mF}$ (measured 3.17 mF)**
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

- $CCM_VOUT_THR = 1\text{ V}$
- $OVC_THR = VOC_THRS_31 \rightarrow 89.3\text{ mV}$
- $HSC_THR = VHSC_THRS_15 \rightarrow 160\text{ mV}$
- $T_NOM = T_NOM_{MIN} \rightarrow 1\text{ s}$
- $CCM_PWM_TON = 50\text{ }\mu\text{s}$
- $CCM_PWM_TON_MF = 2\text{ x}$
- $CCM_PWM_SC_T_NB = 20\text{ pulses}$
- $CCM_PWM_T = 300\text{ }\mu\text{s}$
- $CCM_TIMEOUT = 200\text{ ms}$
- $CCM_PWM_SC_T = 2\text{ ms}$
- GUI settings at the end of CCM operations as shown in Figure 45

Figure 45. CCM configuration and result from GUI for test setup B6

Result B6:

With setup B6, the C_{LOAD} is charged in 10 ms (start phase) + 22.3 ms (standard phase).

The C_{IN} strongly limits the boost effect so that $V_S \text{ max} = 13.9 \text{ V}$, and it helps the start phase, which requires only five pulses vs the six observed without C_{IN} in trial A4. The C_{IN} allows higher current peaks to be achieved in the start phase; in fact, on the 1st pulse we reach 45.5 A on setup B6 vs 36.8 A on setup A4, helping to reach the set CCM_VOUT_THR with five instead of six pulses.

The overall t_{CHARGE} of trial B6 is slightly longer than A4 due to the impact of C_{IN} in the portion of standard phase limited by I^2t fuse protection. The duration of standard phase is 22.3 ms with setup B6 vs 19.4 ms with setup A4, because a greater achieved current leads to faster I^2t protection triggering. As a consequence, HS_GATE stays on for shorter THres, increasing the duration of the standard charging phase.

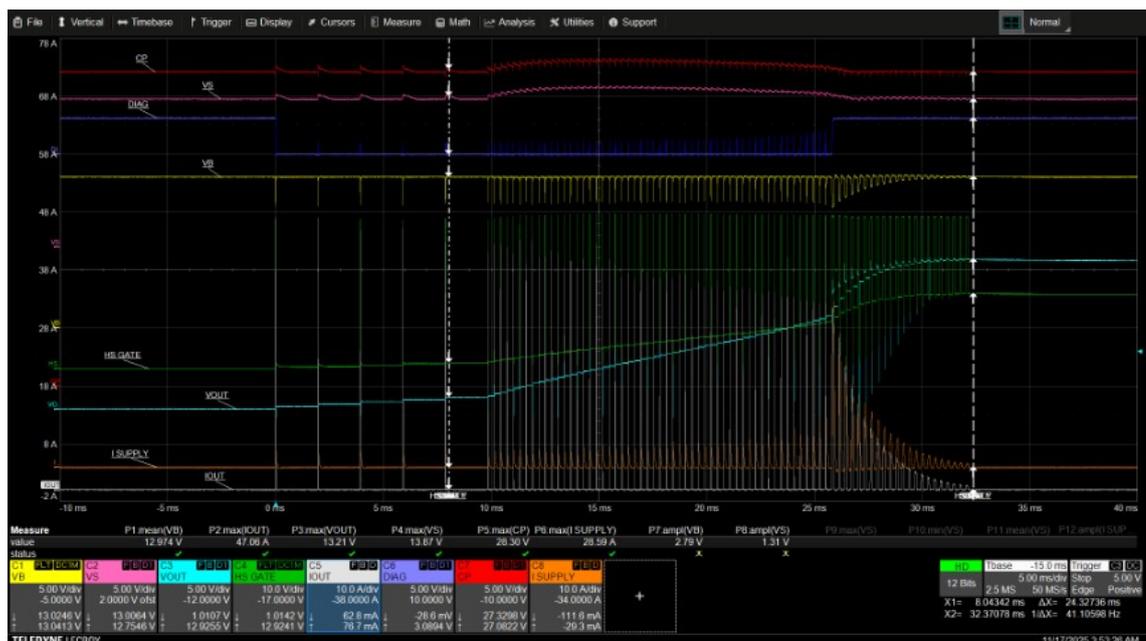
Figure 46. Waveforms acquired during CCM with setup B6


Figure 47. Zoomed view of waveforms acquired at 1st pulse during CCM with setup B6

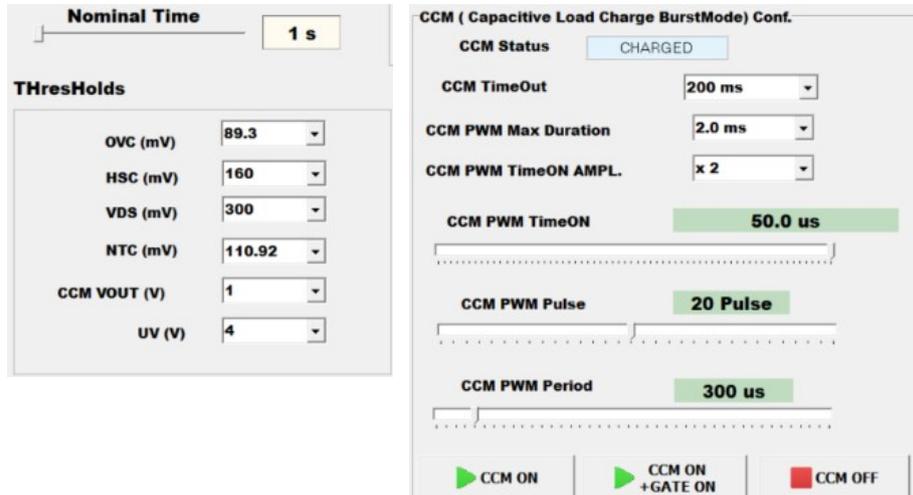

5.2.2 Trial Setup C

It adopts the same setup as trial B6 with VB increased at 24 V vs 13 V.

- **VB = 24 V**
- $R_{SHUNT} = 5 \text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- **$C_{LOAD} = 3.3 \text{ mF}$ (measured 3.17 mF)**
- $C_{IN} = 314 \text{ }\mu\text{F}$ and $C_S = 20 \text{ }\mu\text{F}$

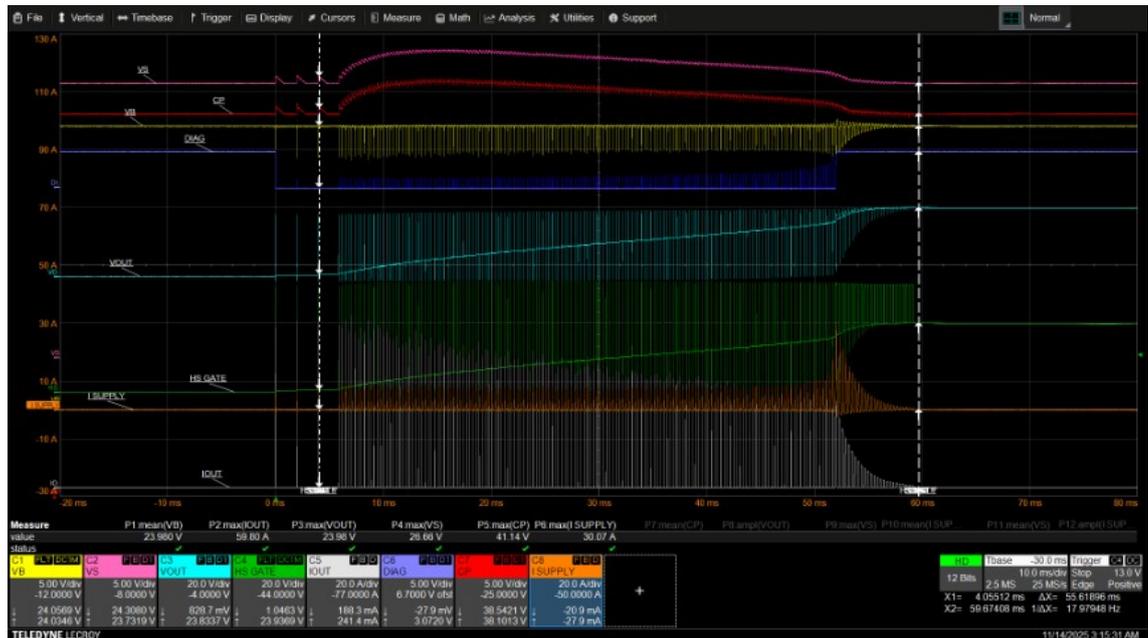
Device in Unlocked state with the following settings:

- $CCM_VOUT_THR = 1 \text{ V}$
- $OVC_THR = VOC_THRS_{31} \rightarrow 89.3 \text{ mV}$
- $HSC_THR = VHSC_THRS_{15} \rightarrow 160 \text{ mV}$
- $T_NOM = T_NOM_{MIN} \rightarrow 1 \text{ s}$
- $CCM_PWM_TON = 50 \text{ }\mu\text{s}$
- $CCM_PWM_TON_MF = 2 \times$
- $CCM_PWM_SC_T_NB = 20 \text{ pulses}$
- $CCM_PWM_T = 300 \text{ }\mu\text{s}$
- $CCM_TIMEOUT = 200 \text{ ms}$
- $CCM_PWM_SC_T = 2 \text{ ms}$
- GUI settings at the end of CCM operations as shown in [Figure 48](#)

Figure 48. CCM configuration and result from GUI for test setup C

Result C:

With setup C, the C_{LOAD} is charged in 6 ms (start phase) + 53.6 ms (standard phase).

A higher V_B involves a higher V_{OUT} to be achieved by increasing the t_{CHARGE} vs the adoption of a lower V_B .

Figure 49. Waveforms acquired during CCM with setup C

5.2.3
Trial Setup D

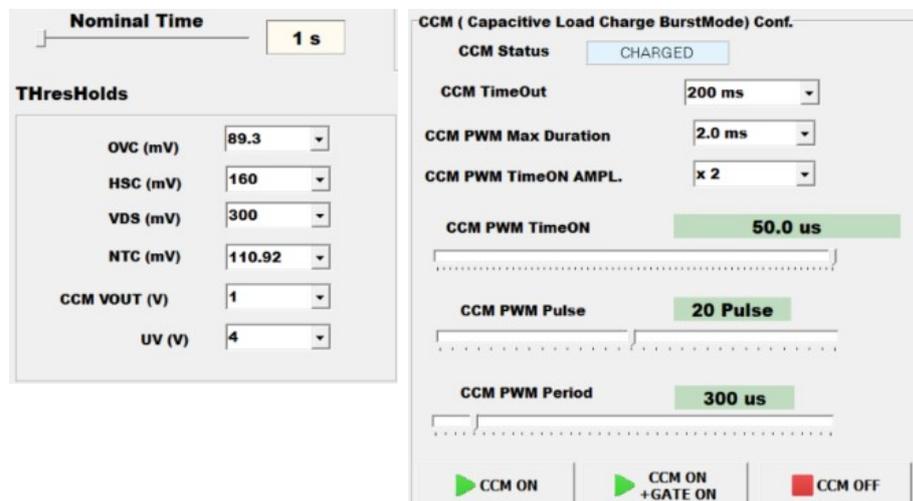
It adopts the same setup as trials B6 with V_B increased at 48 V vs 13 V.

- **$V_B = 48 V$**
- $R_{SHUNT} = 5 m\Omega$
- Ambient temperature = room temperature $\sim 25^\circ C$ generating $T_J \sim 35^\circ C$
- **$C_{LOAD} = 3.3 mF$ (measured 3.17 mF)**
- $C_{IN} = 314 \mu F$ and $C_S = 20 \mu F$

Device in Unlocked state with the following settings:

- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_31 → 89.3 mV
- HSC_THR = VHSC_THRS_15 → 160 mV
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 2 x
- CCM_PWM_SC_T_NB = 20 pulses
- CCM_PWM_T = 300 μs
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in [Figure 50](#)

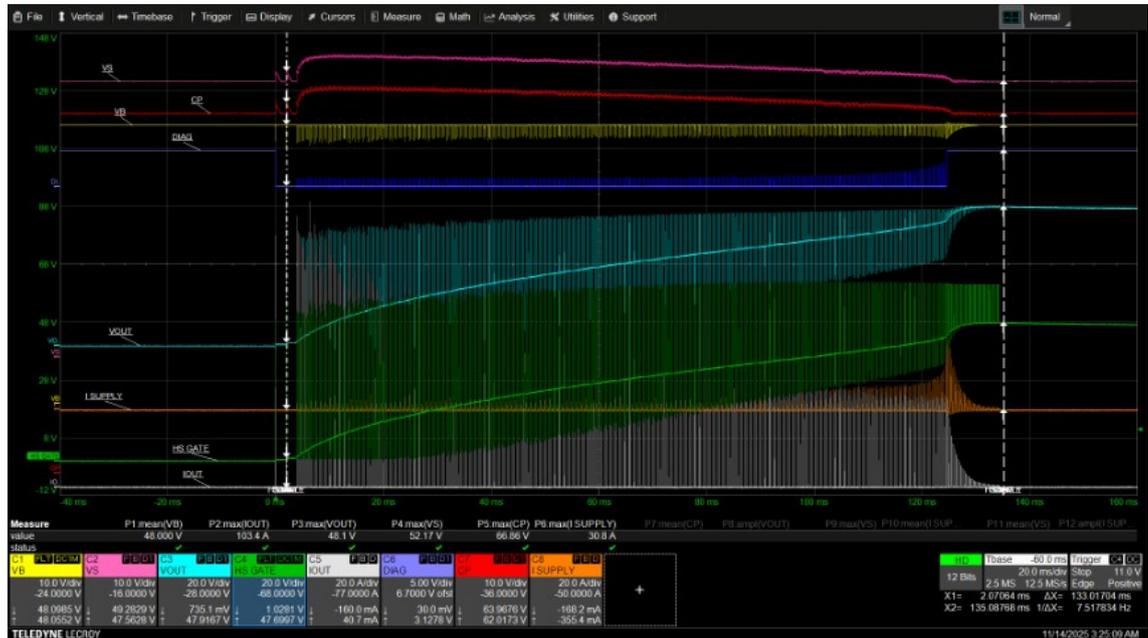
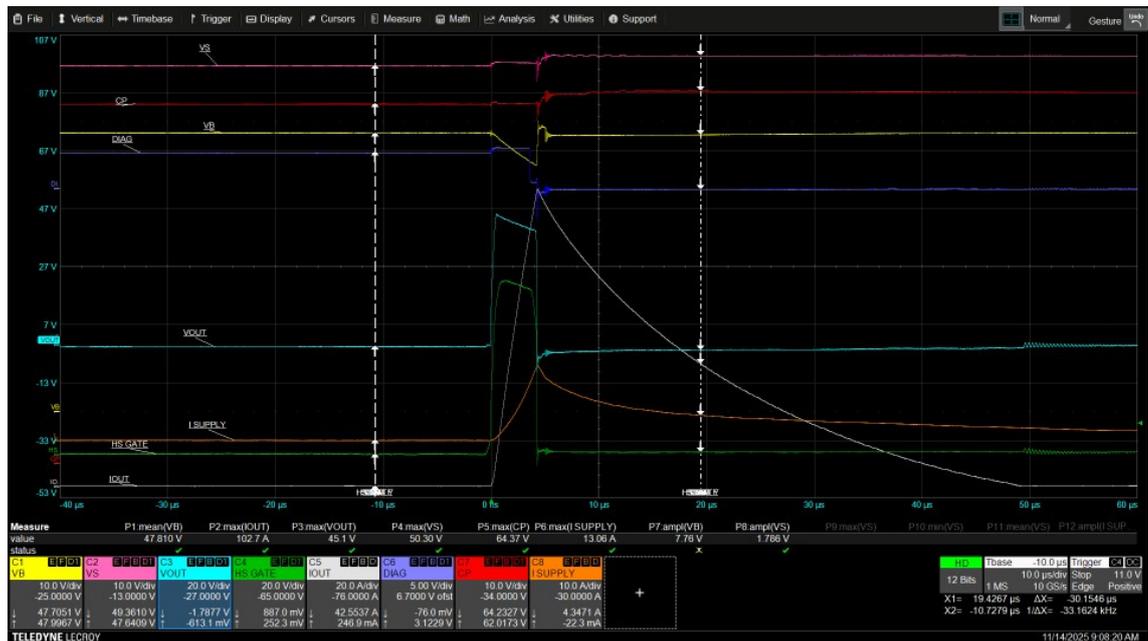
Figure 50. CCM configuration and result from GUI for test setup D



Result D:

With setup D, the C_{LOAD} is charged in 4 ms (start phase) + 131 ms (standard phase).

Thanks to C_{IN} , the max value achieved by VS is 52.2 V and the gap of VS after 1st pulse is 1.79 V.

Figure 51. Waveforms acquired during CCM with setup D

Figure 52. Zoomed view of waveforms acquired at 1st pulse during CCM with setup D


5.2.4

Trial Setup E1

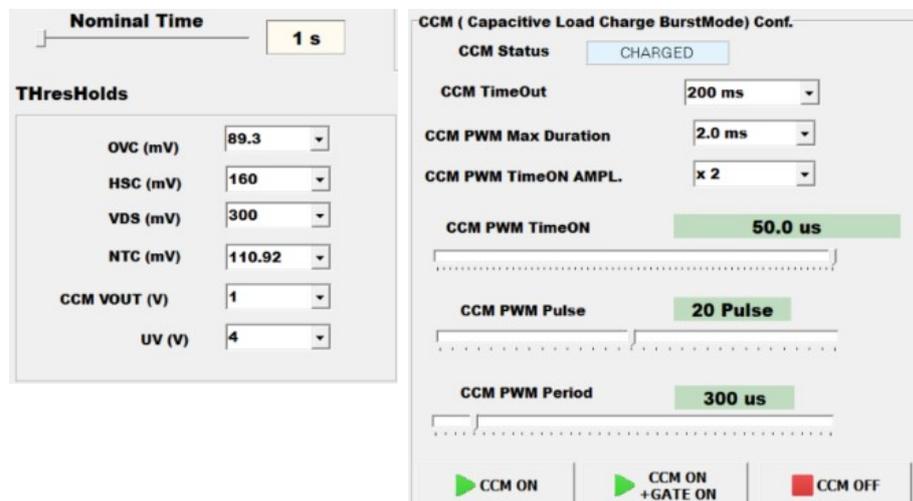
It adopts the same setup as trial B6 with C_{LOAD} increased at 4.7 mF vs 3.3 mF.

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_31 → 89.3 mV
- HSC_THR = VHSC_THRS_15 → 160 mV
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 2 x
- CCM_PWM_SC_T_NB = 20 pulses
- CCM_PWM_T = 300 μs
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in [Figure 53](#)

Figure 53. CCM configuration and result from GUI for test setup E1



Result E1:

With the mentioned setup E1, the C_{LOAD} is charged in 4 ms (start phase) + 30 ms (standard phase).

This setup is verified both in Unlocked and Fail-safe modes with negligible difference in terms of t_{CHARGE} .

The setting of various parameters is written in NVM to maintain in Fail-safe state with the same setup adopted on the device in Unlocked state.

The CCM mode is activated in Fail-safe state by four pulses on DIN. Due to DIN remaining high at the end of the C_{LOAD} charge, the HS_GATE remains ON differently on the trials done in Unlocked state in which the gate was turned OFF at the end of the CCM.

Figure 54. Waveforms acquired during CCM with setup E1 with device in Unlocked mode

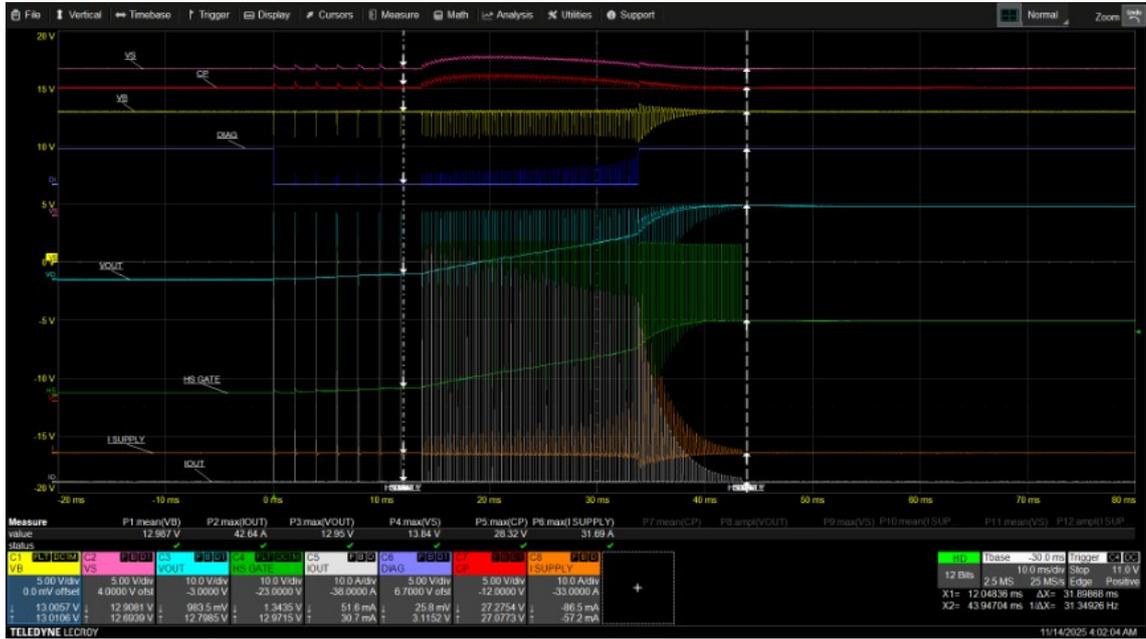


Figure 55. Waveforms acquired during CCM with setup E1 with device in Fail-safe mode

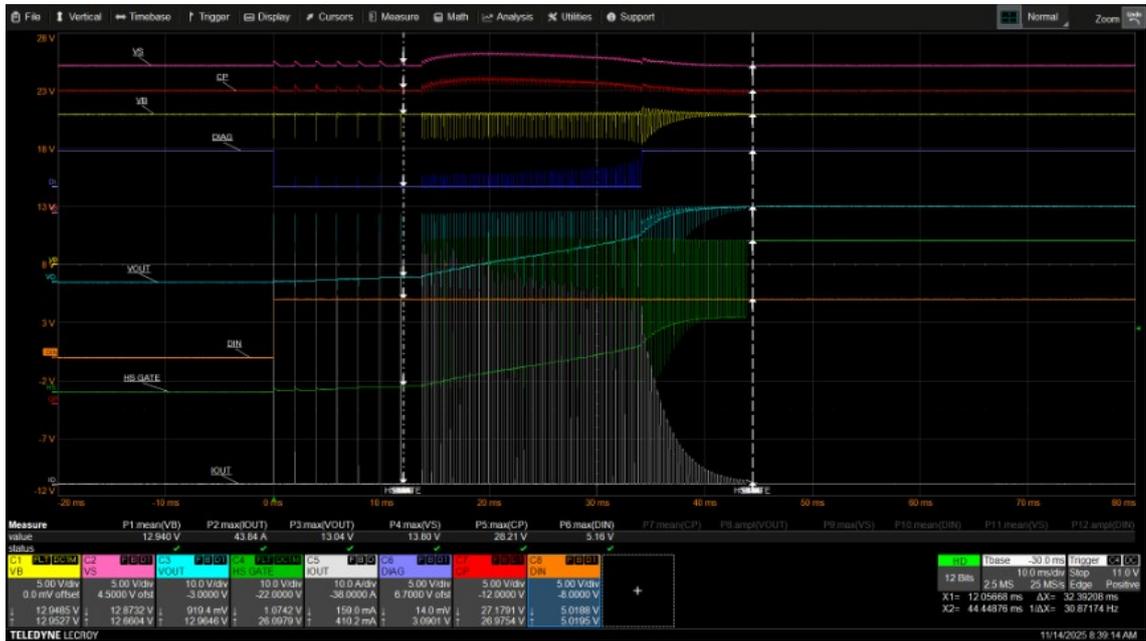


Figure 56. Zoomed waveforms acquired at CCM start with setup E1 with device in Fail-safe mode

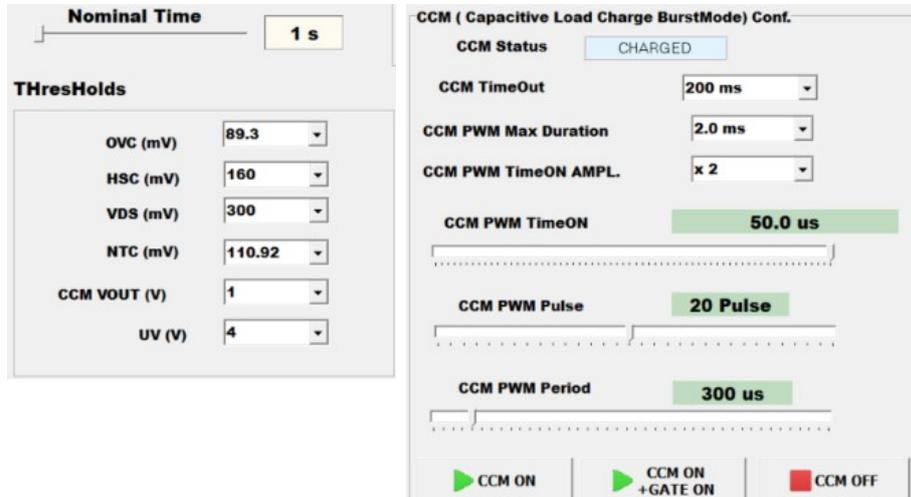

5.2.5 Trial Setup F

It adopts the same setup as trial E1 with VB increased at 24 V vs 13 V.

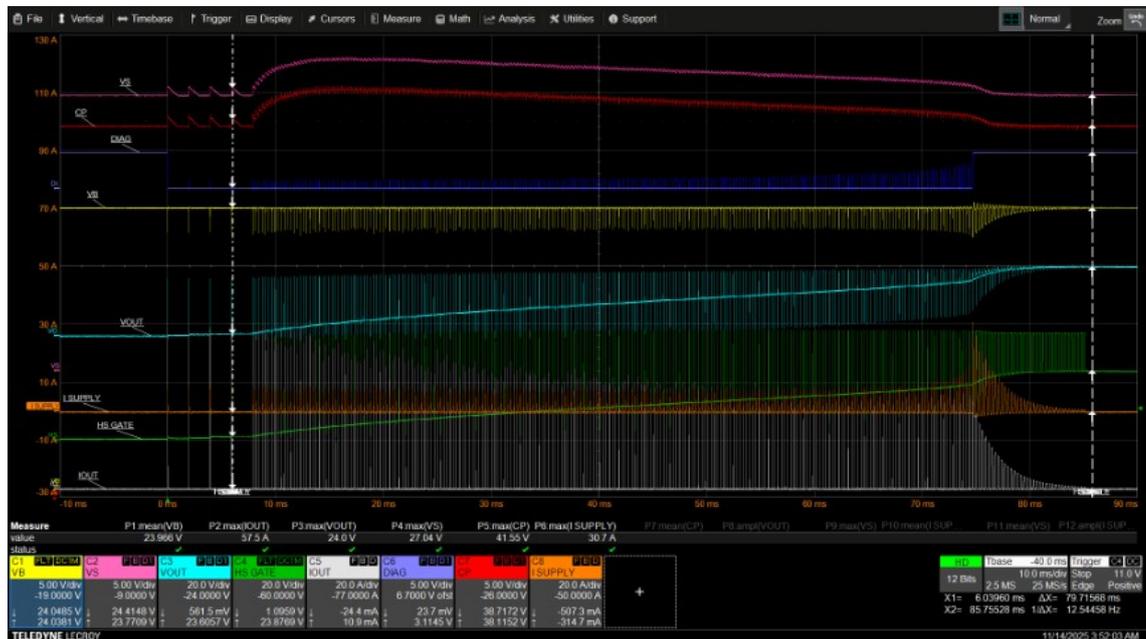
- **VB = 24 V**
- $R_{SHUNT} = 5 \text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- **$C_{LOAD} = 4.7 \text{ mF}$ (measured 4.52 mF)**
- $C_{IN} = 314 \text{ }\mu\text{F}$ and $C_S = 20 \text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

- $CCM_VOUT_THR = 1 \text{ V}$
- $OVC_THR = VOC_THRS_31 \rightarrow 89.3 \text{ mV}$
- $HSC_THR = VHSC_THRS_15 \rightarrow 160 \text{ mV}$
- $T_NOM = T_NOM_{MIN} \rightarrow 1 \text{ s}$
- $CCM_PWM_TON = 50 \text{ }\mu\text{s}$
- $CCM_PWM_TON_MF = 2 \times$
- $CCM_PWM_SC_T_NB = 20 \text{ pulses}$
- $CCM_PWM_T = 300 \text{ }\mu\text{s}$
- $CCM_TIMEOUT = 200 \text{ ms}$
- $CCM_PWM_SC_T = 2 \text{ ms}$
- GUI settings at the end of CCM operations as shown in Figure 57

Figure 57. CCM configuration and result from GUI for test setup F

Result F:

With the mentioned setup F, the C_{LOAD} is charged in 8 ms (start phase) + 77.7 ms (standard phase). Working with 4.7 mF as C_{LOAD} and VB at 24 V, the maximum value achieved by VS was 27 V.

Figure 58. Waveforms acquired during CCM with setup F

5.2.6
Trial Setup G

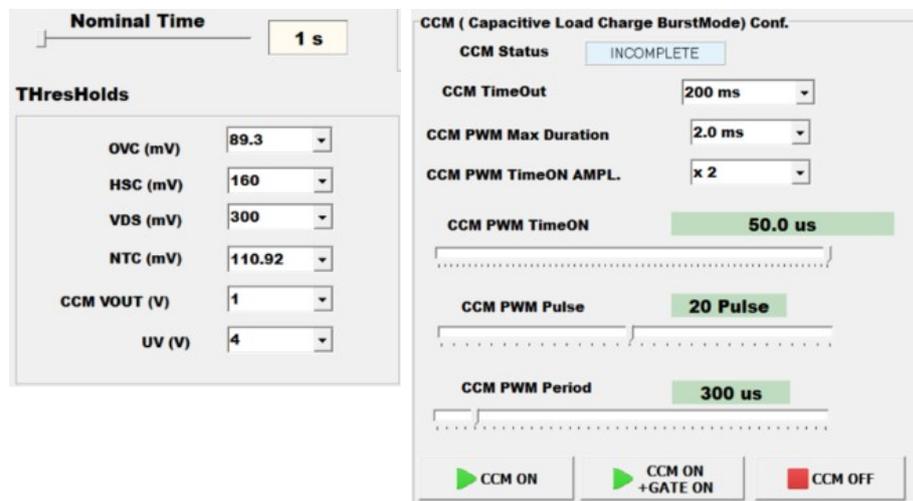
It adopts the same setup as trial E1 with VB increased at 48 V vs 13 V.

- **VB = 48 V**
- $R_{SHUNT} = 5 \text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7 \text{ mF}$ (measured **4.52 mF**)
- $C_{IN} = 314 \text{ }\mu\text{F}$ and $C_S = 20 \text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

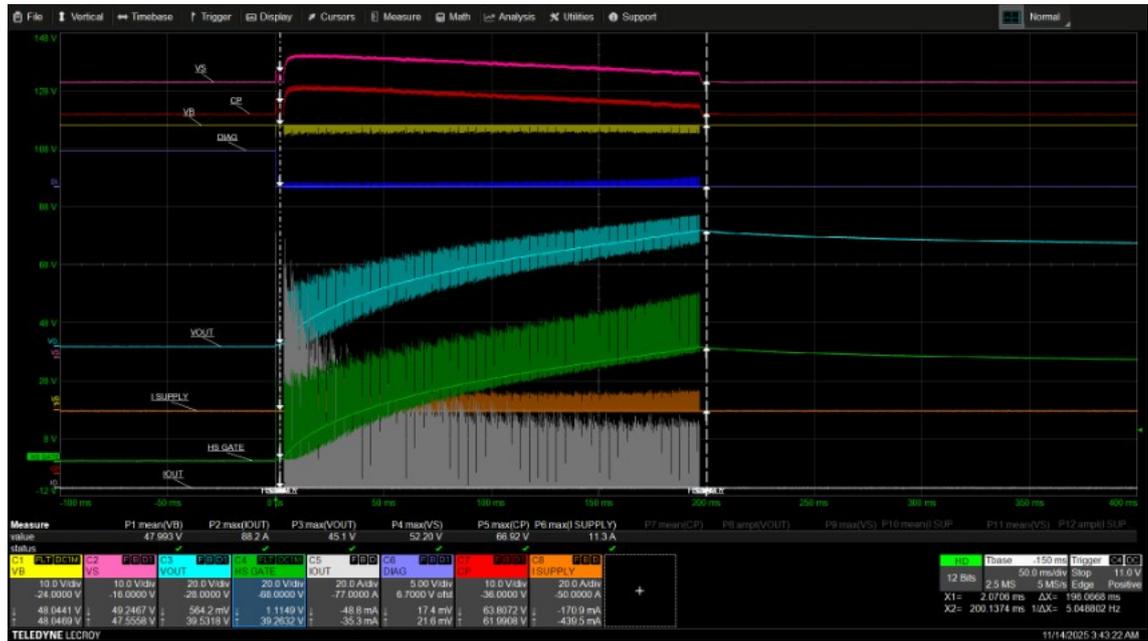
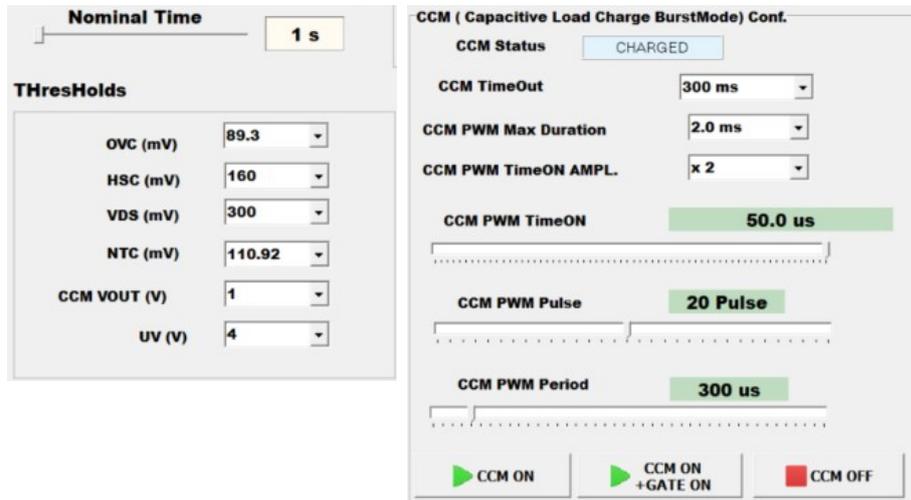
- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_31 → 89.3 mV
- HSC_THR = VHSC_THRS_15 → 160 mV
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 2 x
- CCM_PWM_SC_T_NB = 20 pulses
- CCM_PWM_T = 300 μs
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in [Figure 59](#)

Figure 59. CCM configuration and result from GUI for test setup G



Result G:

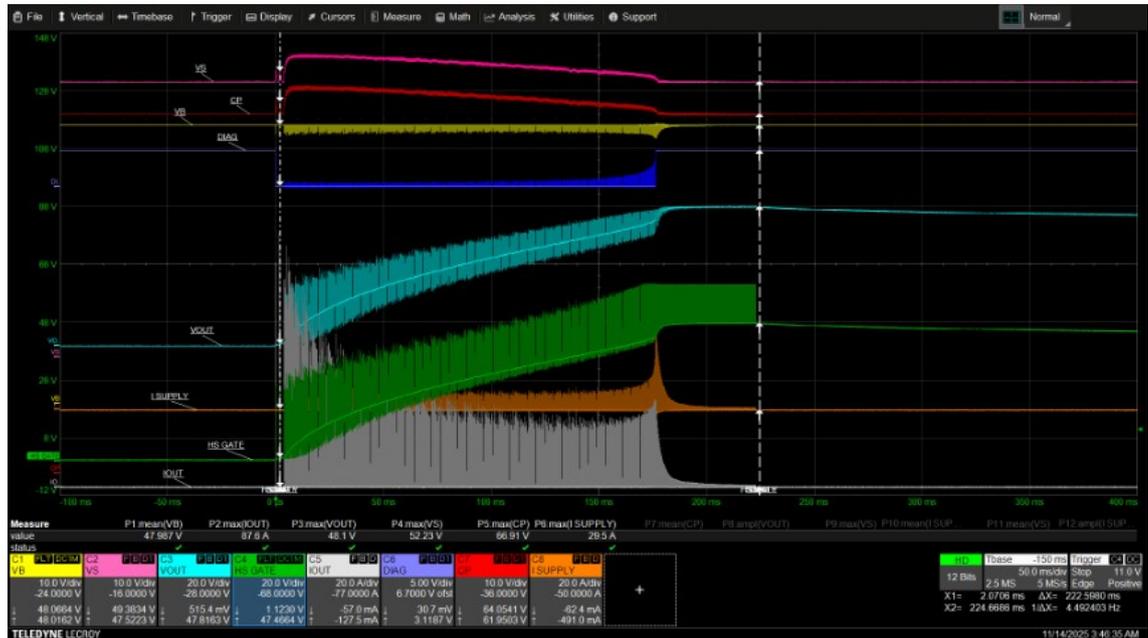
With the mentioned setup G, the 4.7 mF C_{LOAD} charge results incomplete in 2 ms (start phase) + 198 ms (standard phase) as shown in [Figure 60](#) so that the trial was repeated increasing CCM timeout from 200 ms to 300 ms.

Figure 60. Waveforms acquired during CCM with setup G

Figure 61. CCM configuration and result from GUI for test setup G-bis with CCM timeout at 300 ms

Result G-bis:

With the mentioned setup G-bis, the 4.7 mF C_{LOAD} charge is completed in 2 ms (start phase) + 222.6 ms (standard phase).

An impact of VB at 48 V vs 13 V is visible on IOUT max and VS max:

- IOUT max reached 87.6 A on trial G-bis vs 42.6 A on trial E1
- VS max reached 52.2 V on trial G-bis vs 13.8 V on trial E1

Figure 62. Waveforms acquired during CCM with setup G-bis


5.3 Effect of CCM_VOUT_THR

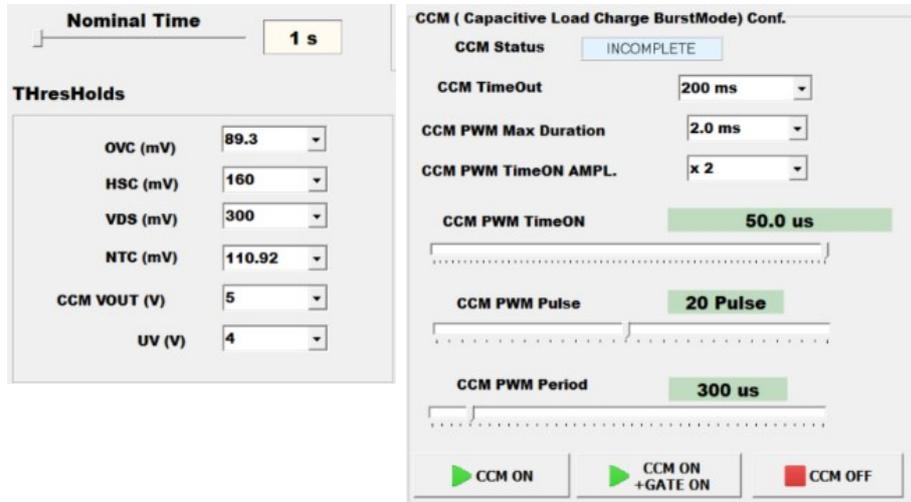
5.3.1 Trial Setup H

It adopts the same setup as trial E1 with the CCM_VOUT_THR increased at 5 V (max) vs 1 V (min).

- VB = 13 V
- RSHUNT = 5 mΩ
- Ambient temperature = room temperature ~25°C generating TJ ~35°C
- C_{LOAD} = 4.7 mF (measured 4.52 mF)
- C_{IN} = 314 μF and C_S = 20 μF

Device in Unlocked state with the following settings:

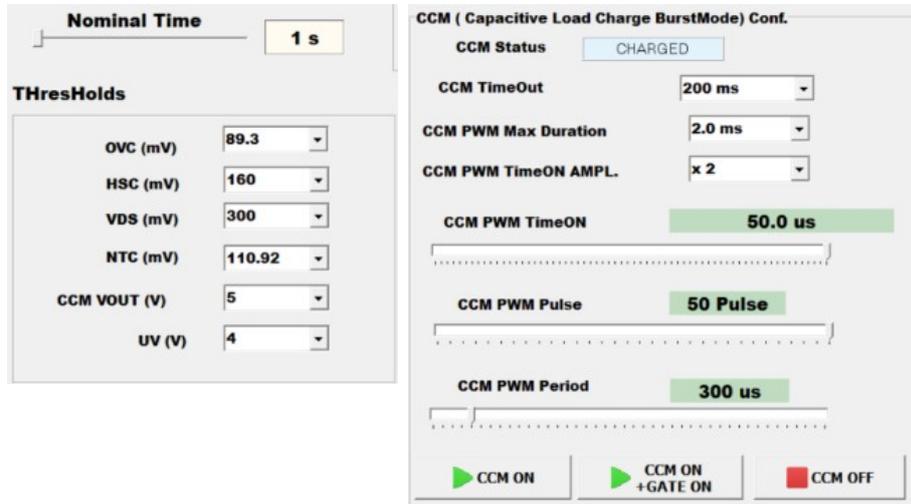
- **CCM_VOUT_THR = 5 V**
- OVC_THR = VOC_THRS_31 → 89.3 mV
- HSC_THR = VHSC_THRS_15 → 160 mV
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 2 x
- CCM_PWM_SC_T_NB = 20 pulses
- CCM_PWM_T = 300 μs
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in [Figure 63](#)

Figure 63. CCM configuration and result from GUI for test setup H

Result H:

With the mentioned setup G, the 4.7 mF C_{LOAD} charge results incomplete in 40 ms - 20 pulses (start phase) with VOUT reaching 2.5 V because the number of pulses is not enough to successfully complete the start phase as shown in Figure 64.

The trial was repeated by increasing the CCM PWM pulses from 20 to 50.

Figure 64. Waveforms acquired during CCM with setup H


Figure 65. CCM configuration and result from GUI for test setup H-bis with CCM PWM pulses set at 50

Result H-bis:

With the mentioned setup H-bis, the 4.7 mF C_{LOAD} charge results incomplete in 94.6 ms (start phase) + 20.4 ms (standard phase).

The CCM_VOUT_THR set at maximum value involves a longer charging time, strongly affecting the duration of the start phase.

Figure 66. Waveforms acquired during CCM with setup H-bis


5.4 Effect of CCM_PWM_SC_T

5.4.1 Trial Setup I

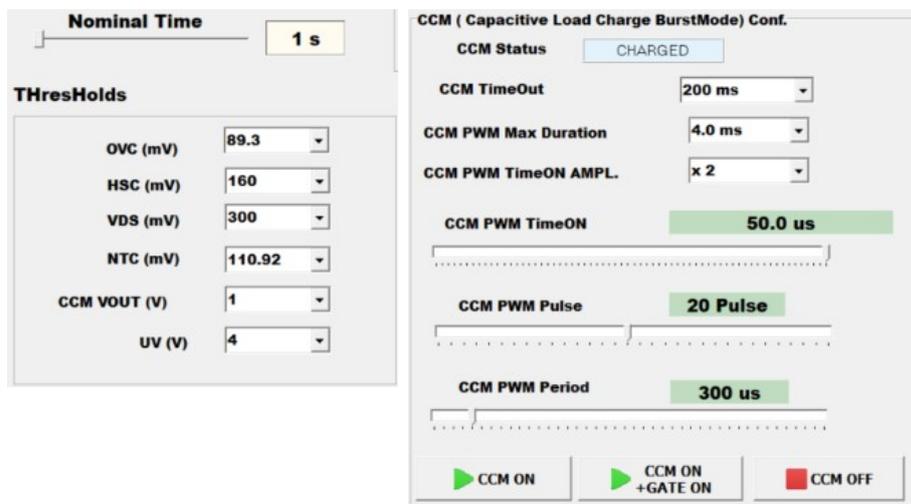
It adopts the same setup as trial E1 with the CCM_PWM_SC_T increased at 4 ms vs 2 ms.

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

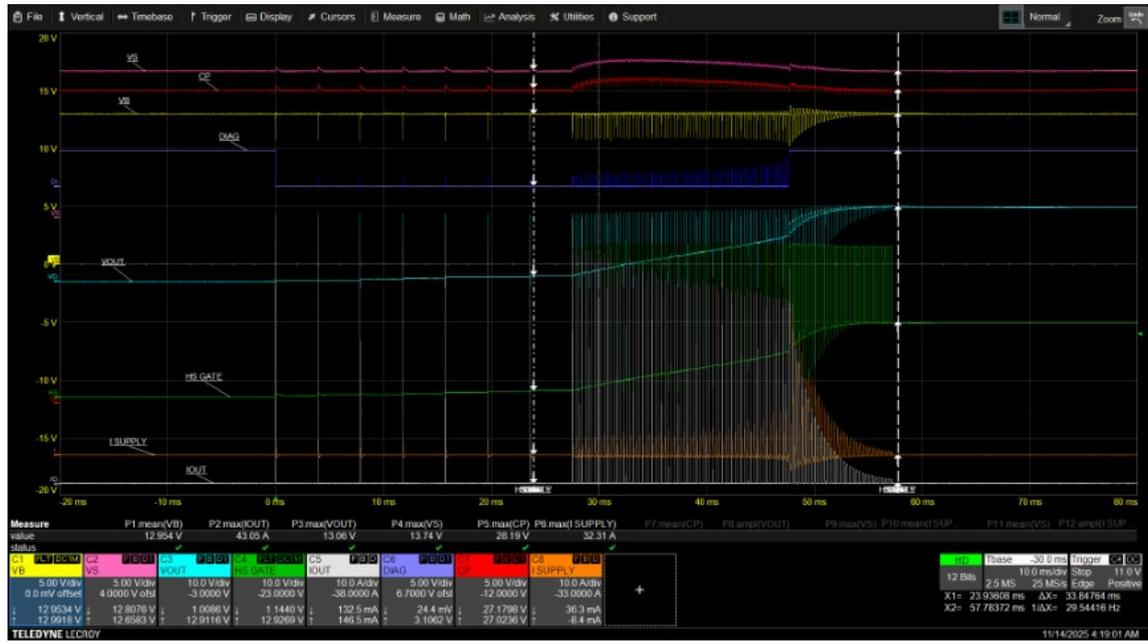
- $CCM_VOUT_THR = 1\text{ V}$
- $OVC_THR = VOC_THRS_31 \rightarrow 89.3\text{ mV}$
- $HSC_THR = VHSC_THRS_15 \rightarrow 160\text{ mV}$
- $T_NOM = T_NOM_{MIN} \rightarrow 1\text{ s}$
- $CCM_PWM_TON = 50\text{ }\mu\text{s}$
- $CCM_PWM_TON_MF = 2\text{ x}$
- $CCM_PWM_SC_T_NB = 20\text{ pulses}$
- $CCM_PWM_T = 300\text{ }\mu\text{s}$
- $CCM_TIMEOUT = 200\text{ ms}$
- **$CCM_PWM_SC_T = 4\text{ ms}$**
- GUI settings at the end of CCM operations as shown in [Figure 67](#)

Figure 67. CCM configuration and result from GUI for test setup I



Result I:

With the mentioned setup I, the C_{LOAD} is charged in 26 ms (start phase) + 31.8 ms (standard phase). A longer $CCM_PWM_SC_T$ leads to a longer charging time, affecting the duration of the start phase.

Figure 68. Waveforms acquired during CCM with setup I


5.5 Effect of CCM_PWM_T

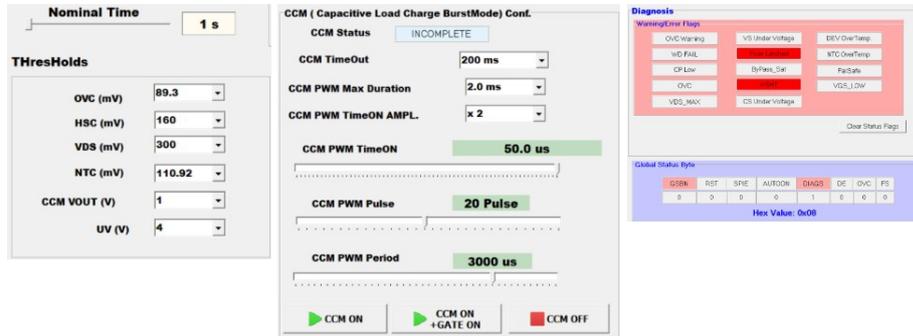
5.5.1 Trial Setup J

It adopts the same setup as trial E1 with the CCM_PWM_T increased at 3000 μ s vs 300 μ s.

- VB = 13 V
- RSHUNT = 5 m Ω
- Ambient temperature = room temperature \sim 25°C generating TJ \sim 35°C
- C_{LOAD} = 4.7 mF (measured 4.52 mF)
- C_{IN} = 314 μ F and C_S = 20 μ F

Device in Unlocked state with the following settings:

- CCM_VOUT_THR = 5 V
- OVC_THR = VOC_THRS_31 \rightarrow 89.3 mV
- HSC_THR = VHSC_THRS_15 \rightarrow 160 mV
- T_NOM = T_NOM_{MIN} \rightarrow 1 s
- CCM_PWM_TON = 50 μ s
- CCM_PWM_TON_MF = 2 x
- **CCM_PWM_SC_T_NB = 20 pulses**
- **CCM_PWM_T = 3000 μ s**
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in [Figure 69](#)

Figure 69. CCM configuration and result from GUI for test setup J

Result J:

With the mentioned setup J, the 4.7 mF C_{LOAD} charge results incomplete in 14 ms (start phase) + 186 ms (standard phase) with VOUT reaching 6.6 V because a longer PWM period with a very small duty cycle are not enough to successfully complete the start phase as shown in Figure 70. The diagnosis reported DIAGS flag due to eFuse + hard short protections being triggered.

The trial was repeated by increasing the CCM timeout from 200 ms to 400 ms.

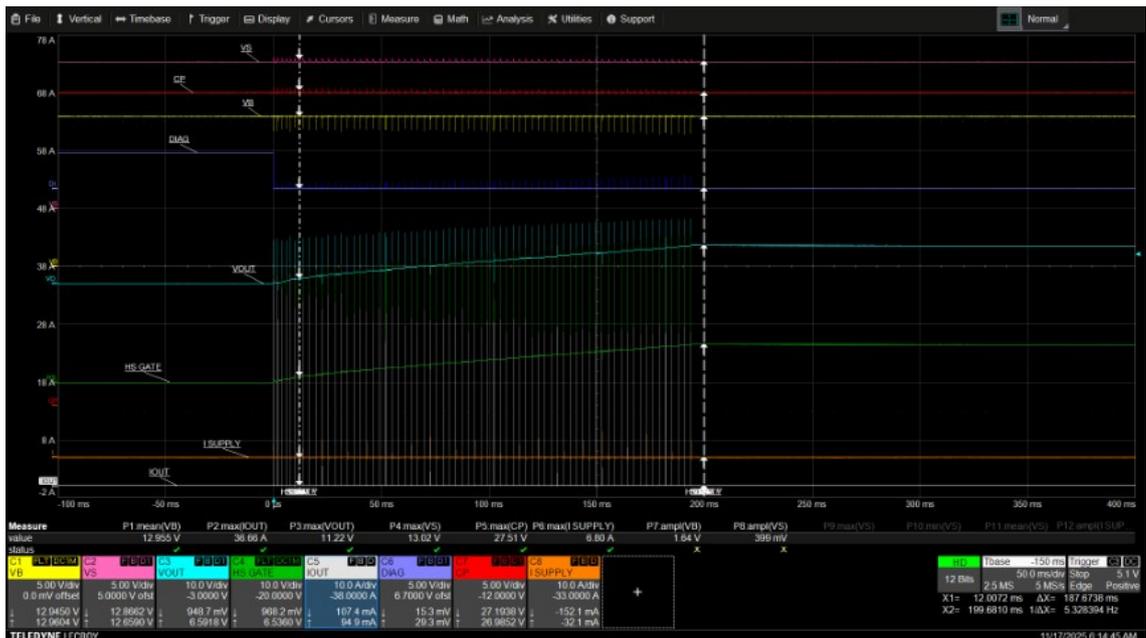
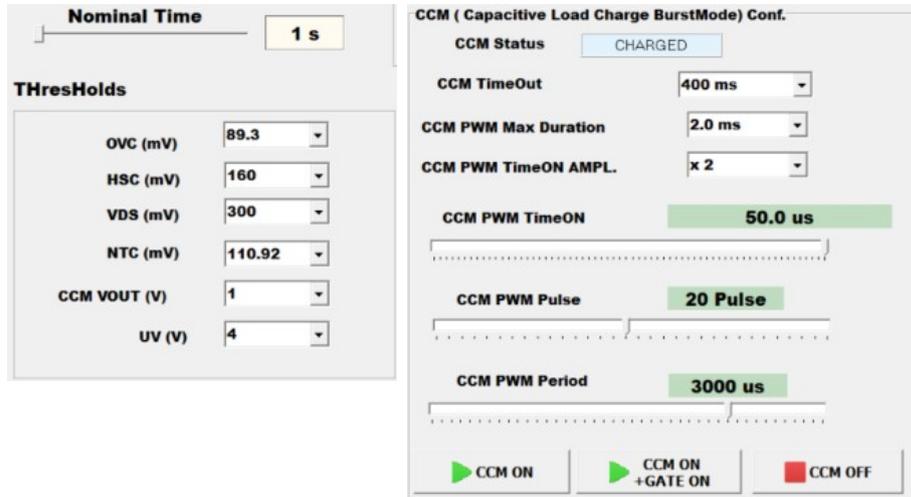
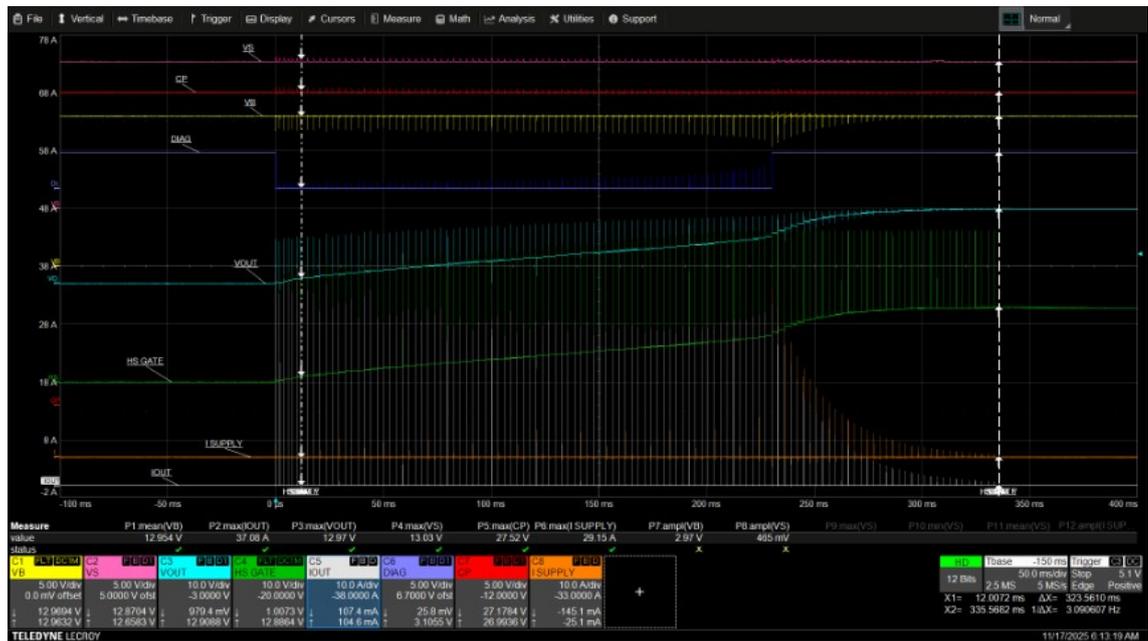
Figure 70. Waveforms acquired during CCM with setup J


Figure 71. CCM configuration and result from GUI for test setup J-bis with CCM timeout set at 400 ms

Result J-bis:

With the mentioned setup J-bis, the 4.7 mF C_{LOAD} charge results incomplete in 14 ms (start phase) + 321.6 ms (standard phase).

Figure 72. Waveforms acquired during CCM with setup J-bis


5.6 Effect of CCM_PWM_TON

5.6.1 Trial Setup K

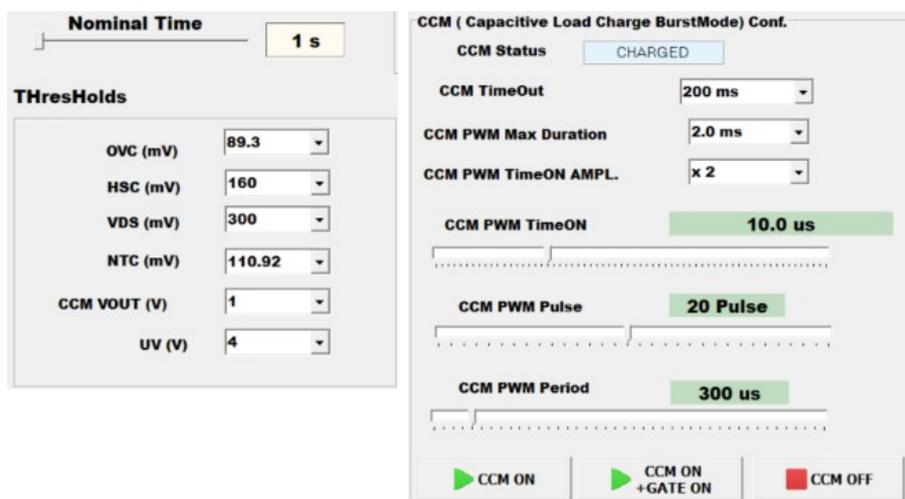
It adopts the same setup as trial E1 with the CCM_PWM_TON decreased at 10 μ s vs 50 μ s.

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

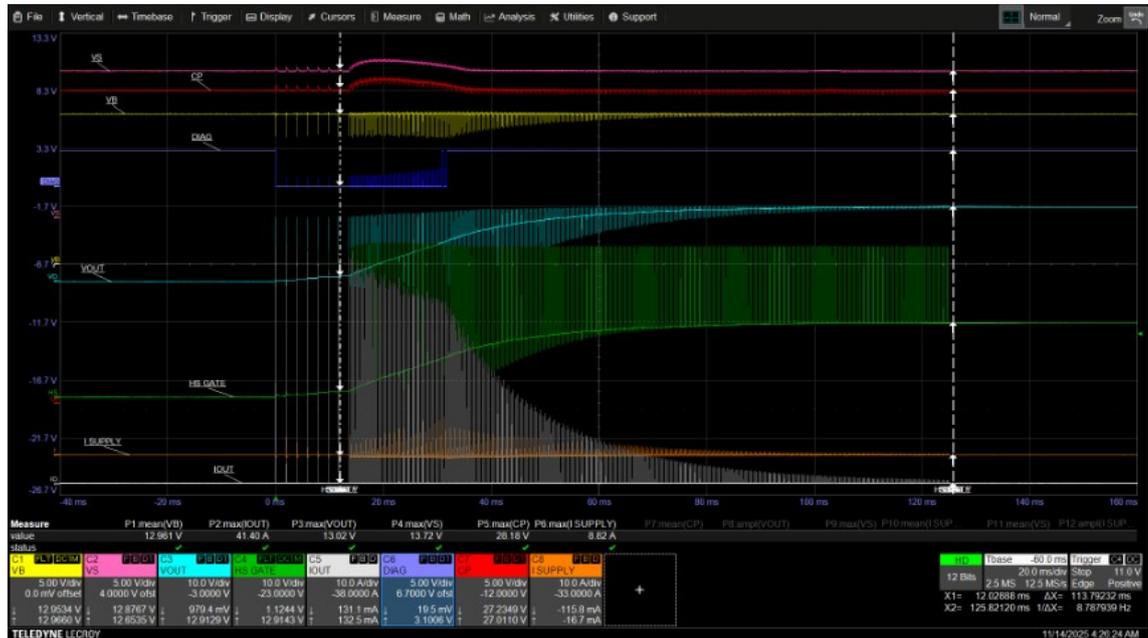
- $CCM_VOUT_THR = 1\text{ V}$
- $OVC_THR = VOC_THRS_31 \rightarrow 89.3\text{ mV}$
- $HSC_THR = VHSC_THRS_15 \rightarrow 160\text{ mV}$
- $T_NOM = T_NOM_{MIN} \rightarrow 1\text{ s}$
- **$CCM_PWM_TON = 10\text{ }\mu\text{s}$**
- $CCM_PWM_TON_MF = 2\text{ x}$
- $CCM_PWM_SC_T_NB = 20\text{ pulses}$
- $CCM_PWM_T = 300\text{ }\mu\text{s}$
- $CCM_TIMEOUT = 200\text{ ms}$
- $CCM_PWM_SC_T = 2\text{ ms}$
- GUI settings at the end of CCM operations as shown in [Figure 73](#)

Figure 73. CCM configuration and result from GUI for test setup K



Result K:

With the mentioned setup K, the C_{LOAD} is charged in 14 ms (start phase) + 111.8 ms (standard phase).

Figure 74. Waveforms acquired during CCM with setup K


5.7 Effect of PWM Ton Multiplying Factor

5.7.1 Trial Setup L

It adopts the same setup as trial E1 with the CCM_PWM_TON at 30 μ s vs 50 μ s and CCM_PWM_TON_MF multiplying factor at 8 x vs 2 x (duty cycle moved from 33.3% to 80%).

- VB = 13 V
- R_{SHUNT} = 5 m Ω
- Ambient temperature = room temperature ~25°C generating T_J ~35°C
- C_{LOAD} = 4.7 mF (measured 4.52 mF)
- C_{IN} = 314 μ F and C_S = 20 μ F

Device in Unlocked state with the following settings:

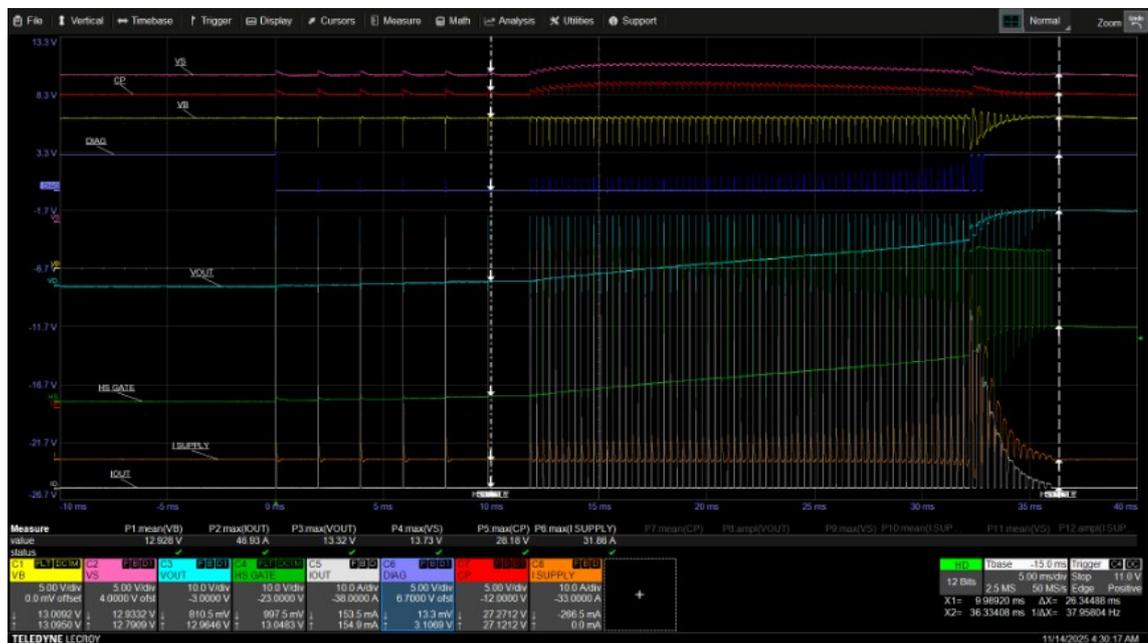
- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_31 \rightarrow 89.3 mV
- HSC_THR = VHSC_THRS_15 \rightarrow 160 mV
- T_{NOM} = T_{NOM}_{MIN} \rightarrow 1 s
- **CCM_PWM_TON = 30 μ s**
- **CCM_PWM_TON_MF = 8 x**
- CCM_PWM_SC_T_NB = 20 pulses
- CCM_PWM_T = 300 μ s
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in Figure 75

Figure 75. CCM configuration and result from GUI for test setup L

Result L:

With the mentioned setup L, the C_{LOAD} is charged in 12 ms (start phase) + 24.3 ms (standard phase).

An increase of CCM PWM Time ON decreases the duration of the CCM standard phase due to a greater PWM duty cycle at 80% (TON = 240 μ s and TOFF = 300 μ s)

Figure 76. Waveforms acquired during CCM with setup L


5.8 Effect of TON protection mode

5.8.1 Trial Setup M

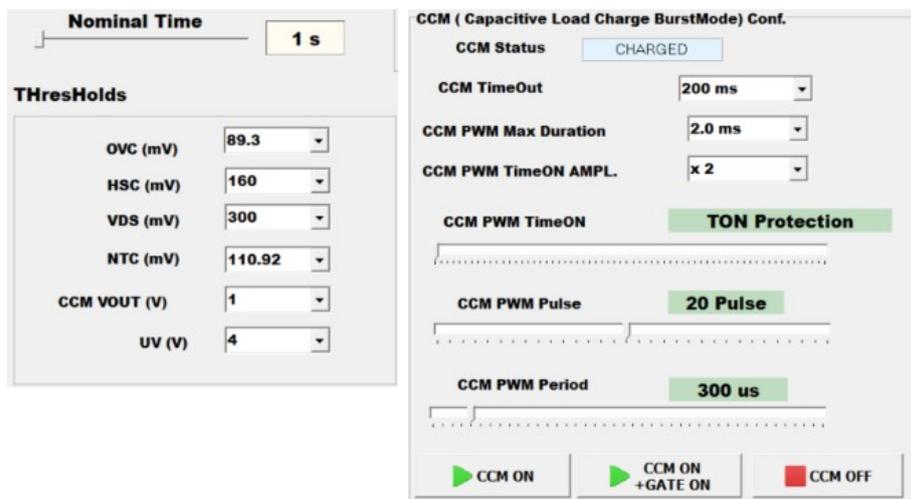
It adopts the same setup as trial E with the CCM_PWM_TON set in TON protection vs 50 us.

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

- $CCM_VOUT_THR = 1\text{ V}$
- $OVC_THR = VOC_THRS_31 \rightarrow 89.3\text{ mV}$
- $HSC_THR = VHSC_THRS_15 \rightarrow 160\text{ mV}$
- $T_NOM = T_NOM_{MIN} \rightarrow 1\text{ s}$
- **CCM_PWM_TON = TON protection**
- $CCM_PWM_TON_MF = 2\text{ x}$
- $CCM_PWM_SC_T_NB = 20\text{ pulses}$
- $CCM_PWM_T = 300\text{ }\mu\text{s}$
- $CCM_TIMEOUT = 200\text{ ms}$
- $CCM_PWM_SC_T = 2\text{ ms}$
- GUI settings at the end of CCM operations as shown in [Figure 77](#)

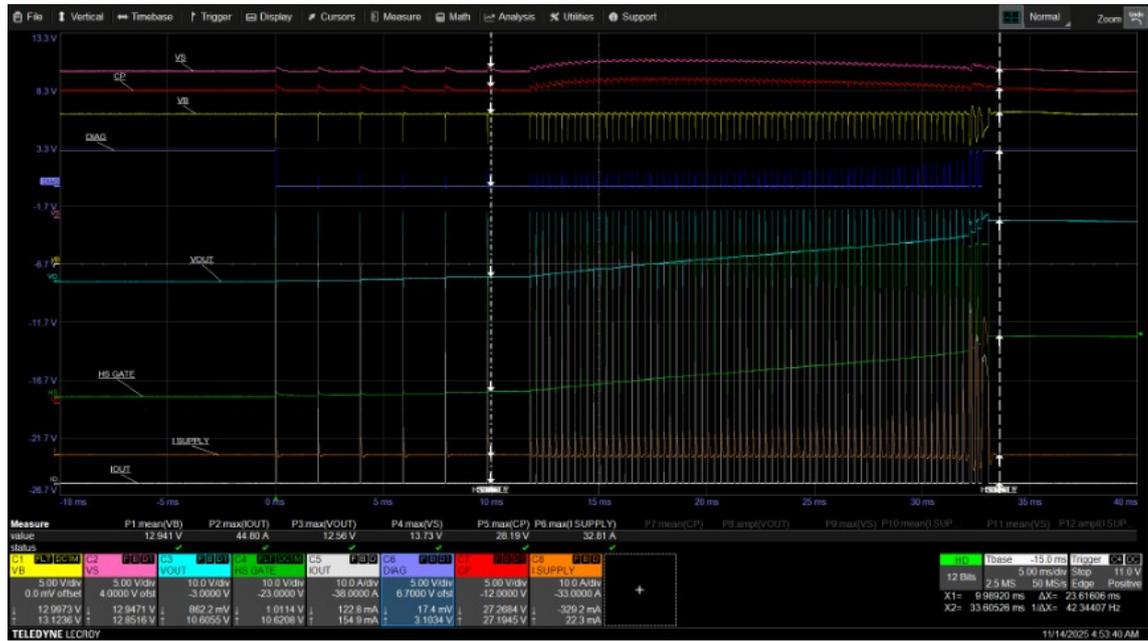
Figure 77. CCM configuration and result from GUI for test setup M



Result M:

With the mentioned setup M, the C_{LOAD} is charged in 12 ms (start phase) + 21.6 ms (standard phase).

The selection of TON protection as CCM PWM Time ON brings the duration of the CCM standard phase to the minimum value because the HS_GATE stays ON until I^2t protection is triggered within the selected CCM PWM period.

Figure 78. Waveforms acquired during CCM with setup M


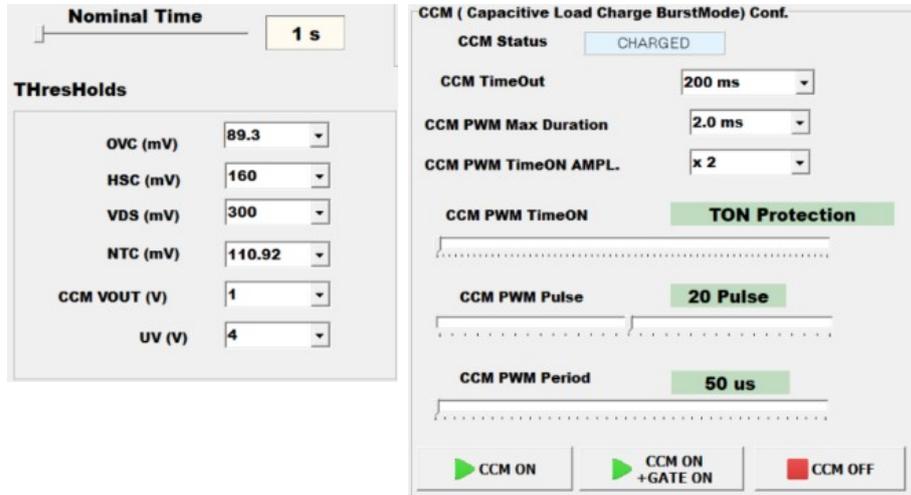
5.8.2 Trial Setup N

It adopts the same setup as trial M with the CCM_PWM_TON in TON protection but CCM_PWM_T (PWM Period) set at 50 μ s vs 300 μ s.

- VB = 13 V
- RSHUNT = 5 m Ω
- Ambient temperature = room temperature \sim 25 $^{\circ}$ C generating TJ \sim 35 $^{\circ}$ C
- CLOAD = 4.7 mF (measured 4.52 mF)
- CIN = 314 μ F and CS = 20 μ F

Device in Unlocked state with the following settings:

- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_31 \rightarrow 89.3 mV
- HSC_THR = VHSC_THRS_15 \rightarrow 160 mV
- T_NOM = T_NOM_MIN \rightarrow 1 s
- **CCM_PWM_TON = TON protection**
- CCM_PWM_TON_MF = 2 x
- CCM_PWM_SC_T_NB = 20 pulses
- **CCM_PWM_T = 50 μ s**
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in Figure 79

Figure 79. CCM configuration and result from GUI for test setup N

Result N:

With the mentioned setup N, the 4.7 mF C_{LOAD} is charged in 14 ms (start phase) + 3.9 ms (standard phase). This setup allows us to achieve the fastest charge of the selected C_{LOAD} at 13 V.

Figure 80. Waveforms acquired during CCM with setup N


5.9 Effect of OVC_THR and HSC_THR

5.9.1 Trial Setup O

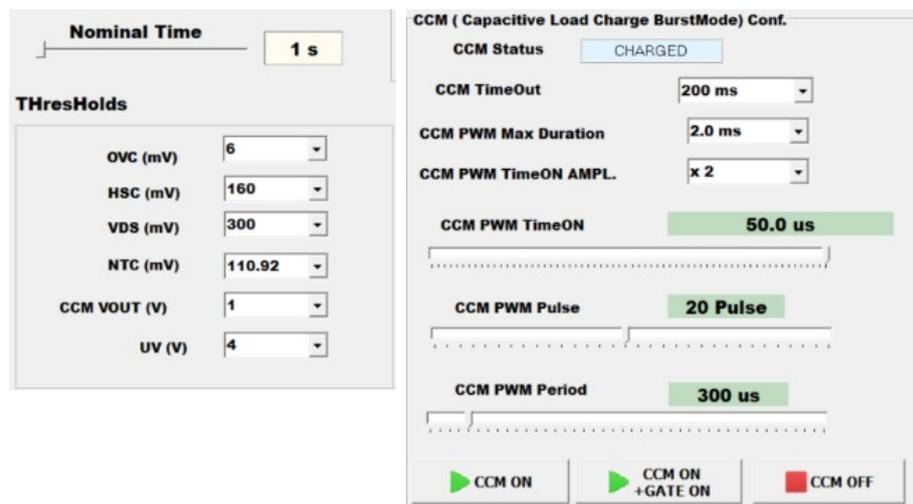
It adopts the same setup as trial E1 with OVC_THR set at 6 mV (min) vs 89.3 mV (max).

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

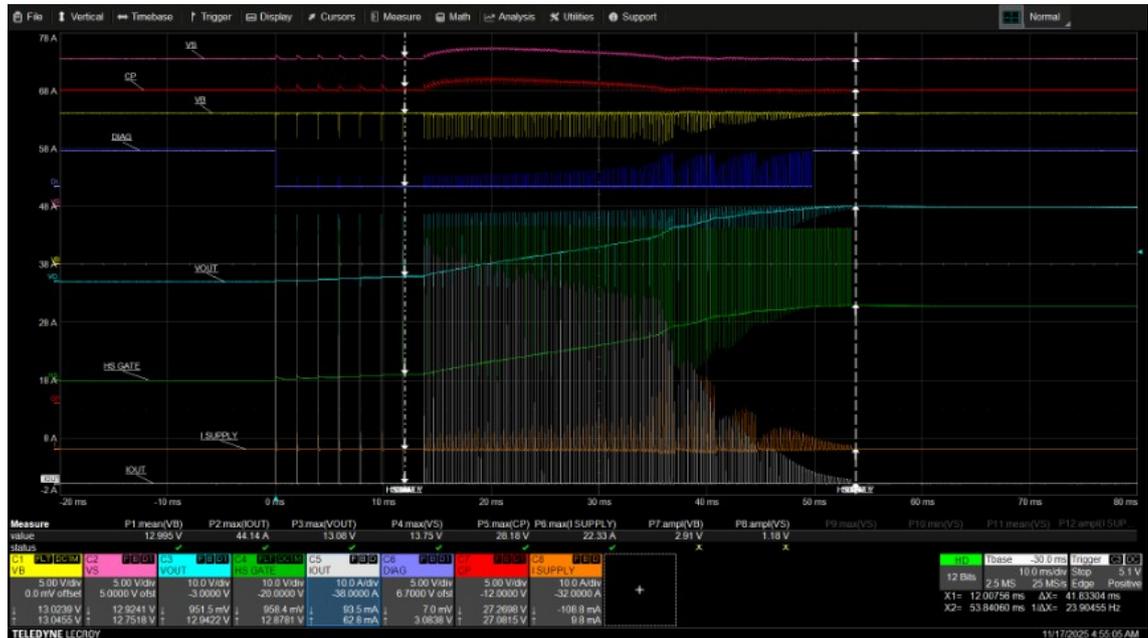
- $CCM_VOUT_THR = 1\text{ V}$
- **$OVC_THR = VOC_THRS_0 \rightarrow 6\text{ mV}$**
- $HSC_THR = VHSC_THRS_15 \rightarrow 160\text{ mV}$
- $T_NOM = T_NOM_{MIN} \rightarrow 1\text{ s}$
- $CCM_PWM_TON = 50\text{ }\mu\text{s}$
- $CCM_PWM_TON_MF = 2\text{ x}$
- $CCM_PWM_SC_T_NB = 20\text{ pulses}$
- $CCM_PWM_T = 300\text{ }\mu\text{s}$
- $CCM_TIMEOUT = 200\text{ ms}$
- $CCM_PWM_SC_T = 2\text{ ms}$
- GUI settings at the end of CCM operations as shown in [Figure 81](#)

Figure 81. CCM configuration and result from GUI for test setup O



Result O:

With the mentioned setup O, the $4.7\text{ mF } C_{LOAD}$ is charged in 14 ms (start phase) + 39.8 ms (standard phase). This setup involves a slower speed in the standard charging phase due to the min OVC threshold strongly affecting the standard phase duration.

Figure 82. Waveforms acquired during CCM with setup O


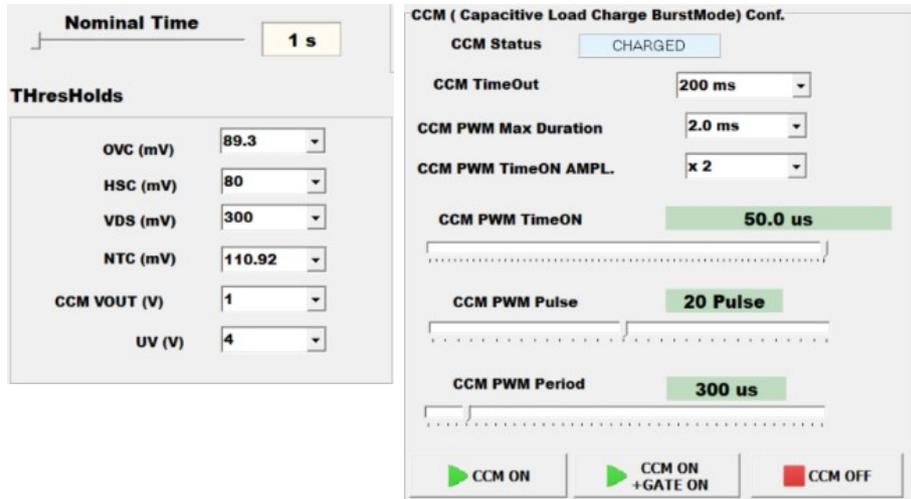
5.9.2 Trial Setup P

It adopts the same setup as trial E1 with HSC_THR set at 80 mV vs 160 mV (max).

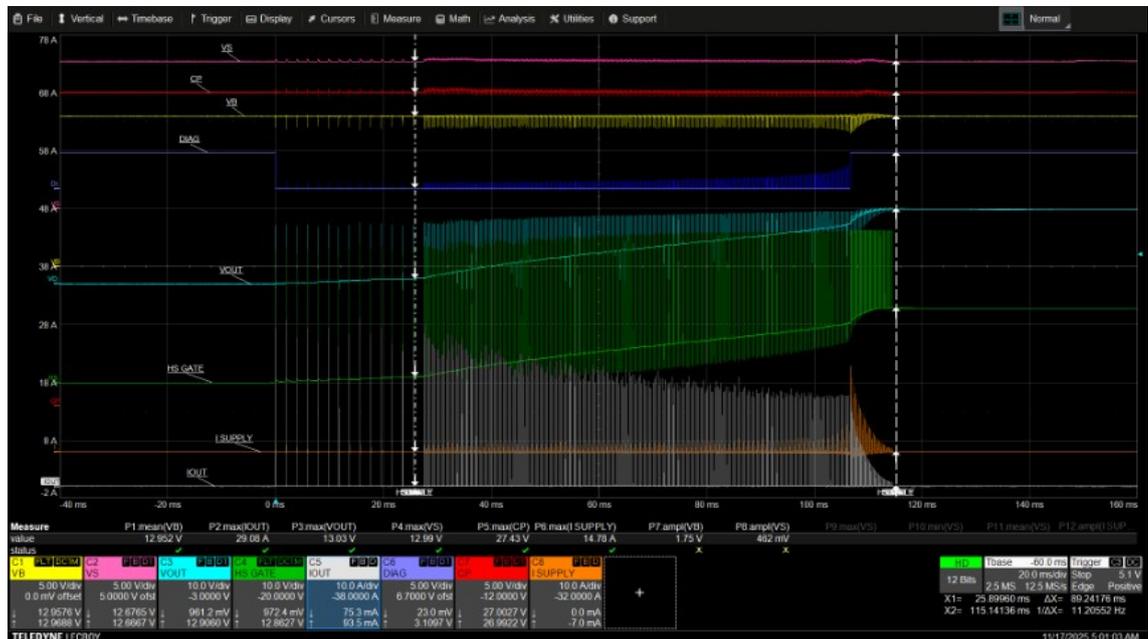
- VB = 13 V
- R_{SHUNT} = 5 mΩ
- Ambient temperature = room temperature ~25°C generating T_J ~35°C
- C_{LOAD} = 4.7 mF (measured 4.52 mF)
- C_{IN} = 314 μF and C_S = 20 μF

Device in Unlocked state with the following settings:

- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_31 → 89.3 mV
- **HSC_THR = VHSC_THRS_10 → 80 mV**
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 2 x
- CCM_PWM_SC_T_NB = 20 pulses
- CCM_PWM_T = 300 μs
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in Figure 83

Figure 83. CCM configuration and result from GUI for test setup P

Result P:

With the mentioned setup P, the 4.7 mF C_{LOAD} is charged in 28 ms (start phase) + 87.1 ms (standard phase). This setup involves a slower speed to charge due to a lower HSC threshold affecting the current peaks of both start and standard charging phases.

Figure 84. Waveforms acquired during CCM with setup P

5.9.3
Trial Setup Q1

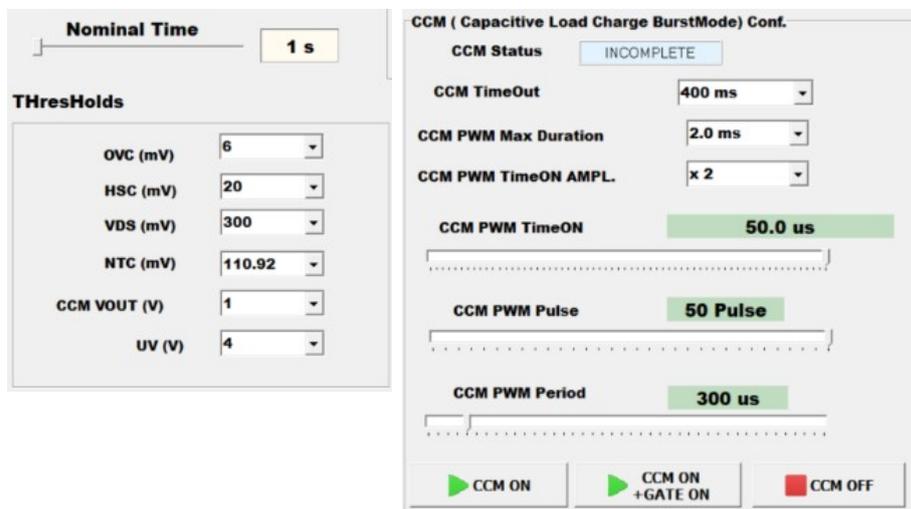
It adopts the same setup as trial E1 with OVC_THR set at 6 mV (min) vs 89.3 mV (max) and HSC_THR set at 20 mV (min) vs 160 mV (max).

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

- CCM_VOUT_THR = 1 V
- **OVC_THR = VOC_THRS_0 → 6 mV**
- **HSC_THR = VHSC_THRS_0 → 20 mV**
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 2 x
- **CCM_PWM_SC_T_NB = 50 pulses**
- CCM_PWM_T = 300 μs
- **CCM_TIMEOUT = 400 ms**
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in [Figure 85](#)

Figure 85. CCM configuration and result from GUI for test setup Q1

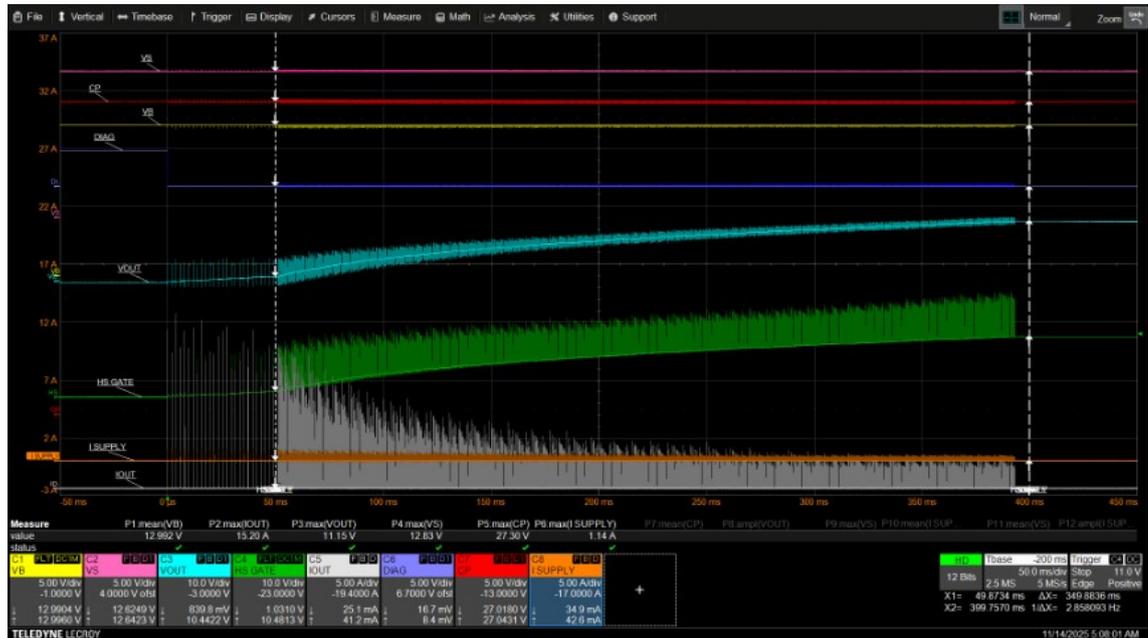


Result Q1:

Even if the CCM pulses are increased to 50 and CCM timeout is set at 400 ms, with the mentioned setup Q1, the 4.7 mF C_{LOAD} is not charged in 50 ms (start phase) + 350 ms (standard phase). VOUT reaches 10.4 V after 400 ms.

This setup cannot charge the C_{LOAD} because the usage of minimum value for OVC and HSC thresholds involves peak with minimum current during both charging phases. IO_{UT} max results only 15.2 A vs 42.6 A of trial E1 in which both OVC and HSC were set at maximum levels.

To successfully complete the charge of the mentioned C_{LOAD}, fixing other parameters, the minimum OVC and HSC levels are the ones used in trial Q2.

Figure 86. Waveforms acquired during CCM with setup Q1


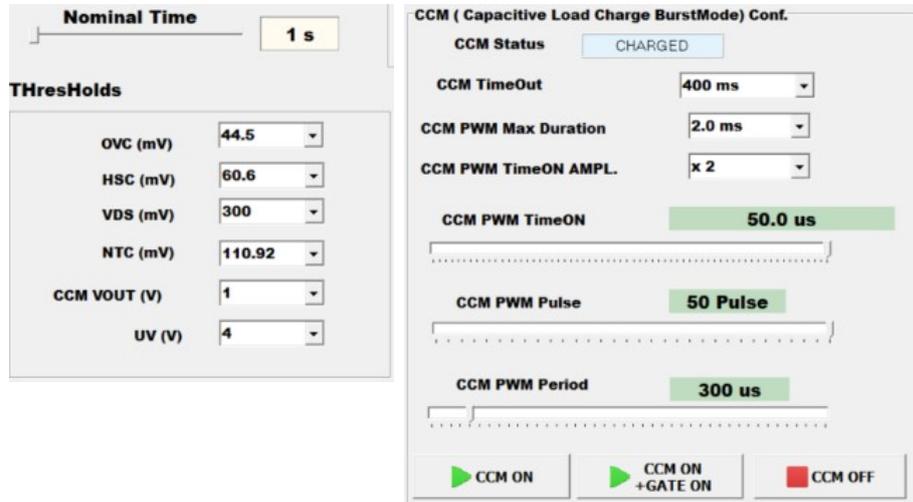
5.9.4 Trial Setup Q2

It adopts the same setup as trial E1 with OVC_THR set at 44.5 mV vs 89.3 mV (max) and HSC_THR set at 60.6 mV vs 160 mV (max).

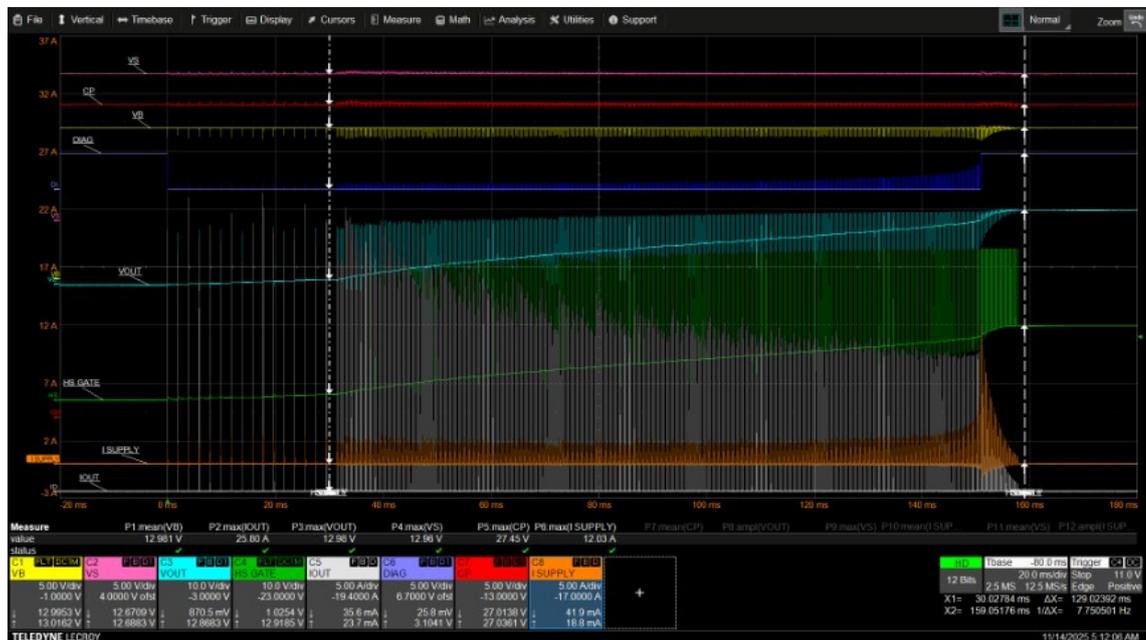
- VB = 13 V
- RSHUNT = 5 mΩ
- Ambient temperature = room temperature ~25°C generating TJ ~35°C
- CLOAD = 4.7 mF (measured 4.52 mF)
- CIN = 314 μF and CS = 20 μF

Device in Unlocked state with the following settings:

- CCM_VOUT_THR = 1 V
- **OVC_THR = VOC_THRS_24 → 44.5 mV**
- **HSC_THR = VHSC_THRS_8 → 60.6 mV**
- T_NOM = T_NOM_MIN → 1 s
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 2 x
- **CCM_PWM_SC_T_NB = 50 pulses**
- CCM_PWM_T = 300 μs
- **CCM_TIMEOUT = 400 ms**
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in Figure 87

Figure 87. CCM configuration and utilities result from GUI for test setup Q2

Result Q2:

With the mentioned setup Q2, the 4.7 mF C_{LOAD} is charged in 32 (start phase) + 127 ms (standard phase). E1 vs Q1 vs Q2 trials show the strong contribution of OVC and HSC setting in t_{CHARGE} .

Figure 88. Waveforms acquired during CCM with setup Q2

5.9.5 Trial Setup R1

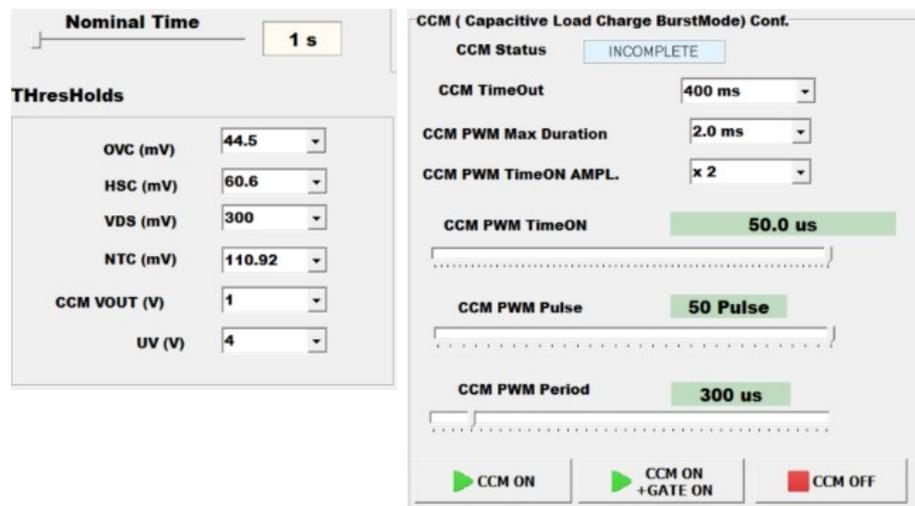
It adopts the same setup as trial Q2 but VB is set at 48 V.

- **VB = 48 V**
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

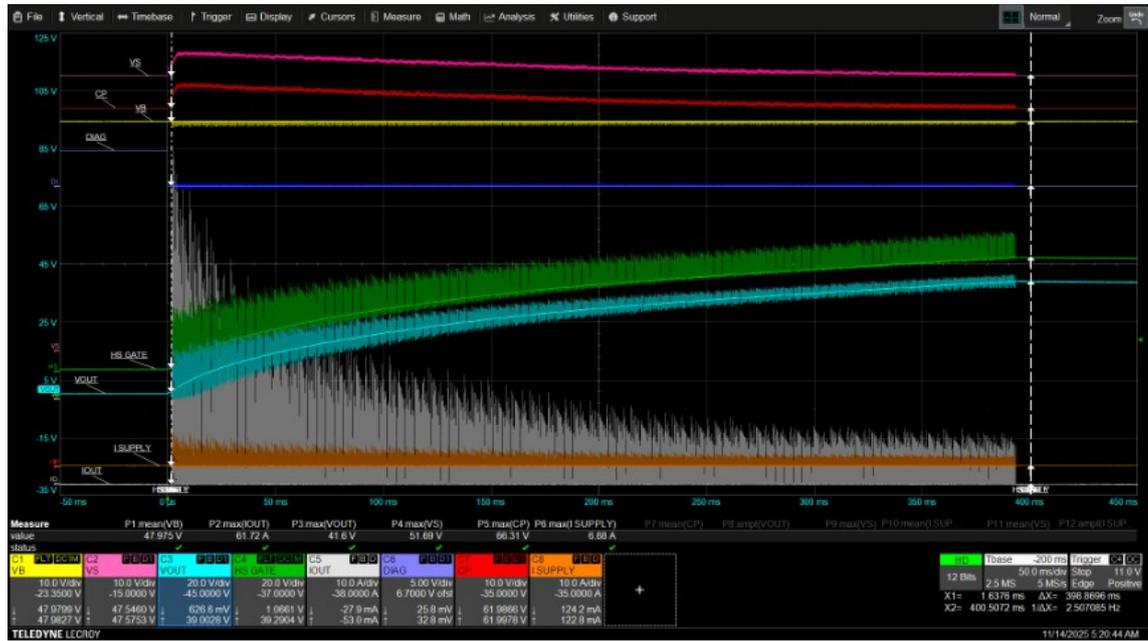
- CCM_VOUT_THR = 1 V
- **OVC_THR = VOC_THRS_24 → 44.5 mV**
- **HSC_THR = VHSC_THRS_8 → 60.6 mV**
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 2 x
- **CCM_PWM_SC_T_NB = 50 pulses**
- CCM_PWM_T = 300 μs
- **CCM_TIMEOUT = 400 ms**
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in [Figure 89](#)

Figure 89. CCM configuration and result from GUI for test setup R1



Result R1:

With the mentioned setup R1, the 4.7 mF C_{LOAD} is not charged in 2 ms (start phase) + 398 ms (standard phase). VOUT reaches only 39 V after 400 ms due to the VB set at 48 V vs the 13 V used in trial Q2. Please note that the usage of VB = 48 V involves IO_{UT} max at 61.7 A and VS max at 51.7 V.

Figure 90. Waveforms acquired during CCM with setup R1


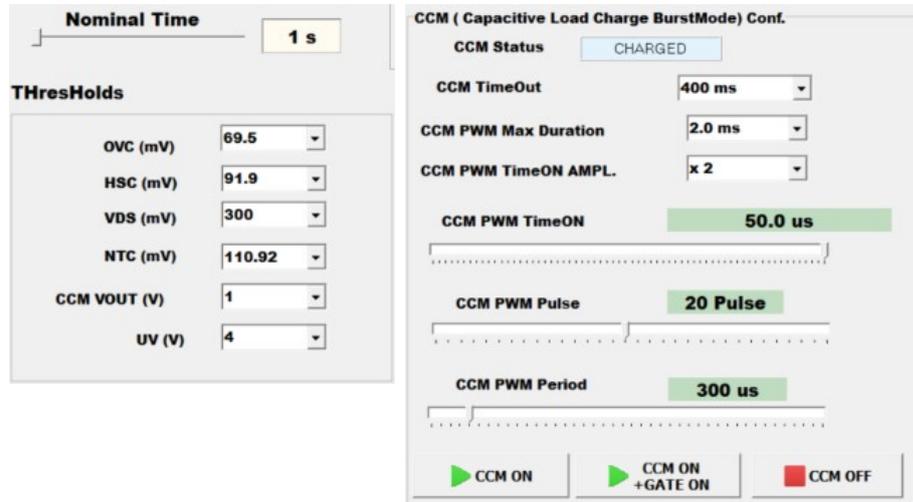
5.9.6 Trial Setup R2

It adopts the same setup as trial R1, but the OVC and HSC thresholds are set at higher levels, allowing the C_{LOAD} charge to be successfully completed.

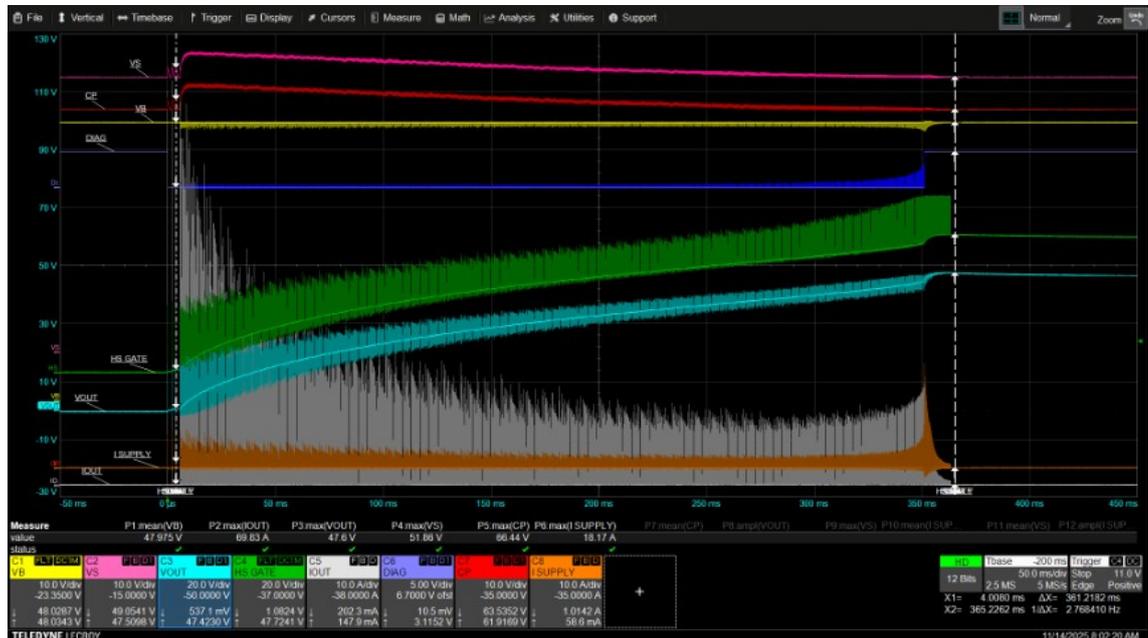
- **VB = 48 V**
- $R_{SHUNT} = 5 \text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7 \text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314 \text{ }\mu\text{F}$ and $C_S = 20 \text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

- $CCM_VOUT_THR = 1 \text{ V}$
- **$OVC_THR = VOC_THRS_29 \rightarrow 69.5 \text{ mV}$**
- **$HSC_THR = VHSC_THRS_11 \rightarrow 91.9 \text{ mV}$**
- $T_NOM = T_NOM_{MIN} \rightarrow 1 \text{ s}$
- $CCM_PWM_TON = 50 \text{ }\mu\text{s}$
- $CCM_PWM_TON_MF = 2 \times$
- **$CCM_PWM_SC_T_NB = 50 \text{ pulses}$**
- $CCM_PWM_T = 300 \text{ }\mu\text{s}$
- **$CCM_TIMEOUT = 400 \text{ ms}$**
- $CCM_PWM_SC_T = 2 \text{ ms}$
- GUI settings at the end of CCM operations as shown in Figure 91

Figure 91. CCM configuration and result from GUI for Test setup R2

Result R2:

With the mentioned setup R2, the 4.7 mF C_{LOAD} is charged in 6 ms (start phase) + 359 ms (standard phase). Please note that this setup involves I_{OUT} max at 69.8 A and V_S max at 51.8 V confirming that selected C_{IN} is also very safe in this heavy setup to limit the boost effect.

Figure 92. Waveforms acquired during CCM with setup R2


5.10 Effect of $C_{LOAD} = 6.9$ mF

5.10.1 Trial Setup S

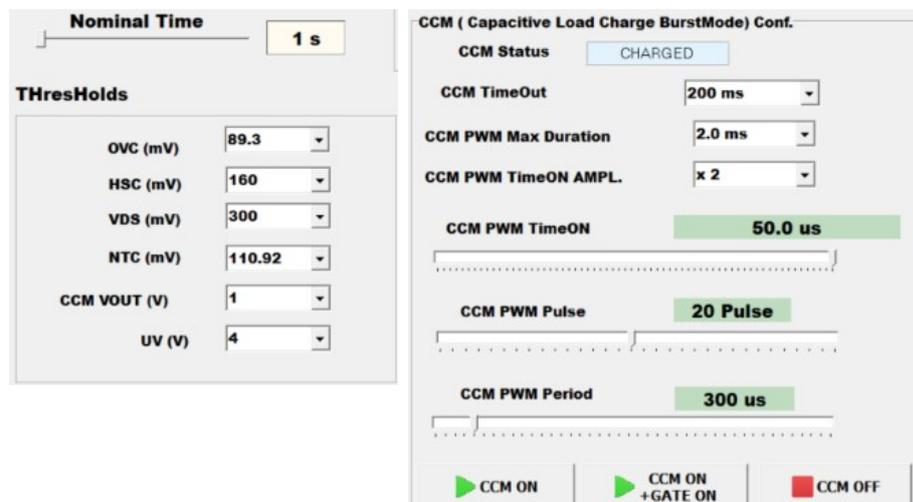
It adopts the same setup as trial E1 with the C_{LOAD} increased at 6.9 mF vs 4.7 mF.

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- **$C_{LOAD} = 6.9\text{ mF}$ (measured **6.69 mF**)**
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

- $CCM_VOUT_THR = 1\text{ V}$
- $OVC_THR = VOC_THRS_31 \rightarrow 89.3\text{ mV}$
- $HSC_THR = VHSC_THRS_15 \rightarrow 160\text{ mV}$
- $T_NOM = T_NOM_{MIN} \rightarrow 1\text{ s}$
- $CCM_PWM_TON = 50\text{ }\mu\text{s}$
- $CCM_PWM_TON_MF = 2\text{ x}$
- $CCM_PWM_SC_T_NB = 20\text{ pulses}$
- $CCM_PWM_T = 300\text{ }\mu\text{s}$
- $CCM_TIMEOUT = 200\text{ ms}$
- $CCM_PWM_SC_T = 2\text{ ms}$
- GUI settings at the end of CCM operations as shown in [Figure 93](#)

Figure 93. CCM configuration and result from GUI for test setup S



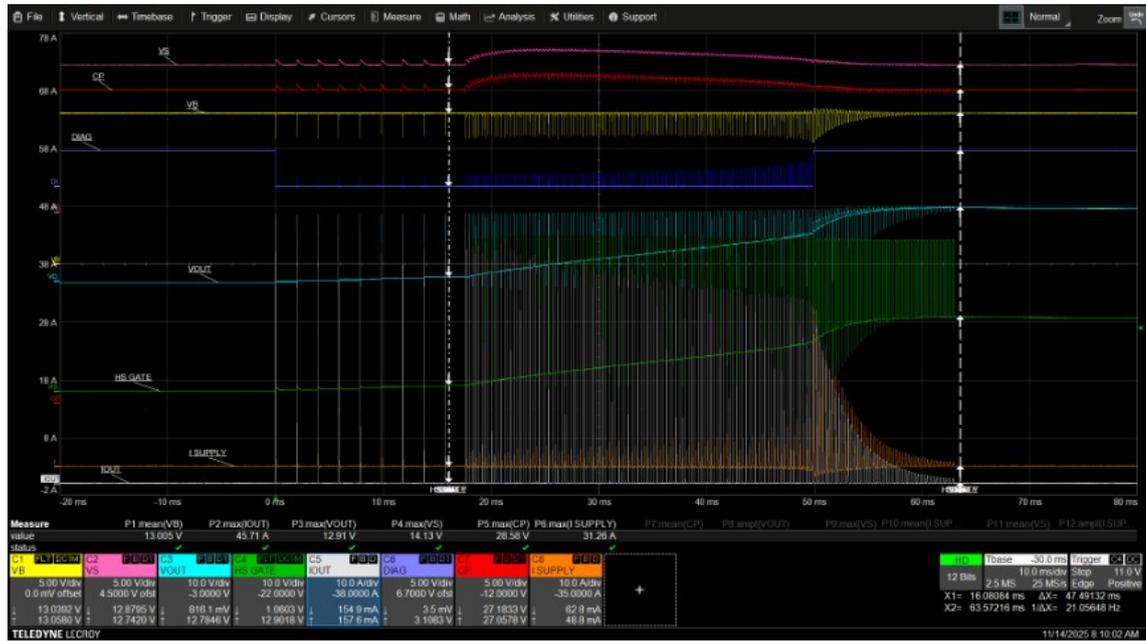
Result S:

With the mentioned setup S, the $6.9\text{ mF } C_{LOAD}$ is charged in 18 ms (start phase) + 48.5 ms (standard phase).

Using the same setup of trial E1, the overall t_{CHARGE} moves from 43.9 ms to 63.5 ms due to the C_{LOAD} that was increased from 4.7 mF to 6.9 mF .

Also, I_{OUT} max and V_S max are impacted:

- I_{OUT} max at 45.7 A (trial S) vs 42.6 A (trial E1)
- V_S max at 14.1 V (trial S) vs 13.8 V (trial E1)

Figure 94. Waveforms acquired during CCM with setup S


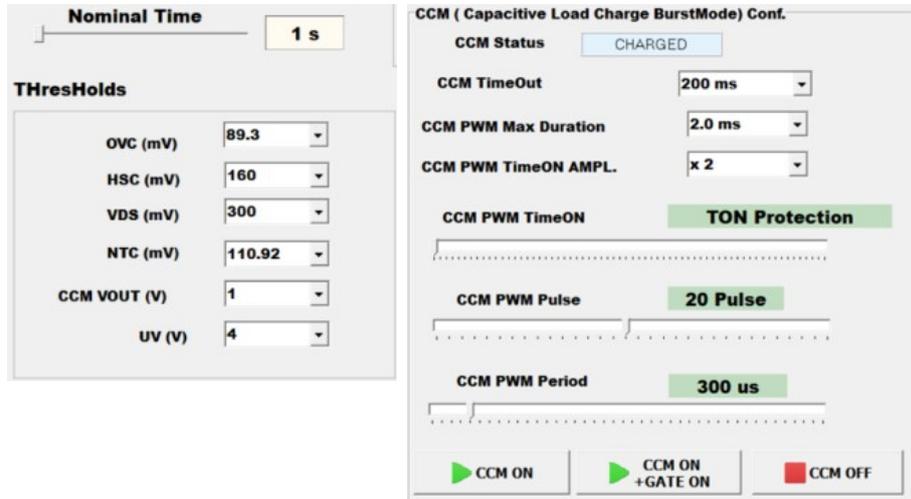
5.10.2 Trial Setup T

It adopts the same setup as trial S with the CCM_PWM_TON set in TON protection to reduce t_{CHARGE} .

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- **$C_{LOAD} = 6.9\text{ mF}$ (measured 6.69 mF)**
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

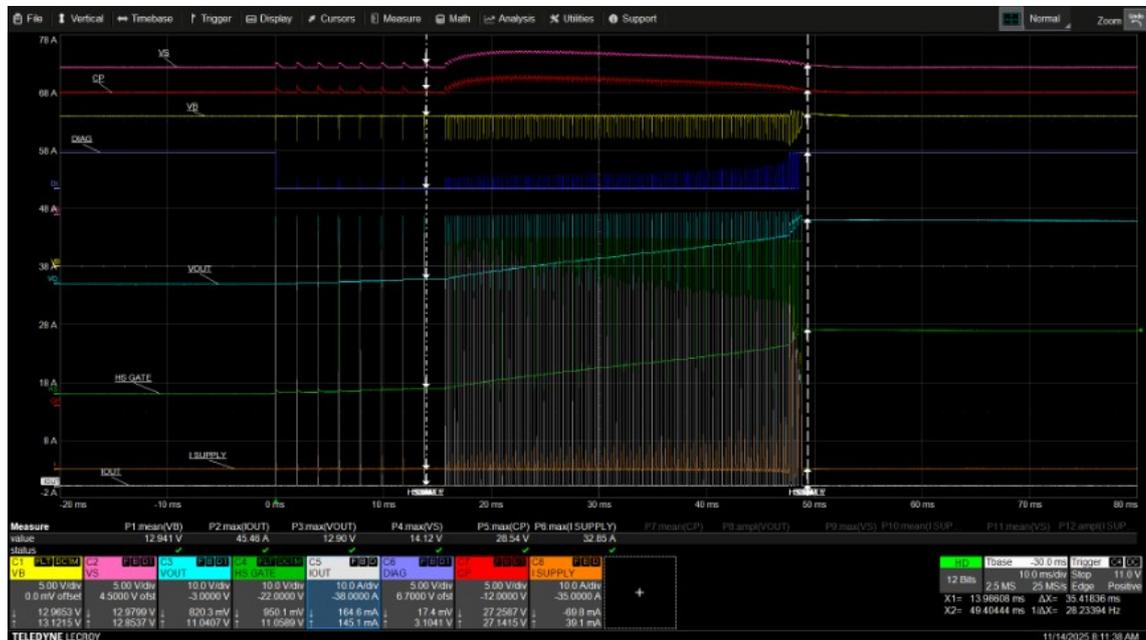
- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_31 $\rightarrow 89.3\text{ mV}$
- HSC_THR = VHSC_THRS_15 $\rightarrow 160\text{ mV}$
- $T_{NOM} = T_{NOM_{MIN}} \rightarrow 1\text{ s}$
- **CCM_PWM_TON = TON protection**
- CCM_PWM_TON_MF = 2 x
- CCM_PWM_SC_T_NB = 20 pulses
- CCM_PWM_T = 300 μs
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in [Figure 95](#)

Figure 95. CCM configuration and result from GUI for test setup T

Result T:

With the mentioned setup T, the 6.9 mF C_{LOAD} is charged in 16 ms (start phase) + 33.4 ms (standard phase).

The setting of TON protection allows the overall t_{CHARGE} from 63.5 ms (trial S) to 49.4 ms (trial T).

Using the same setup of trial M, the overall t_{CHARGE} moves from 33.6 ms to 49.4 ms due to the increase of C_{LOAD} from 4.7 mF (trial M) to 6.9 mF (trial T).

Figure 96. Waveforms acquired during CCM with setup T


5.11 Effect of Junction Temperature on CCM

5.11.1 Trial Setup U

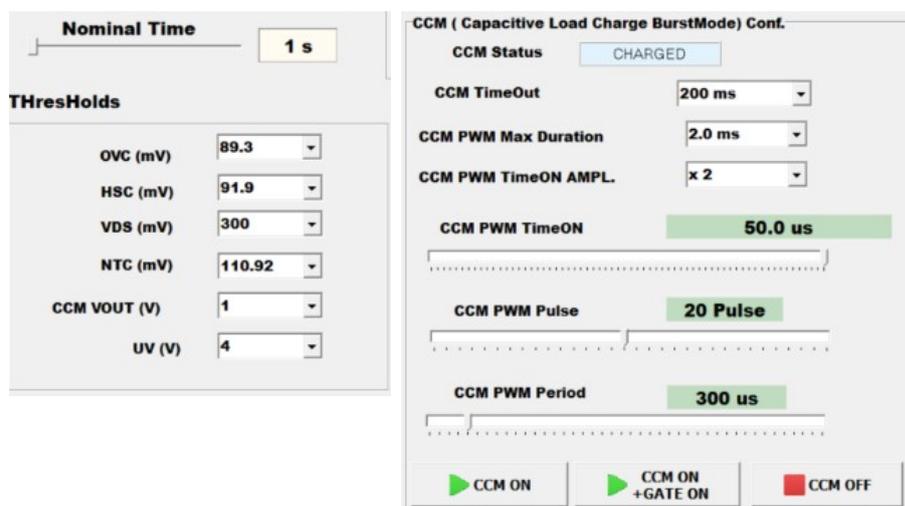
It adopts the same setup as trial E1, with HSC_THR modified from the max level 160 mV to 91.9 mV.

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- **$C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)**
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

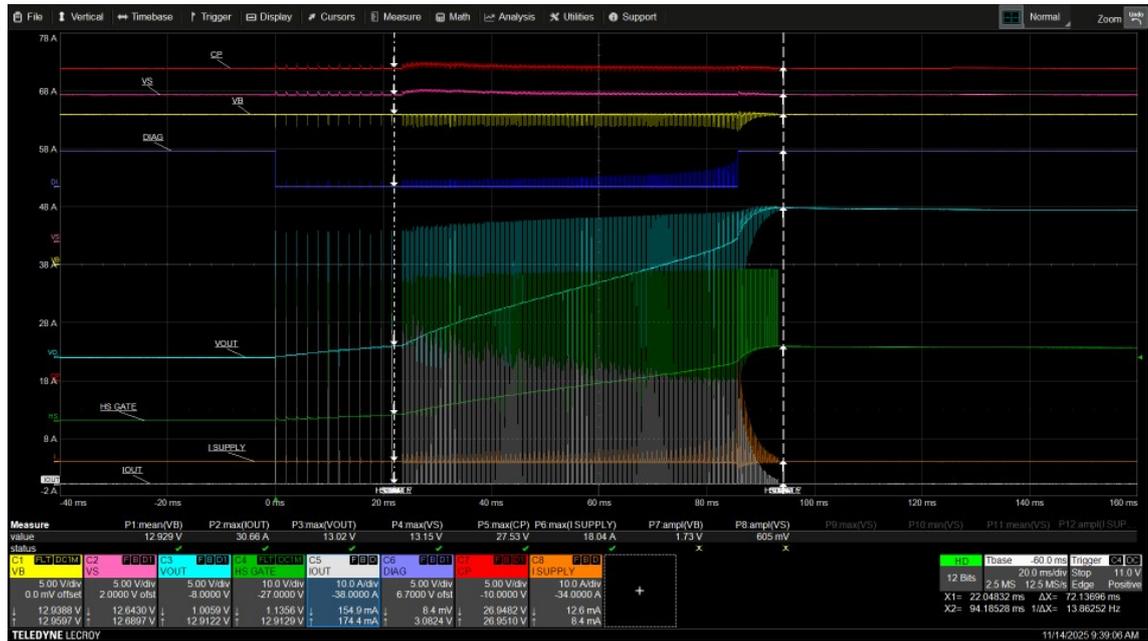
- $CCM_VOUT_THR = 1\text{ V}$
- $OVC_THR = VOC_THRS_31 \rightarrow 89.3\text{ mV}$
- **$HSC_THR = VHSC_THRS_11 \rightarrow 91.9\text{ mV}$**
- $T_NOM = T_NOM_{MIN} \rightarrow 1\text{ s}$
- $CCM_PWM_TON = 50\text{ }\mu\text{s}$
- $CCM_PWM_TON_MF = 2\text{ x}$
- $CCM_PWM_SC_T_NB = 20\text{ pulses}$
- $CCM_PWM_T = 300\text{ }\mu\text{s}$
- $CCM_TIMEOUT = 200\text{ ms}$
- $CCM_PWM_SC_T = 2\text{ ms}$
- GUI settings at the end of CCM operations as shown in [Figure 97](#)

Figure 97. CCM configuration and result from GUI for test setup U



Result U:

With the mentioned setup U, the $4.7\text{ mF } C_{LOAD}$ is charged in 24 ms (start phase) + 70.1 ms (standard phase).

Figure 98. Waveforms acquired during CCM with setup U


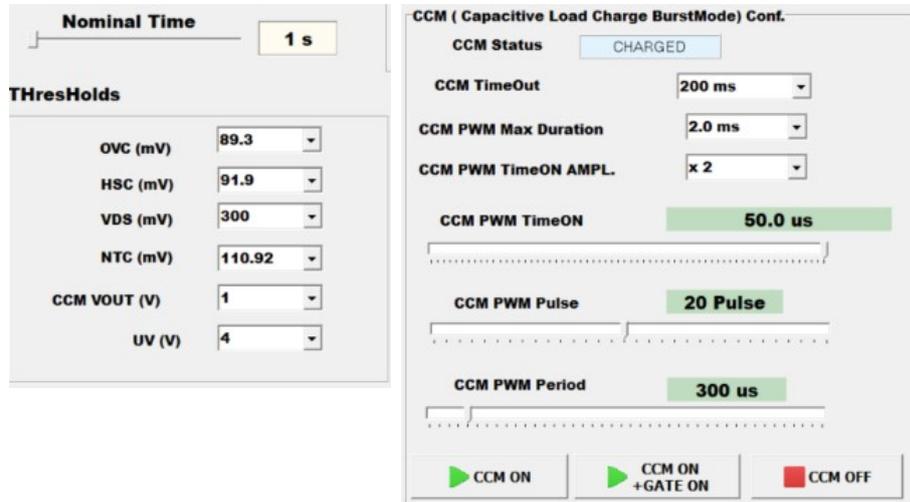
5.11.2 Trial Setup V

It adopts the same setup as trial U, with the ambient temperature modified to hot.

- VB = 13 V
- R_{SHUNT} = 5 mΩ
- Ambient temperature = room temperature ~90°C generating T_J ~100°C
- C_{LOAD} = 4.7 mF (measured 4.52 mF)
- C_{IN} = 314 μF and C_S = 20 μF

Device in Unlocked state with the following settings:

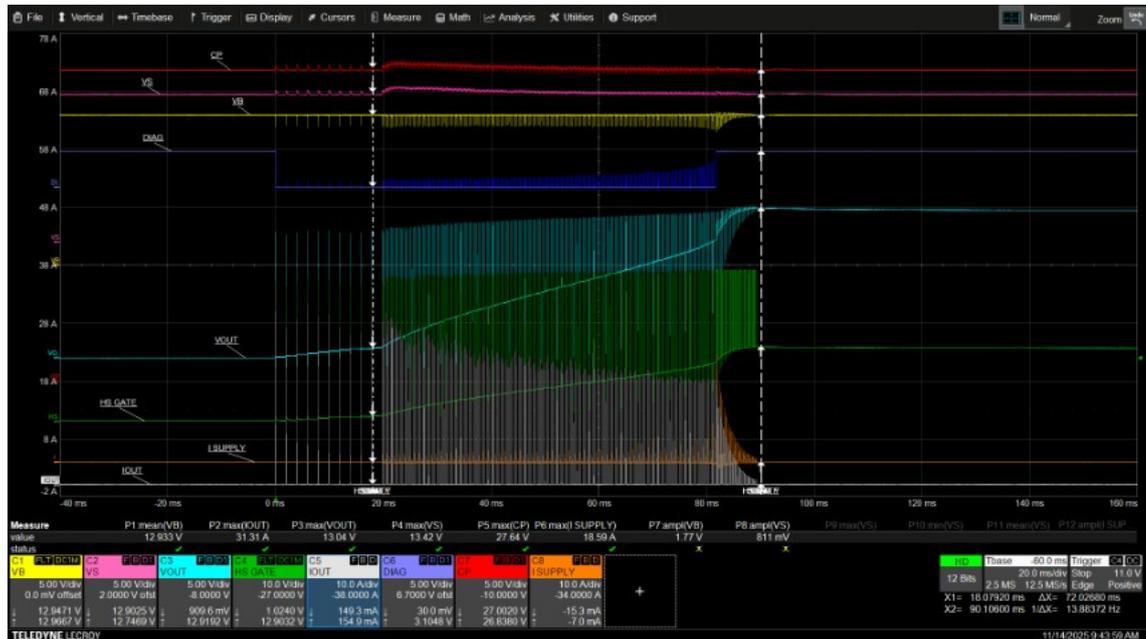
- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_31 → 89.3 mV
- HSC_THR = VHSC_THRS_11 → 91.9 mV
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 2 x
- CCM_PWM_SC_T_NB = 20 pulses
- CCM_PWM_T = 300 μs
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in Figure 99

Figure 99. CCM configuration and result from GUI for test setup V

Result V:

With the mentioned setup V, the 4.7 mF C_{LOAD} is charged in 20 ms (start phase) + 70 ms (standard phase).

The temperature of gate controller device has a negligible effect on t_{CHARGE} that can be affected by the temperature of the C_{LOAD} and the temperature of the external MOSFET.

In the reported examples U vs V, the VNF1248F device was heated by the hot air flow over the device that is very close to the MOSFET while the C_{LOAD} is far from the used circuit. In this specific example, the trial V involves a slightly faster t_{CHARGE} vs trial U because the impact of a higher current peak in the start phase; in fact, we observed ten pulses with max $I_{OUT} = 31.3$ A in trial V vs 12 pulses with max $I_{OUT} = 30.6$ A in trial U.

Figure 100. Waveforms acquired during CCM with setup V


5.12 Effect of R_{SHUNT} on CCM

5.12.1 Trial Setup W

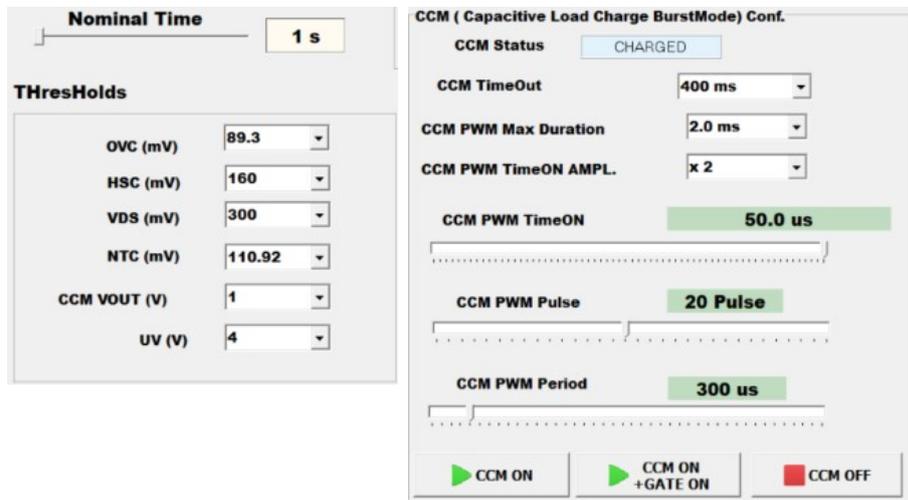
It adopts the same setup as trial E1 with the R_{SHUNT} increased at 20 m Ω vs 5 m Ω and the CCM timeout increased at 400 ms vs 200 ms.

- $V_B = 13\text{ V}$
- **$R_{SHUNT} = 20\text{ m}\Omega$**
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

- $CCM_VOUT_THR = 1\text{ V}$
- $OVC_THR = VOC_THRS_31 \rightarrow 89.3\text{ mV}$
- $HSC_THR = VHSC_THRS_15 \rightarrow 160\text{ mV}$
- $T_NOM = T_NOM_{MIN} \rightarrow 1\text{ s}$
- $CCM_PWM_TON = 50\text{ }\mu\text{s}$
- $CCM_PWM_TON_MF = 2\text{ x}$
- $CCM_PWM_SC_T_NB = 20\text{ pulses}$
- $CCM_PWM_T = 300\text{ }\mu\text{s}$
- **$CCM_TIMEOUT = 400\text{ ms}$**
- $CCM_PWM_SC_T = 2\text{ ms}$
- GUI settings at the end of CCM operations as shown in [Figure 101](#)

Figure 101. CCM configuration and result from GUI for test setup W



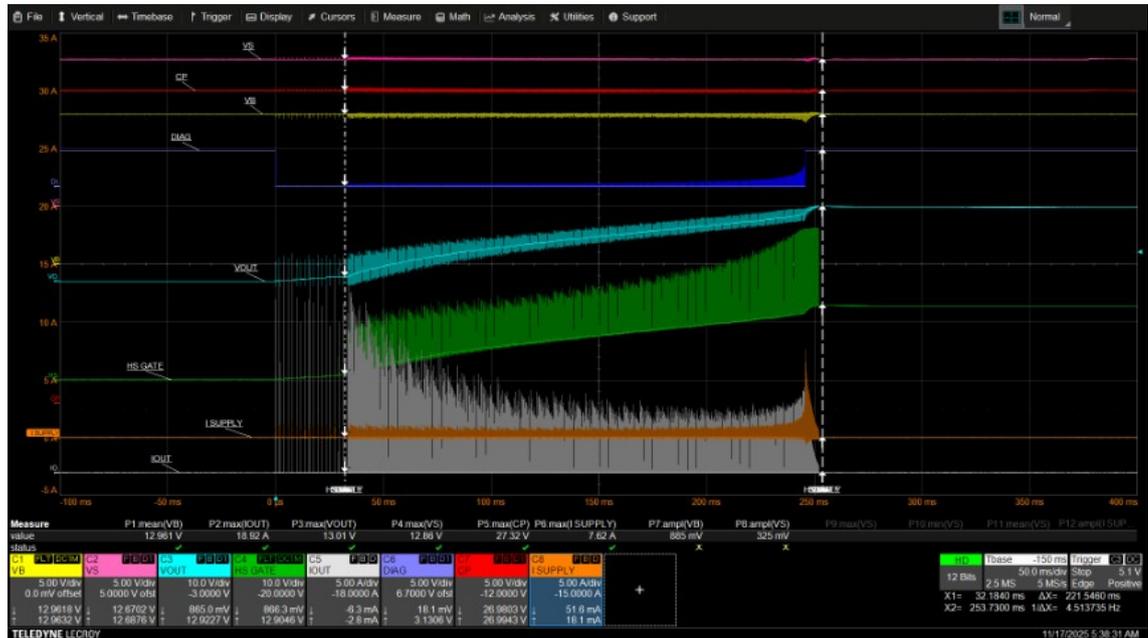
Result W:

With the mentioned setup W, the 4.7 mF C_{LOAD} is charged in 34 ms (start phase) + 219.5 ms (standard phase).

The CCM timeout is increased at 400 ms to complete the charge.

The increase of R_{SHUNT} from 5 m Ω to 20 m Ω involves reading from the ADC of current level four times greater.

Considering that the setup is the same as the one adopted in trial E1, we see IOU_T max moving from 42.6 A with $R_{SHUNT} = 5\text{ m}\Omega$ to 18.9 A with $R_{SHUNT} = 20\text{ m}\Omega$. The t_{CHARGE} time increases from 43.9 ms to 253.5 ms.

Figure 102. Waveforms acquired during CCM with setup W


5.13 Effect of TNOM on CCM

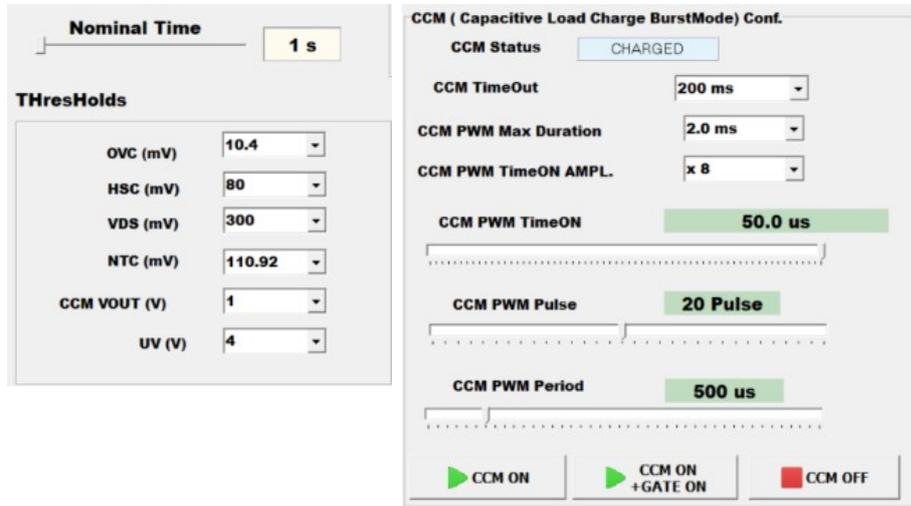
5.13.1 Trial Setup X1

It adopts a dedicated setup to point out the effect of T_{NOM} set at 1 s (min value).

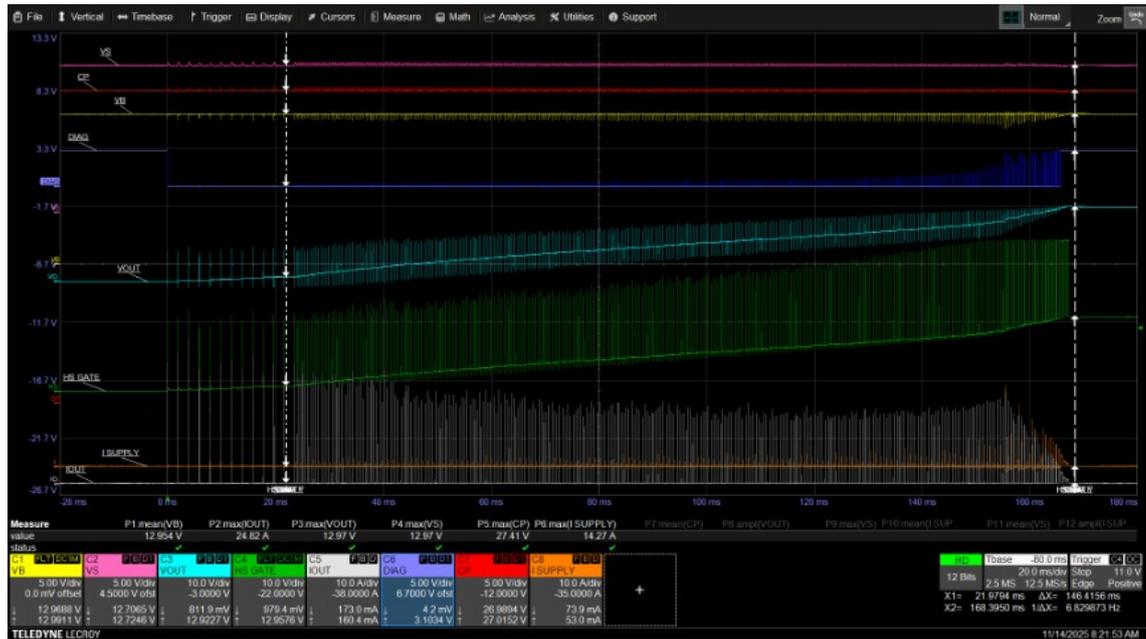
- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

- $CCM_VOUT_THR = 1\text{ V}$
- $OVC_THR = VOC_THRS_3 \rightarrow 10.4\text{ mV}$
- $HSC_THR = VHSC_THRS_10 \rightarrow 80\text{ mV}$
- **$T_{NOM} = T_{NOM_MIN} \rightarrow 1\text{ s}$**
- $CCM_PWM_TON = 50\text{ }\mu\text{s}$
- $CCM_PWM_TON_MF = 8\text{ x}$
- $CCM_PWM_SC_T_NB = 20\text{ pulses}$
- $CCM_PWM_T = 500\text{ }\mu\text{s}$
- $CCM_TIMEOUT = 200\text{ ms}$
- $CCM_PWM_SC_T = 2\text{ ms}$
- GUI settings at the end of CCM operations as shown in Figure 103

Figure 103. CCM configuration and result from GUI for test setup X1

Result X1:

 With setup X1, the 4.7 mF C_{LOAD} is charged in 24 ms (start phase) + 144.4 ms (standard phase).

Figure 104. Waveforms acquired during CCM with setup X1

5.13.2
Trial Setup X2

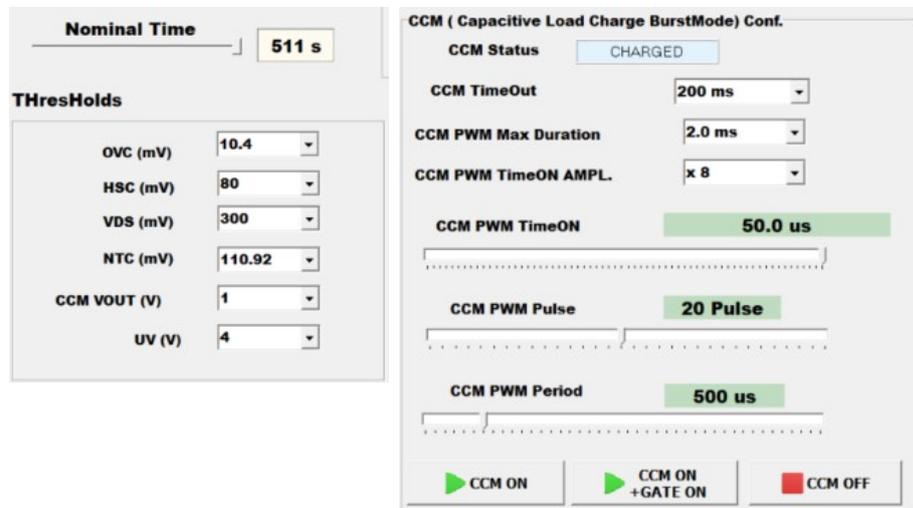
 It adopts the the same setup as trial X1 with T_{NOM} set at 511 s (max value) vs 1 s (min value).

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

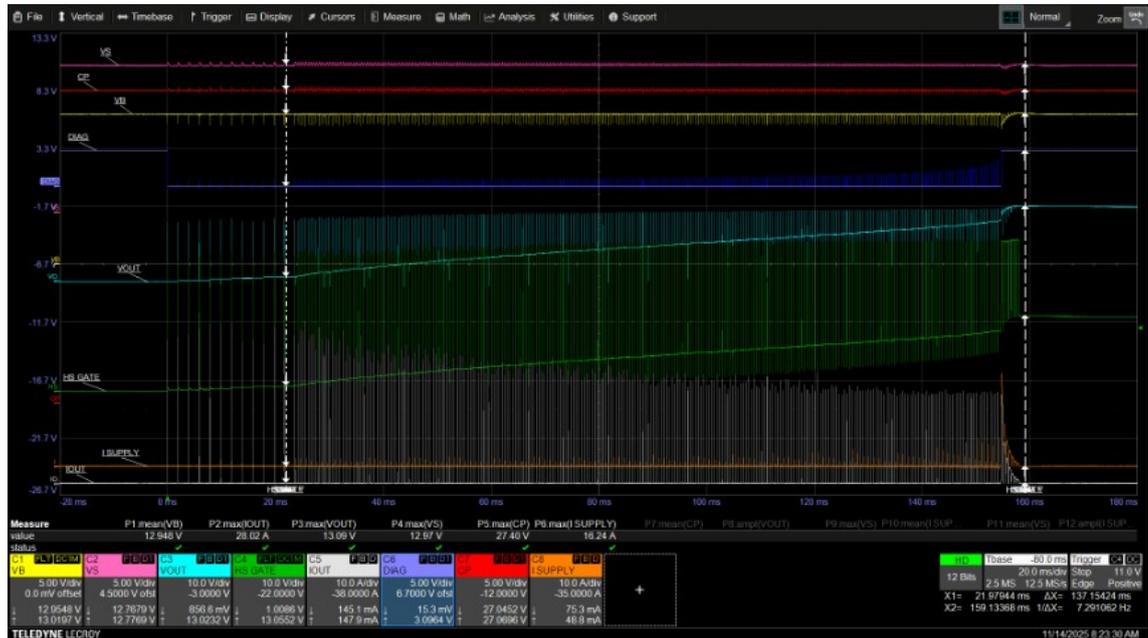
- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_3 → 10.4 mV
- HSC_THR = VHSC_THRS_10 → 80 mV
- **T_NOM = T_NOM_{MAX} → 511 s**
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 8 x
- CCM_PWM_SC_T_NB = 20 pulses
- CCM_PWM_T = 500 μs
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in [Figure 105](#)

Figure 105. CCM configuration and result from GUI for test setup X2



Result X2:

With the mentioned setup X2, the 4.7 mF C_{LOAD} is charged in 24 ms (start phase) + 135.1 ms (standard phase). The T_{NOM} set at max (trial X2 at 511 s) vs min (trial X1 at 1 s) value involves a faster t_{CHARGE} due to its contribution in I^2t fuse protection triggering in the standard charging phase. Max T_{NOM} involves a longer time ON of HS_GATE because a longer time is needed to trigger I^2t protection. In any case, the impact on the overall t_{CHARGE} is very little and it is visible by the slopes of the VOUT signal during the standard phase and by the final portion highlighted in yellow in the below image where the I^2t protection is triggered by OVC assuring longer time ON of HS_GATE.

Figure 106. Waveforms acquired during CCM with setup X2


5.14 CCM attempt on OUT shorted to GND

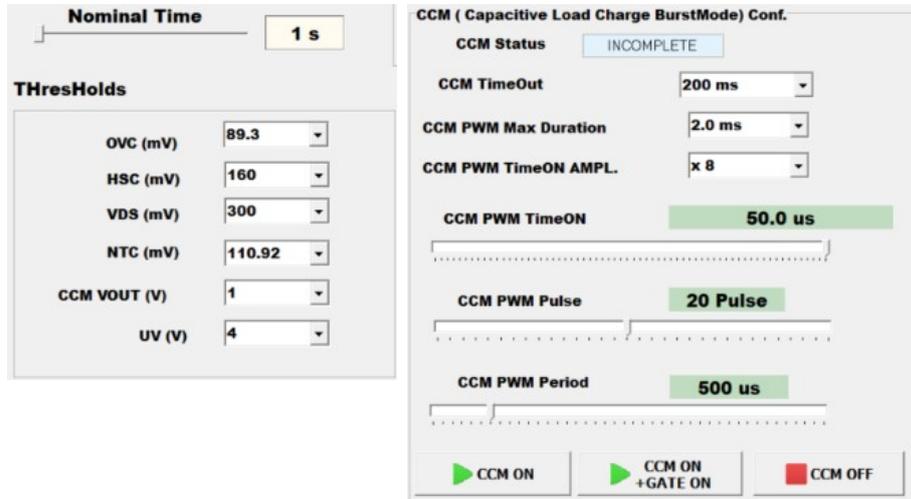
5.14.1 Trial Setup Y

It adopts a dedicated setup to point out the consequences of a capacitive charging mode launched with OUT shorted to GND.

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- **$C_{LOAD} = \text{short circuit between OUT and GND}$**
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

- $CCM_VOUT_THR = 1\text{ V}$
- $OVC_THR = VOC_THRS_31 \rightarrow 89.3\text{ mV}$
- $HSC_THR = VHSC_THRS_15 \rightarrow 160\text{ mV}$
- $T_NOM = T_NOM_{MIN} \rightarrow 1\text{ s}$
- $CCM_PWM_TON = 50\text{ }\mu\text{s}$
- $CCM_PWM_TON_MF = 8\text{ x}$
- $CCM_PWM_SC_T_NB = 20\text{ pulses}$
- $CCM_PWM_T = 500\text{ }\mu\text{s}$
- $CCM_TIMEOUT = 200\text{ ms}$
- $CCM_PWM_SC_T = 2\text{ ms}$
- GUI settings at the end of CCM operations as shown in [Figure 107](#)

Figure 107. CCM configuration and result from GUI for test setup Y

Result Y:

With the mentioned setup Y, the CCM is aborted after 20 pulses corresponding to 40 ms of the start phase because VOUT remained at 0 V so that no transition to the standard phase is allowed.

Figure 108. Waveforms acquired during CCM with setup Y


5.15 Examples of CCM completed or stopped before capacitance charge completion

5.15.1 Trial Setup Z1

It adopts a dedicated setup.

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

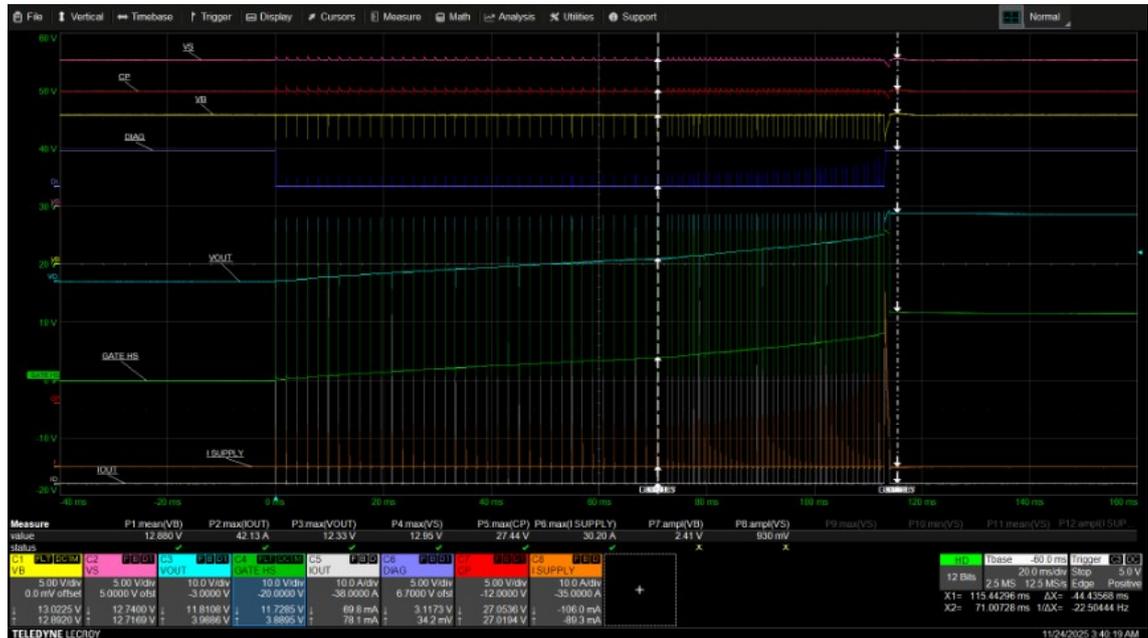
- **CCM_VOUT_THR = 4 V**
- $OVC_THR = VOC_THRS_31 \rightarrow 89.3\text{ mV}$
- $HSC_THR = VHSC_THRS_15 \rightarrow 160\text{ mV}$
- $T_NOM = T_NOM_{MIN} \rightarrow 1\text{ s}$
- $CCM_PWM_TON = TON\text{ protection}$
- $CCM_PWM_TON_MF = 2\text{ x}$
- **CCM_PWM_SC_T_NB = 50 pulses**
- **CCM_PWM_T = 1000 μs**
- **CCM_TIMEOUT = 400 ms**
- $CCM_PWM_SC_T = 2\text{ ms}$
- GUI settings at the end of CCM operations as shown in [Figure 109](#)

Figure 109. CCM configuration and result from GUI for test setup Z1

The screenshot displays the CCM (Capacitive Load Charge BurstMode) configuration GUI. On the left, the 'Nominal Time' is set to 1 s. The 'THreshHolds' section includes: OVC (mV) at 89.3, HSC (mV) at 160, VBS (mV) at 300, NTC (mV) at 110.92, CCM VOUT (V) at 4, and UV (V) at 4. The main configuration area shows: CCM Status as CHARGED, CCM Timeout at 400 ms, CCM PWM Max Duration at 2.0 ms, CCM PWM TimeON AMPL. at x2, CCM PWM TimeON as TON Protection, CCM PWM Pulse as 50 Pulse, and CCM PWM Period as 1000 μs . At the bottom, there are buttons for CCM ON, CCM ON + GATE ON, and CCM OFF. On the right, a 'Register' window shows two columns of registers. The first column (Ctrl Reg) includes registers like AUTO_ON_DIS, LOCKED_MODE_EN, CCM_CTRL_OFF, CCM_CTRL_ON, NVM_DEF_UPLOAD, NVM_DEF_CFGEN, FS_MODE1, FS_MODE0, DNL_CTRL_OPT, DNL_CTRL_EN, GOSTBY, EN, S_T_START, S_T_STOP, S_T_CFG2, S_T_CFG1, S_T_CFG0, OUTCTL, BYPASSCTL, WD_TRIG, and PARITY BIT. The second column (Status Reg) includes registers like CCM_STATUS1, CCM_STATUS0, CS_LIV, EXT_REG_ON, DIS_OUT_FAIL, SELFTEST, OUTST, BYPASSST, LOCKED_STATE, FAILSAFE, HWLO_ST, VS_UV, HSHT, VDS_MAX, BYPASS_SAT, FUSE_LATCH, OVC, DEV_OVT, NTC_OVT, VGS_LOW, CP_LOW, WD_FAIL, and PARITY BIT. The status of these registers is indicated by 0 or 1.

Result Z1:

With the mentioned setup Z1, the $4.7\text{ mF } C_{LOAD}$ is charged in 74 ms (start phase) + 41.4 ms (standard phase).

Figure 110. Waveforms acquired during CCM with setup Z1


5.15.2 Trial Setup Z2

It adopts the same setup as trial Z1, but the device is in Fail-safe.

- VB = 13 V
- R_{SHUNT} = 5 mΩ
- Ambient temperature = room temperature ~25°C generating T_J ~35°C
- C_{LOAD} = 4.7 mF (measured 4.52 mF)
- C_{IN} = 314 μF and C_S = 20 μF

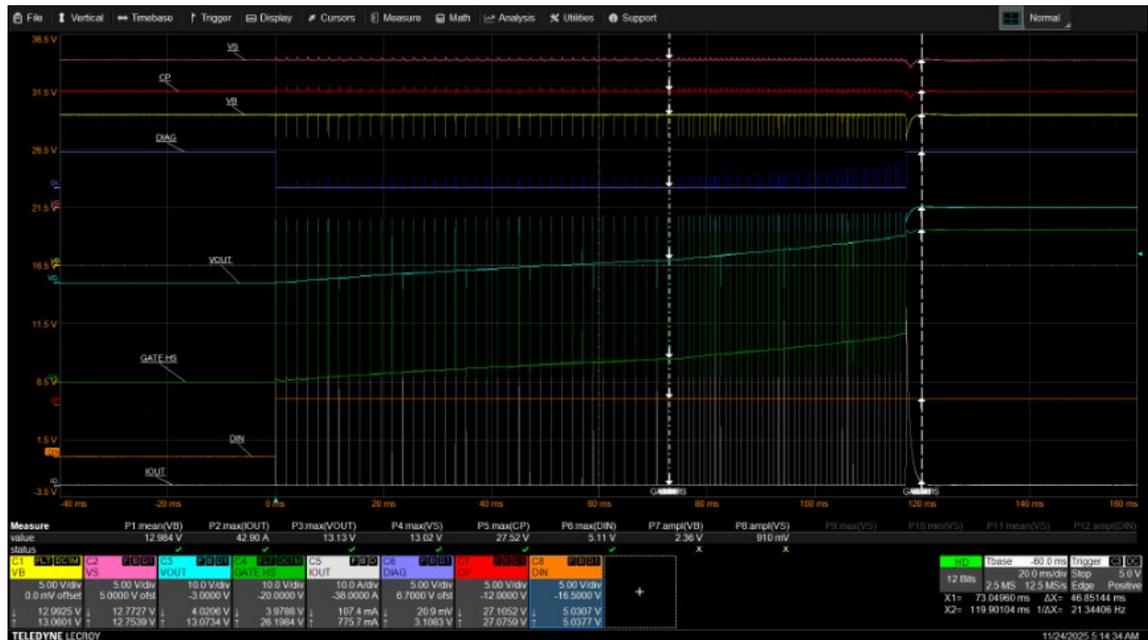
Device in Fail-safe state with the following settings:

- **CCM_VOUT_THR = 4 V**
- OVC_THR = VOC_THRS_31 → 89.3 mV
- HSC_THR = VHSC_THRS_15 → 160 mV
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = TON protection
- CCM_PWM_TON_MF = 2 x
- **CCM_PWM_SC_T_NB = 50 pulses**
- **CCM_PWM_T = 1000 μs**
- **CCM_TIMEOUT = 400 ms**
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in Figure 111

Figure 111. CCM configuration and result from GUI for test setup Z2

Result Z2:

With the mentioned setup Z1, the 4.7 mF C_{LOAD} is charged in 76 ms (start phase) + 44.4 ms (standard phase). The slight longer t_{CHARGE} vs trial A1 is due to one additional pulse present in the start phase and a longer duration in the standard phase due to VOUT reaching 13.1 V vs 11.7 V.

Figure 112. Waveforms acquired during CCM with setup Z2

5.15.3
Trial Setup Z3

It adopts the same setup as trial Z1 but the CCM is purposely aborted after ~47 ms by means of a dedicated SPI frame in CR#1 where bit 18 (CCM_CTRL_ON) is set at "0" and bit 19 (CCM_CTRL_OFF) is set at "1".

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Fail-safe state with the following settings:

- **CCM_VOUT_THR = 4 V**
- OVC_THR = VOC_THRS_31 → 89.3 mV
- HSC_THR = VHSC_THRS_15 → 160 mV
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = TON protection
- CCM_PWM_TON_MF = 2 x
- **CCM_PWM_SC_T_NB = 50 pulses**
- **CCM_PWM_T = 1000 μs**
- **CCM_TIMEOUT = 400 ms**
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in Figure 113

Figure 113. CCM configuration and result from GUI for test setup Z3



Please note that the CCM_CTRL_OFF (bit19 in CR#1) is refreshed after the CCM is aborted.

Result Z3:

With the mentioned setup Z3, the 4.7 mF C_{LOAD} is aborted after 46.8 ms during the start phase due to a dedicated command on CR# 1. The VOUT reaches 2.8 V once the CCM is stopped.

Figure 114. Waveforms acquired during CCM with setup Z3

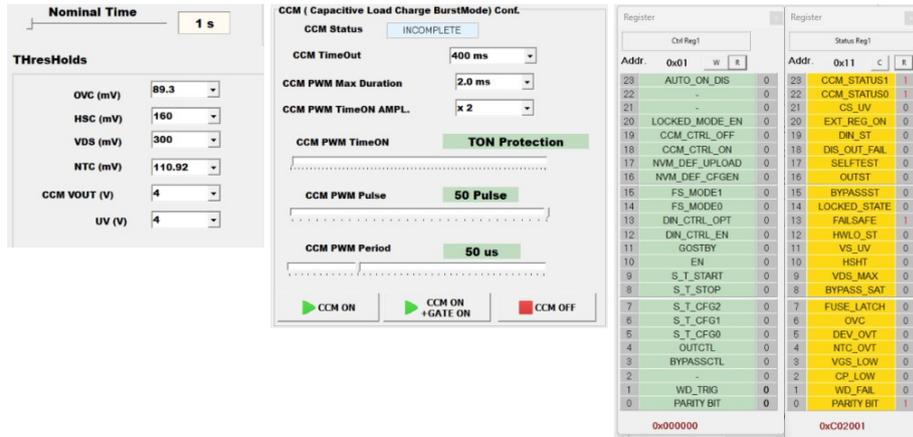

5.15.4 Trial Setup Z4

It adopts the same setup as trial Z3 with the device in Fail-safe mode and the CCM purposely aborted after 85.6 ms by means of a dedicated DIN set from high to low.

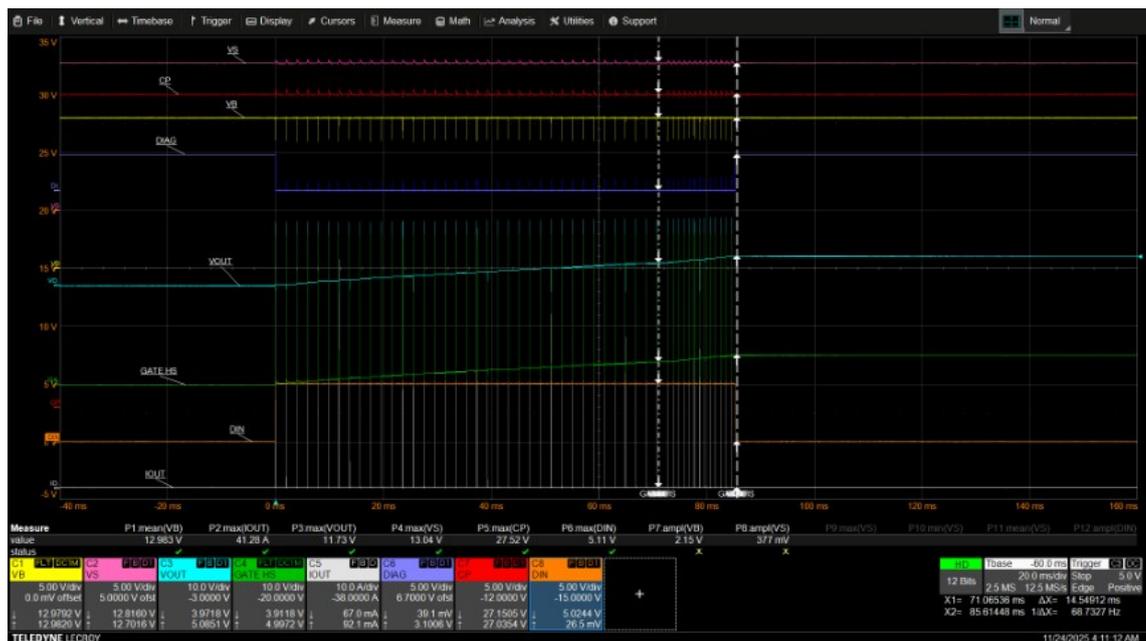
- VB = 13 V
- R_{SHUNT} = 5 mΩ
- Ambient temperature = room temperature ~25°C generating T_J ~35°C
- C_{LOAD} = 4.7 mF (measured 4.52 mF)
- C_{IN} = 314 μF and C_S = 20 μF

Device in Fail-safe state with the following settings (written in NVM):

- **CCM_VOUT_THR = 4 V**
- OVC_THR = VOC_THRS_31 → 89.3 mV
- HSC_THR = VHSC_THRS_15 → 160 mV
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = TON protection
- CCM_PWM_TON_MF = 2 x
- **CCM_PWM_SC_T_NB = 50 pulses**
- **CCM_PWM_T = 1000 μs**
- **CCM_TIMEOUT = 400 ms**
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in Figure 115

Figure 115. CCM configuration and result from GUI for test setup Z4

Result Z4:

With the mentioned setup Z4, the 4.7 mF C_{LOAD} is aborted after 74 ms (start phase) + 11.6 ms (standard phase) due to DIN moving from high to low. The VOUT reaches 5.1 V once the CCM is stopped.

Figure 116. Waveforms acquired during CCM with setup Z4


5.16 Examples of CCM + GATE ON

5.16.1 Trial Setup E2

It adopts the same setup as trial E1 with C_{LOAD} at 4.7 mF but in this case we launched CCM + GATE ON.

- $V_B = 13\text{ V}$
- $R_{SHUNT} = 5\text{ m}\Omega$
- Ambient temperature = room temperature $\sim 25^\circ\text{C}$ generating $T_J \sim 35^\circ\text{C}$
- $C_{LOAD} = 4.7\text{ mF}$ (measured 4.52 mF)
- $C_{IN} = 314\text{ }\mu\text{F}$ and $C_S = 20\text{ }\mu\text{F}$

Device in Unlocked state with the following settings:

- CCM_VOUT_THR = 1 V
- OVC_THR = VOC_THRS_31 → 89.3 mV
- HSC_THR = VHSC_THRS_15 → 160 mV
- T_NOM = T_NOM_{MIN} → 1 s
- CCM_PWM_TON = 50 μs
- CCM_PWM_TON_MF = 2 x
- CCM_PWM_SC_T_NB = 20 pulses
- CCM_PWM_T = 300 μs
- CCM_TIMEOUT = 200 ms
- CCM_PWM_SC_T = 2 ms
- GUI settings at the end of CCM operations as shown in [Figure 117](#)
- In the same frame on CR#1 set CCM_CTRL_ON (bit 18) = 1b AND OUTCTL (bit 4) = 1b

Figure 117. CCM configuration and result from GUI for test setup E2. At the end of charge the HS_GATE is turned again ON to sustain OUT voltage

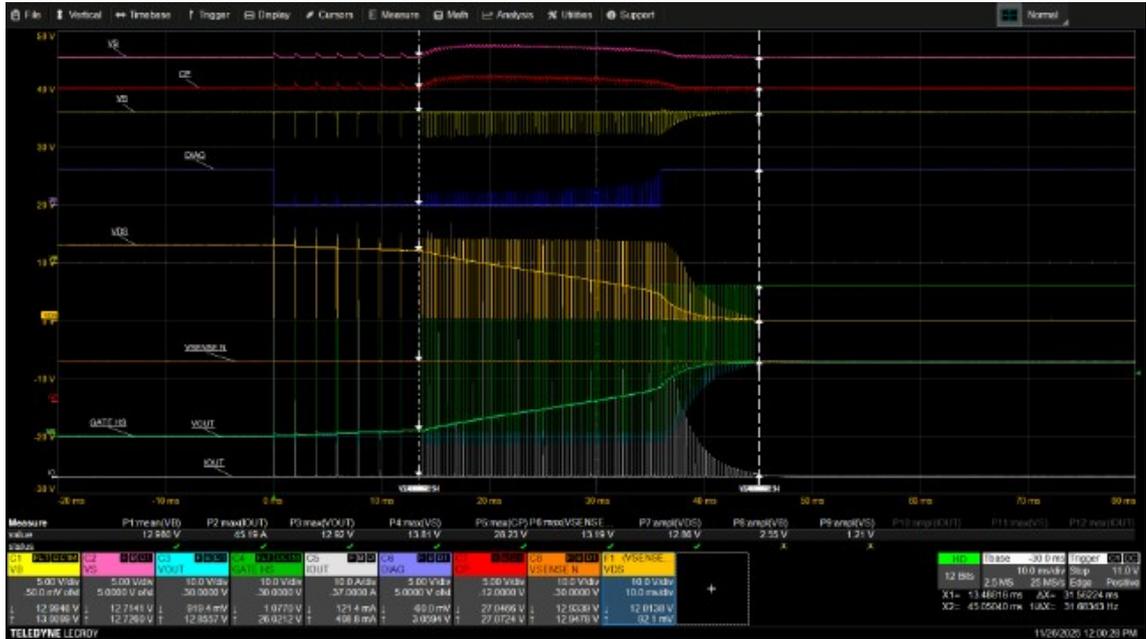


Result E2:

With the mentioned setup E2, the C_{LOAD} is charged in 4 ms (start phase) + 31 ms (standard phase).

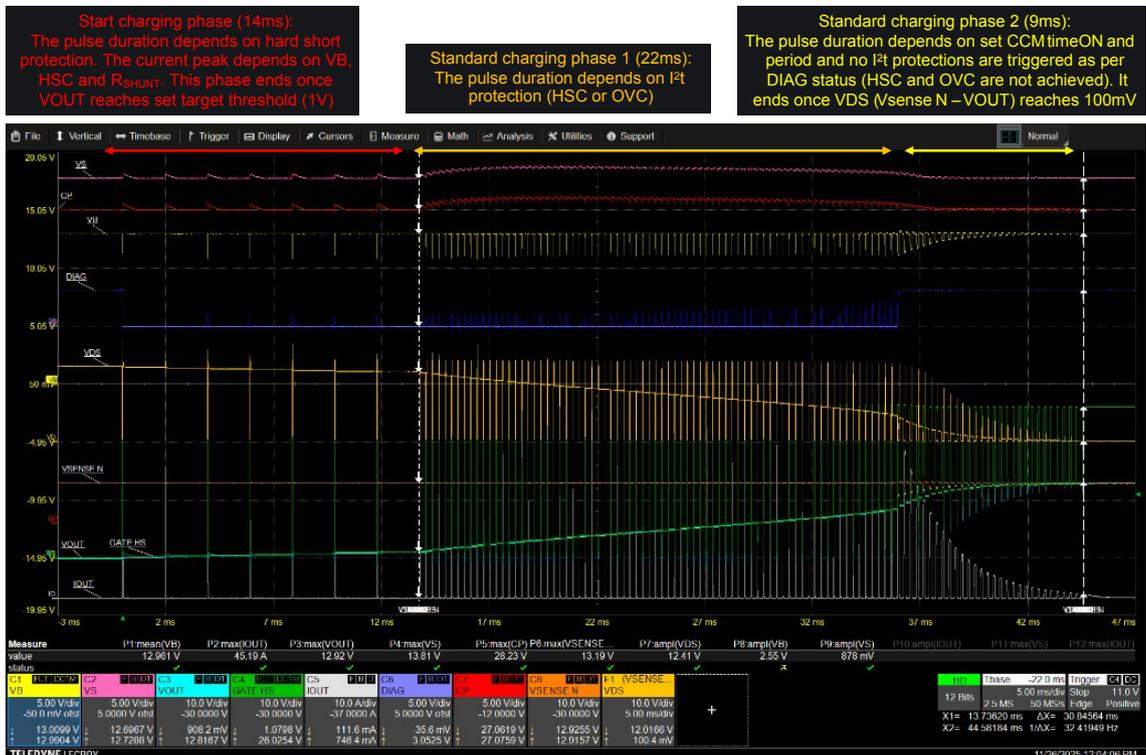
In this case, once C_{LOAD} is charged, OUTCTL (bit4) = 1b in CR#1 maintain ON the MOS (OUTST bit 16 in SR#1 is at "1") to maintain VOUT value close to VB.

Figure 118. Waveforms including VDS acquired during CCM with setup E2 with device in Unlocked state



Below is the zoomed image focused on the CCM step, with HS_GATE maintained ON at the end of the C_{LOAD} charge.

Figure 119. Zoomed waveforms including VDS focused on CCM step with setup E2 with device in Unlocked state



6 Conclusions

As shown in the examples verified in this document, the [VNF1248F](#) device can sustain, through the CCM feature, the charging of a wide range of capacitive loads operating at supply voltages of 12 V, 24 V, and 48 V. For 48 V applications, while CCM is active, the parasitic elements combined with the application circuitry of [VNF1248F](#) can cause a voltage boost effect that is potentially critical.

In this document, all hazardous conditions are avoided by varying the value of C_{IN} capacitors and, where necessary, by using a transient voltage suppressor (TVS) [SM15T68CAY](#).

Similarly, end users must select the application components to prevent dangerous voltage levels that could exceed the absolute maximum ratings of the [VNF1248F](#) device.

Revision history

Table 7. Document revision history

Date	Revision	Changes
12-Mar-2026	1	First release.

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